

Cardiac Rhythm Disease Management Product Performance Report

Important Patient Management Information for Physicians

2010

Second Edition – Issue 63







A Message from the Vice President

Dear Customer,

At Medtronic, product quality and reliability have been and will continue to be a priority. For over 27 years, Medtronic has compiled and produced product performance reports with one primary goal, to provide you with the product information you need to best care for your patients.

Our commitment to you is best expressed in Medtronic's mission: "To strive without reserve for the greatest possible reliability and quality in our products; to be the unsurpassed standard of comparison and to be recognized as a company of dedication, honesty, integrity, and service." To this end, we continually explore new ways to expand, improve, and learn from our product performance systems and measures.

Our quality goals cannot be reached alone. We welcome your collaboration, insight, and recommendations. Please contact our Technical Services Department at 1 (800) 723-4636 with your feedback comments and any questions.

Your participation and assistance in returning explanted products are also critical. Returned products are tested and evaluated so that we can fully measure the performance of our devices. Please refer to the instructions on the next page for assistance in returning products to the Medtronic CRDM Returned Product Analysis Laboratory.

As we constantly strive to exceed your expectations, we thank you for your dedication to improving and saving the lives of those suffering from cardiac rhythm disorders.

With appreciation and warm regards,

Tim Samsel

Vice President, Quality and Regulatory

Medtronic Cardiac Rhythm Disease Management

Medtronic, Inc.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

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For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States:

Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

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 ${\it Tim Samsel, Vice President, CRDM Quality and Regulatory}$

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Introduction

All product performance reports are not created equal. For 27 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), cardiac resynchronization therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic Cardiac Rhythm Disease Management (CRDM) uses both returned product analysis and multicenter clinical studies to monitor performance.

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study. Medtronic CRDM is unique in the industry in that we track CRT, ICD, and IPG device survival using both methods.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is

designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead-related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure.

The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

Since May 2000, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly, Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted products from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab. For information on how to contact the Lab, refer to Contact Information of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see Contact Information of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for individual device and lead in the *population sample*. The population sample for

CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in our multicenter, international prospective System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined in the study protocol.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads
- implanted in patients who are lost to follow-up

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles Method for Estimating CRT, ICD, and IPG Device Performance (page 6) and Method for Estimating Lead Performance (page 75).

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with an orange X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

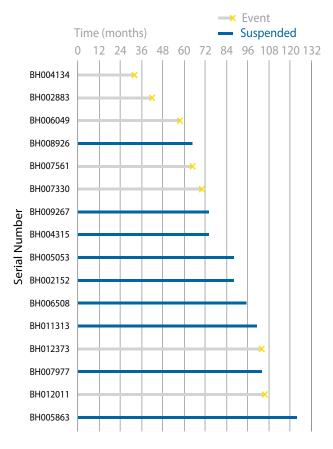


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that seven of the 16 devices suffered events, and nine are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized, as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For the interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The Effective Sample Size (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval overestimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices underestimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The Interval Survival Probability (F) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the Proportion with Event (E). This number can be interpreted as the estimated rate at which events do not occur in the time interval.

The Cumulative Survival Probabilities (G) from the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

Table 1 Life Table for Figure 1

	Α	В	C	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Definitions:

A	B	C	D	E	F	G
Number	Number	Number	Effective	Proportion	Interval	Cumulative
Number Entered Number of devices active at the start of the interval	Number Suspended Number of devices removed from service for reasons other than an event	Number of Events Number of units removed from service due to an event	Effective Sample Size Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered.	Proportion with Event Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size.	Interval Survival Probability The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event.	

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the Interval Survival Probability (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%.

The *Cumulative Survival Probabilities* (G) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.

Cumulative Survival Probability (%) 100 90 80 70 40 30 12 48 60 84 96 108 120 0 24 36 72 132 Time (months) 96 24 48 60 72 84 108 120 132 0 12 36 93.8 87.5 81.3 68.3 68.3 68.3 34.1 34.1 100 100 100 34.1 16 16 16 15 12.5 0.5 16 **Effective Sample Size**

Figure 2 Survival Curve for Data Given in Table 1

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product **Performance Report**

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using 1-month intervals (for CRT, ICD, and IPG devices) or 3-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.1

¹ Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis – 3rd Edition (Wiley Series in Probability and Statistics).

Method for Estimating CRT, ICD, and IPG Device Performance

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's United States device registration data and US returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) has functioned normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Definition of Malfunction

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function, and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion - The condition when:

- (a) a device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) a device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include estimated longevities for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

Expanded Malfunction Detail

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component – Findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – Findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery – Findings linked to the battery and its components

Software/Firmware – Findings linked to software or firmware function

Possible Early Battery Depletion – Findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – Findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive

Returned Product Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed evenly within the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first 5 years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables are rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more malfunctions or battery depletions. This occurs because, even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates.

Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and **Population Samples Are Defined**

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

A CRT, ICD, or IPG model or model family will be included in this report when it has accumulated at least 10,000 implant months and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in Medtronic's Device And Registrant Tracking (DART) system.

The DART system is an important element of Medtronic's Quality System. The DART system is designed to meet or exceed the US FDA's device tracking requirements set forth by the Safe Medical Devices Act. In the United States, over 98% of Medtronic's CRT, ICD, and IPG implants become registered in the DART

Method for Estimating CRT, ICD, and IPG Device Performance, continued

Because pacemakers do not cure the patient's underlying health problem, when a pacemaker stops functioning (due to either normal battery replacement or malfunction) it is replaced with a new pacemaker. Therefore, the replacement recorded in the DART system is a good indication that the previous pacemaker experienced either battery depletion or malfunction. The fraction of replaced devices that are subsequently returned can be used to estimate the correction factor for the underreporting of the combination of battery depletion and malfunction.

Note that devices of patients who have expired do not factor into the calculation of the correction. It is possible some proportion of these device experienced battery depletion or malfunction. Since these are not counted into the correction factor based on the return rate of replaced devices, a correction factor based only on the return rate of replaced devices may still underestimate the true rate of battery depletion and malfunction. However, devices that are replaced because the patient is receiving a system upgrade or are removed because the patient no longer needs it (e.g., due to heart transplant) do contribute to the calculation of the correction factor and therefore impart an opposite bias.

Also note that this method of calculating the correction factor cannot distinguish between devices that are removed due to malfunction and those due to normal battery depletion. It might seem intuitive that devices that unexpectedly malfunction should be much more likely to be returned to the manufacturer than a device with ordinary normal battery depletion. But this has not been conclusively demonstrated. Therefore, this method only provides a correction factor reflecting the combination of battery depletion and malfunction.

No adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to nondevice related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

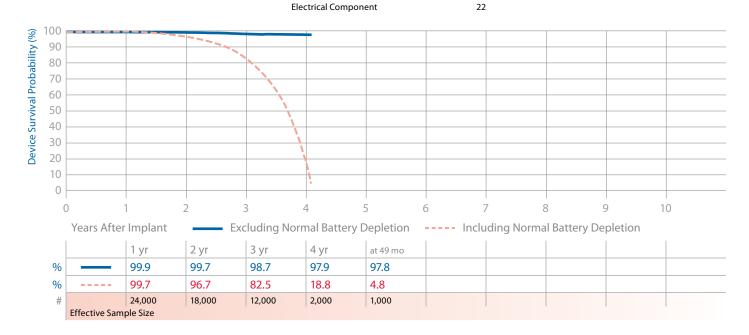
To ensure the number of devices in service is not overstated, Medtronic addresses this underreporting in two ways. Regular updates obtained from the Social Security Administration about deceased persons is used to update Medtronic's DART data about patients who have died but whose deaths had not been reported to Medtronic. In addition, the patient mortality rate derived from our DART system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in DART is significantly different from published rates, an adjustment is applied to correct the difference.

7289 InSync II Marquis

US Market Release	Jul-03					
Registered US Implants	28,000					
Estimated Active US Implants	100					
Normal Battery Depletions (US)	6,386					
Advisories: See page 144 – 2005 Potential						

Malfunctions (US)	298	
Therapy Function Not Compromised	266	
Electrical Component	22	
Software/Firmware	1	
Possible Early Battery Depletion	243	
Therapy Function Compromised	32	
Battery (9 malfunctions related to advisory)	10	

NBD Code		VVED
Serial Number Pref	ĭx	PRJ
Max Delivered Ene	rgy	30 J
Estimated Longevi	ty	See page 20





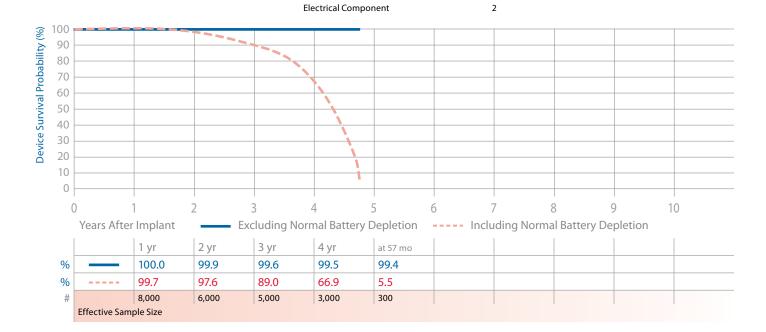
7297 InSync Sentry

US Market Release	Nov-04
Registered US Implants	9,000
Estimated Active US Implants	100
Normal Battery Depletions (US)	1,993
Advisories	None

Product Characteristics

Ma	lfunctions (US)	36	NBD Code	VVED
Tł	nerapy Function Not Compromised	34	Serial Number Prefix	PRK
	Battery	1	Max Delivered Energy	35 J
	Electrical Component	7	Estimated Longevity	See page 20
	Software/Firmware	1		
	Possible Early Battery Depletion	25		

2



Therapy Function Compromised

7299 InSync Sentry

US Market Release	Apr-05	Malfunctions (US)		111	NBD Code	VVED
Registered US Implants	31,000	Therapy Function No	ot Compromised	103	Serial Number Prefix	PRK
Estimated Active US Implants	6,000	Electrical Compo	nent	13	Max Delivered Energy	35 J
Normal Battery Depletions (US)	3,958	Software/Firmwa	are	2	Estimated Longevity	See page 20
Advisories	None	Possible Early Bat	ttery Depletion	88		
		Therapy Function Co	ompromised	8		
		Electrical Compo	nent	8		
100						
90						
90 80 70 60 50 40 30 20						
70						
50						
40						
30		1				
20						
		1				
0						
0 1	2 3	4	5 6	7	8 9	10
Years After Implant	Exclud	ing Normal Battery I	Depletion	Includin	g Normal Battery Depletion	on
1 yr	2 yr 3 y	r 4 yr	at 56 mo			
% 100.0	99.9 99	7 99.4	99.1			
% 99.8	97.8 89	5 63.6	5.8			
# 27,000	22,000 16,0	7,000	300			
Effective Sample Size						



7303 InSync Maximo

Product Characteristics

13 inSync Maxim	0					Product Chai	acteristics	
US Market Release	Jur	n-04 Ma	lfunctions (US)		70	NBD Code		VVED
Registered US Implants	17	.000 TH	nerapy Function N	lot Compromised	63	Serial Number P	refix	PRL
Estimated Active US Implant	5	100	Electrical Comp	onent	13	Max Delivered E	nergy	35 J
Normal Battery Depletions (l	JS) 4	,176	Software/Firmw	are	2	Estimated Longe	evity	See page
Advisories	N	one	Possible Early Ba	attery Depletion	48			
		TI	nerapy Function C	ompromised	7			
			Electrical Comp	onent	7			
100								
90								
80								
70		4						
60								
50								
40								
30								
20			· ·					
10			1					
0								
0 1	2	3	4	5 6	7	8	9	10
Years After Impla	ant — E	excluding N	lormal Battery	Depletion -	Includir	ng Normal Batte	ery Depletion	
1 yr	2 yr	3 yr	4 yr	at 56 mo				
% 100.0		99.6	99.4	99.4				
% 99.8	97.6	88.5	63.6	11.5				

1,000

7304 InSync Maximo

Effective Sample Size

15,000

12,000

9,000

5,000

		Apr-0	J5 Ma	Ifunctions (US)		6	3	NBD Code		VVED
Registered US Imp	lants	19,00	00 T ł	nerapy Function N	ot Compromis	ed 6	1	Serial Number P	refix	PRL
Estimated Active l	JS Implants	5,00	00	Battery			1	Max Delivered E	nergy	35 J
Normal Battery De	pletions (US)	2,0	18	Electrical Compo	onent		7	Estimated Longe	evity	See page 2
Advisories		Nor	ne	Possible Early Ba	ttery Depletior	n 5	3			
			Tł	nerapy Function C	ompromised		2			
				Electrical Compo	onent		2			
100										
80										
70										
60										
50										
40										
30										
20										
10										
0										
0	1	2	3	4	5	6	7	8	9	10
Years Af	ter Implant	Ex	cluding N	lormal Battery	Depletion	Inclu	udin	g Normal Batte	ery Depletic	n
	1 yr	2 yr	3 yr	4 yr	at 57 mo					
%	100.0	99.9	99.7	99.3	99.3					
%	99.8	97.8	90.3	68.1	9.2					
#	16,000	13,000	9,000	4,000	200					



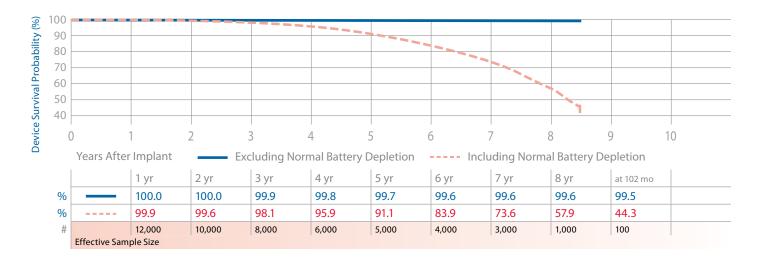
8040 InSync

US Market Release	Aug-01
Registered US Implants	15,000
Estimated Active US Implants	2,000
Normal Battery Depletions (US)	885
Advisories	None

Malfunctions (US)	29
Therapy Function Not Compromised	7
Electrical Component	4
Possible Early Battery Depletion	3
Therapy Function Compromised	22
Electrical Interconnect	22

Product Characteristics

NBD Code	DDDR
Serial Number Prefix	PIN
Estimated Longevity	See page 20



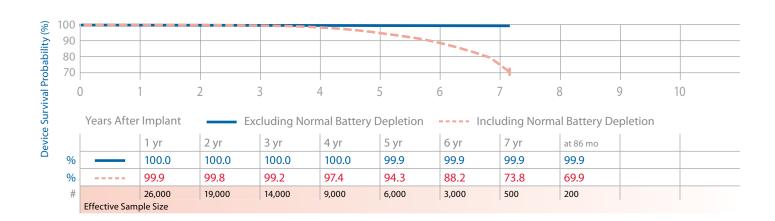
8042 InSync III

US Market Release Feb-03 Registered US Implants 36,000 **Estimated Active US Implants** 18,000 Normal Battery Depletions (US) 551 Advisories None

Malfunctions (US)	10
Therapy Function Not Compromised	3
Electrical Component	2
Possible Early Battery Depletion	1
Therapy Function Compromised	7
Electrical Component	3

NBD Code	DDDR
Serial Number Prefix	PKF
Estimated Longevity	See page 20

Product Characteristics

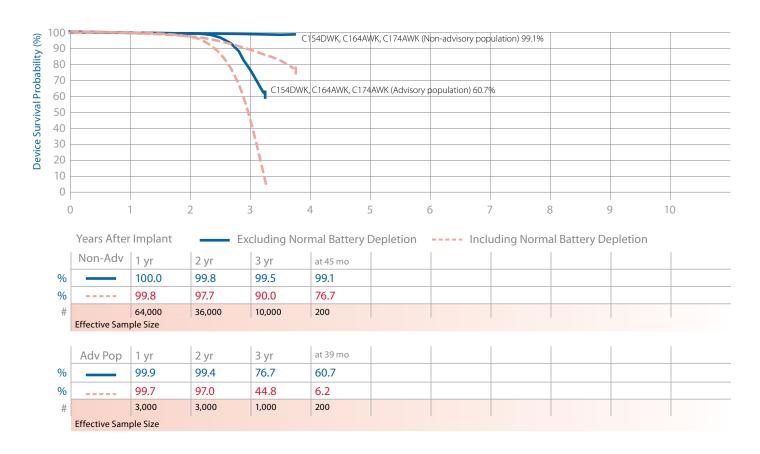


Electrical Interconnect



C154DWK, C164AWK, C174AWK Concerto

C1	54DWK, C164AWK, C174	4AWK Con	certo	(N)	(A)	Product Characteristics	
	US Market Release	May-06	Malfunctions (US)	195	1,059	NBD Code	VVED
	Registered US Implants	May-06 84,000 Therapy Function Not Co s 54,000 Electrical Componen US) 1,512 Electrical Interconner Software/Firmware Possible Early Battery Therapy Function Comp Electrical Componen	Therapy Function Not Compromised	170	1,052	Serial Number Prefix	PVU, PVT, PVR
	Estimated Active US Implants	54,000	Electrical Component	10	1,049	Max Delivered Energy	35 J
	Normal Battery Depletions (US)	1,512	Electrical Interconnect	1		Estimated Longevity	See page 20
	Advisories: See page 138 – 2009		Software/Firmware	1			
	Potential Reduced Device Longevity		Possible Early Battery Depletion	158	3		
	Performance Note: See page 148 –		Therapy Function Compromised	25	7		
	Anomalies in MOSFET Integrated		Electrical Component	24	6		
	Circuit rechnology		Electrical Interconnect	1	1		
	Advisories: See page 138 – 2009 Potential Reduced Device Longevity Performance Note: See page 148 –	1,512	Software/Firmware Possible Early Battery Depletion Therapy Function Compromised Electrical Component	25	7	Estimated Longevity	See page



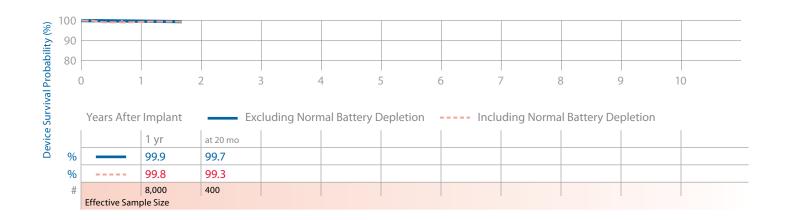


D224TRK Consulta CRT-D

Product Characteristics

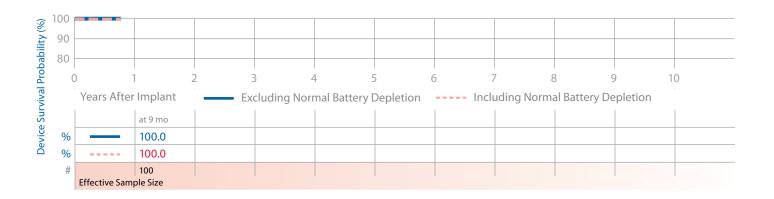
US Market Release	Aug-08	Malfunctions (US)	17	NBD Code	DDED
Registered US Implants	30,000	Therapy Function Not Compromised	16	Serial Number Prefix	PUD
Estimated Active US Implants	27,000	Electrical Component	6	Max Delivered Energy	35 J
Normal Battery Depletions (US)	8	Software/Firmware	1	Estimated Longevity	See page 20
Advisories	None	Possible Early Battery Depletion	9		
		Therapy Function Compromised	1		

Electrical Component



D274TRK Concerto II CRT-D

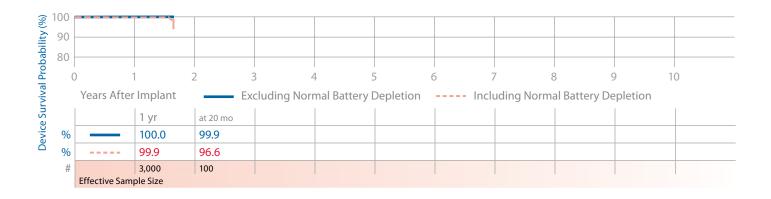
US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	DDED
Registered US Implants	11,000	Therapy Function Not Compromised	0	Serial Number Prefix	PUE, PZB
Estimated Active US Implants	10,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0			Estimated Longevity	See page 20
Advisories	None				





D284TRK Maximo II CRT-D

US Market Release	Mar-08	Malfunctions (US)	2	NBD Code	VVED
Registered US Implants	8,000	Therapy Function Not Compromised	2	Serial Number Prefix	PZP
Estimated Active US Implants	7,000	Possible Early Battery Depletion	2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	7	Therapy Function Compromised	0	Estimated Longevity	See page 20
Advisories	None				





The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included. Device Survival Summary (95% Confidence Interval)

					ŀ	Malfunctions (US)	tions (L	JS)	ŀ	Device S	Device Survival Probability (%)	robability	(%)					
- - -		teaket esse	istered mplants	bətsm 2U əvi stnslı	mal Battery (SU) snoiteld	rapy Function npromised rapy	ction Not npromised	Įŧ		Years Aft	Years After Implant	Jt.						
Number	Family	NS I	I SN ɓəy	itэА	Nor Dep	uoɔ	un⊣	toT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
7289	InSync II Marquis	Jul-03	28,000	100	6,386	32 +	= 599	= 298	Excluding Normal Battery Depletion	99.9	99.7	98.7	97.9 +.2/3	97.8 +.2/3 at 49 mo				
	Advisories: See page 144 – 2005 Potential Premature Battery Depletion Due to Battery Short	ion Due to Ba	– 2005 Pote attery Short	intial Premat	ture	(9) + 0 = 9 (advisory-related subset)	0 = related s	= 9 subset)	Including Normal Battery Depletion	99.7	96.7	82.5 +.6/6	18.8	4.8 +.6/6 at 49 mo				
7297	InSync Sentry	Nov-04	000′6	100	1,993	2 +	34 =	= 36	Excluding Normal Battery Depletion	100.0	99.9	99.6 +.1/2	99.5	99.4 +.2/2 at 57 mo				
									Including Normal Battery Depletion	99.7	97.6	89.0	66.9	5.5 +1.2/-1.0 at 57 mo				
7299	InSync Sentry	Apr-05	31,000	000′9	3,958	+ ∞	103 =	= 111	Excluding Normal Battery Depletion	100.0	99.9	99.7	99.4	99.1 +.2/3 at 56 mo				
									Including Normal Battery Depletion	99.8	97.8	89.5	63.6	5.8 +1.3/-1.1 at 56 mo				
7303	InSync Maximo	Jun-04	17,000	100	4,176	4	63	= 70	Excluding Normal Battery Depletion	100.0	99.8	99.6 +.1/1	99.4	99.4 +.1/2 at 56 mo				
									Including Normal Battery Depletion	99.8	97.6 +.2/3	88.5	63.6	11.5 +1.1/-1.0 at 56 mo				
7304	InSync Maximo	Apr-05	19,000	2,000	2,018	+		= 63	Excluding Normal Battery Depletion	100.0	99.9	99.7	99.3	99.3 +.2/2 at 57 mo				
									Including Normal Battery Depletion	99.8	97.8 +.2/3	90.3	68.1	9.2 +1.8/-1.6 at 57 mo				

		10 yr	99.5 +.2/4 at 102 mo	44.3 +3.3/-3.3 at 102 mo							
		8 yr 10	99.6 99.4. +1.1/2 at	57.9 4.1.8/-1.8 +3 at	99.9 +.1/2 at 86 mo	69.9 +2.8/-3.0 at 86 mo					
		7 yr 8	99.6 +1/2 +	73.6 +1.3/-1.3 +	99.9 9 +.1/2 +	73.8 6 +2.1/-2.2 + a¹					
		6 yr 7	99.6 +1/2	83.9 +.9/-1.0	99.9 + +.0/1	88.2 7					
		5 yr 6	99.7	91.1	99.9	94.3					
(%)		4 yr	99.8	95.9	100.0	97.4	99.1 +.2/2 at 45 mo	76.7 +2.3/-2.5 at 45 mo	60.7 +2.2/-2.3 at 39 mo	6.2 +1.4/-1.2 at 39 mo	
obability	Įt.	3 yr	99.9	98.1 +.3/3	100.0	99.2	99.5	90.0	76.7	44.8	
Device Survival Probability (%)	Years After Implant	2 yr	100.0	99.6	100.0	99.8	99.8 +.0/0	97.7	99.4 +.2/4	97.0	
Device S	Years Afi	1 yr	100.0	99.9	100.0	99.9	100.0 +.0/0	99.8	99.9	99.7	
t			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	
	ı	Tota		Norr		N		Non		Nor	
US)	,	.,	= 29		= 10		= 195		= 1,059		
alfunctions (US)	rapy ction Not npromised	un⊣			m		170		1,052		
Malfun	rapy Function npromised	uoɔ	22 +		7 +		25 +		+		
	mal Battery (2U) snoitald		885		551		1,329	MOSFET	183	p.	MOSFET
	bətem SU əvi stnaf	itoA	2,000		18,000		54,000	nomalies in	50	ntial Reduce	nomalies in
	istered mplants	NS I Bea	15,000		36,000		81,000	e note on Ai gy	4,000	- 2009 Pote	e note on Ai gy
	Narket sase	US I	Aug-01		Feb-03		May-06	Performance lit Technolo	May-06	page 146-	Performance iit Technolo
		Family	InSync		InSync III		Concerto	See page 148 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	Concerto	Advisories: <u>See page 146</u> –2009 Potential Reduced Device Longevity	See page 146 – Performance note on Anomalies in MOSFET Integrated Circuit Technology
	-	Model Number	8040		8042		C154DWK, C164AWK, C174AWK (Non- advisory population)		C154DWK, C164AWK, C174AWK (Advisory population)		

		10 yr						
		8 yr						
		7 yr						
		6 yr						
		5 yr						
(%) k		4 yr						
Device Survival Probability (%)	ınt	3 yr						
Survival F	Years After Implant	2 yr	99.7 +.1/2 at 20 mo	99.3 +.2/3 at 20 mo			99.9 +.1/4 at 20 mo	96.6 +1.9/-4.3 at 20 mo
Device (Years At	1 yr	99.9	99.8	100.0 +.0/0 at 9 mo	100.0 +.0/0 at 9 mo	100.0	99.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le	toT	17		0		2	
ons (US)	n bromised	ToD	II		0		II	
unctions (US)	yrapy oction Mot npromised	The roJ			0			
Malfunctions (US)	ction Not npromised	The The ToD	= 16		0 = 0		2 =	
Malfunctions (US)	npromised retion Not norpromised	The Too The Too Too	= 16		0 = 0 +		+ 5	
Malfunctions (US)	stepy Function repy Function promised sery sery oction Not noromised	http://discourse.com/discourse	1 + 16 =		10,000 = 0 + 0 = 0		0 + 2 =	
Malfunctions (US)	ive US plants mal Battery sylvinorion repy Function promised repy repy repy repy repy repy	Esti Acti Imp Imp Inpe Ine Ine Ine Ine Ine Ine Ine Ine Ine In	8 + 1 + 16 =		10,000 = 0 + 0 = 0		7 0 + 2 =	
Malfunctions (US)	mated ive US shants mal Battery strions (US) trapy Function promised mysway trapy ction Not more	Region Con Con Con Con Con Con Con Con Con C	27,000 8 1 + 16 =		Aug-09 11,000 10,000 0 0 + 0 = 0		7,000 7 0 + 2 =	
Malfunctions (US)	paseed implants by a particular property of the	Region Con Con Con Con Con Con Con Con Con C	30,000 27,000 8 1 + 16 =		10,000 = 0 + 0 = 0		8,000 7,000 7 0 + 2 =	



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly Estimated Langevity

nom these estimates.					E	stimate	d Longe	vity		Elastiva		
					*						Replacement ERI)***	End of
Model Number 7289 7297	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency [*]	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

		Estimated Lo	ngevity		
Model Number	Family	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Time Indicators
8040	InSync	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	**
8042	InSync III	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	**

					Es	timated	d Longe	vity			mmended	
					*					Replace	ment (RRT)***	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency*	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
C154DWK, C164AWK, C174AWK	Concerto	DR+LV true	38 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 16 second charge time
D224TRK	Consulta CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16 second charge time
D274TRK	Concerto II	DR+LV true	38 cc/ 68 g	text	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16 second charge time
D284TRK	Maximo II CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16 second charge time

^{*} Volume and mass differ by connector style.

 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

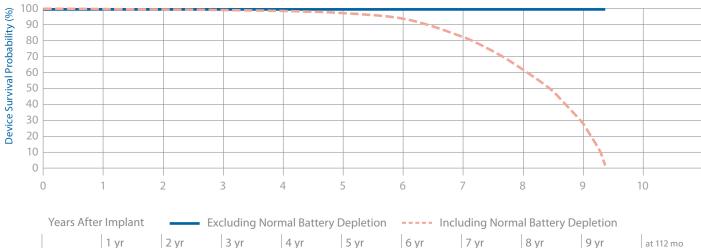
[‡] Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).



7227 GEM

Product Characteristics

US Market Release	Oct-98	Malfunctions (US)	153	NBD Code	VVEV
Registered US Implants	22,000			Serial Number Prefix	PIP, PLN, PLP,
Estimated Active US Implants	1,000				PLR
Normal Battery Depletions (US)	2,803			Max Delivered Energy	35 J
Advisories	None			Estimated Longevity	See page 36



		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 112 mo
%		99.7	99.6	99.5	99.4	99.2	99.2	99.1	99.0	99.0	99.0
%		99.3	98.9	98.6	98.0	97.1	94.1	81.2	61.5	26.5	3.2
#		20,000	17,000	15,000	13,000	11,000	9,000	6,000	4,000	1,000	200
	Effective Samp	ple Size									

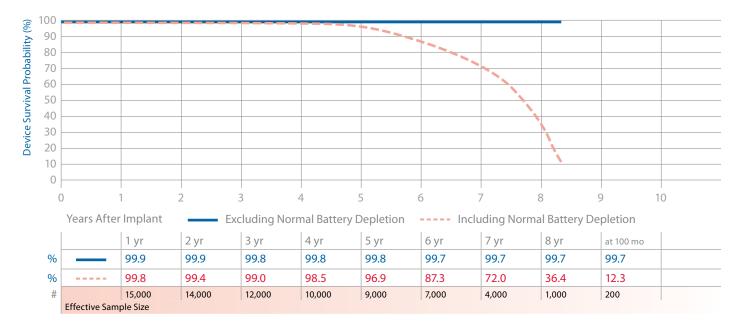
7230 Marquis VR

			_									
JS Mar	rket Release		De	c-02	Malfunctions (US)			52	NBD Coc	le		VVEV
Registe	ered US Implants	5	19,	000	Therapy Function	n Not Compron	nised	27	Serial Nu	mber Prefix		PKD, PLW, PLY
Estima	ted Active US Im	plants	7,	000	Electrical Cor	nponent		12				
Norma	l Battery Deplet	ions (US)		362	Software/Firr	nware		1	Max Deli	vered Energy		30 J
Adviso	ories: See page	144 – 2005 Po	otential		Possible Early	Battery Deplet	13	Estimate	d Longevity		See page 36	
	ture Battery Dep	letion Due to			Other			1				
Jactery	y Short				Therapy Function	n Compromised	d	25				
					Battery (17 mo	alfunctions relate	ed to advisory)	18				
					Electrical Con	nponent		7				
100												
90												
80									4			
70												
() 1		2	3	4	5	6	7	8	3	9	10
	Years After	mplant	E	xcludin	g Normal Batte	ry Depletion	li	ncludin	g Norma	l Battery D	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 y	r	at 89 mo		
%		100.0	99.9	99.9	99.8	99.7	99.6	99.	.3	98.8		
%		99.8	99.5	99.2	98.9	98.2	94.3	84.	.4	79.1		
#		17,000	13,000	11,000	10,000	9,000	5,000	1,00	00	100		
	Effective Samp	le Size										



7231 GEM III VR Product Characteristics

US Market Release	Dec-00	Malfunctions (US)	36	NBD Code	VVEV
Registered US Implants	17,000	Therapy Function Not Compromised	27	Serial Number Prefix	PJL
Estimated Active US Implants	3,000	Battery	1	Max Delivered Energy	30 J
Normal Battery Depletions (US)	2,062	Electrical Component	22	Estimated Longevity	See page 36
Performance Note: See page 154 –		Possible Early Battery Depletion	4		
Performance note on ICD Battery Discharge Behavior		Therapy Function Compromised	9		
		Battery	1		
		Electrical Component	8		



7232 Maximo VR **Product Characteristics**

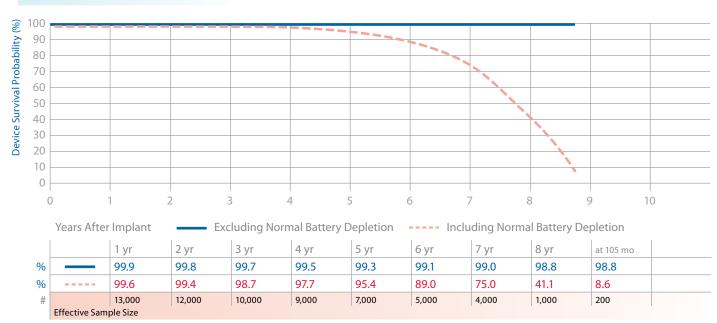
US Ma	rket Release		Od	ct-03	Malfun	ctions (US)			47	NBD Coc	le		VVED
Regist	ered US Implant	ts	44	,000	Thera	y Function N	ot Compromi	sed	35	Serial Nu	ımber Prefix		PRN
Estima	ated Active US Ir	mplants	26	,000	Ele	ectrical Compo	onent		17	Max Delivered Energy			35 J
Norma	al Battery Deple	tions (US)		320	Po	ssible Early Ba	ttery Depletio	n	17	Estimate	d Longevity		See page 36
Adviso	ories: See page	144 – 2005 Pc	tential		Ot	her			1				
Prema	ture Battery De		recition		Thera	y Function Co	ompromised		12				
Batter	y Short				Ele	ctrical Compo	onent		10				
					Ele	ctrical Interco	nnect		1				
					Po	ssible Early Ba	ttery Depletio	n	1				
% 100													
<u>F</u> 90													
ide 80													
Prob	0 1	1 2	2	3	4	1	5	6	7	8	3	9	10
Device Survival Probability (%)	Years After	Implant		Eveludin	a Norn	nal Battery	Doplotion	Ir	cludin	a Norma	l Battery D	oplotion	
urvi	ieais Aitei				g Norr	1		1	ICIUUIII	g Norma	ii battery Di	epietion	ı
S SI		1 yr	2 yr	3 yr		4 yr	5 yr	6 yr	at 7	'8 mo			
evic %		100.0	99.9	99.9		99.9	99.8	99.8	99	.8			
□ %		99.9	99.8	99.5		99.2	97.4	89.9	87.	9			
#		39,000	34,000	29,000)	21,000	9,000	1,000	100)			
	Effective Samp	ole Size											



7271 GEM DR

Product Characteristics

US Market Release	Oct-98	Malfunctions (US)	100	NBD Code	VVED
Registered US Implants	15,000			Serial Number Prefix	PIM
Estimated Active US Implants	500			Max Delivered Energy	27 J
Normal Battery Depletions (US)	1,927			Estimated Longevity	See page 36
Advisories	None				



7274 Marquis DR

JS Mar	ket Release		Ma	r-02	Malfund	ctions (US)			185	NBD Cod	le		VVED
Registe	ered US Implan	ts	48,	000	Therap	y Function No	t Compromise	ed	81	Serial Nu	mber Prefix		PKC
stima	ted Active US I	mplants	5,	000	Ba	ttery (3 malfun	ctions related to	advisory)	5	Max Deli	vered Energy		30 J
lorma	l Battery Deple	etions (US)	5,	069	Ele	ectrical Compo	nent		26	Estimate	d Longevity		See page 36
		e 144 – 2005 P			Po	ssible Early Bat	tery Depletion		50				
	ture Battery De <mark>/ Short</mark>	pletion Due to				y Function Co	•		104				
						ttery (71 malfur		o advisory)	77				
100					Ele	ctrical Compor	nent		27				
90													
80													
70													
60													
50													
40													
30													
20									1				
10													
0)	1	2	3		4	 5	6	7	8	 	9	10
)	1	_)	-	Ť)	0	/)	9	10
	Years After	r Implant	E	xcludin	g Norn	nal Battery [Depletion	In	cludi	ng Norma	l Battery D	epletion	
		1 yr	2 yr	3 yr		4 yr	5 yr	6 yr	7	yr	at 85 mo		
%		100.0	99.9	99.8		99.6	99.4	99.3		ý 9.2	99.2		
%		99.8	99.4	98.4		96.9	90.4	65.5	12	2.4	2.4		
#		42,000	34,000	26,00	0	22,000	18,000	8,000	1,0	000	200		
	Effective Sam	ple Size											



7275 GEM III DR

Product Characteristics

50											
40											
30											
						1					
20							`				
							1				
10							1				
10							1				
10											
							`				
20							1				
20											
30											
40											
50											
60											
70											
70											
80											
90											
100											
					Electrical Inter	connect		1			
					Electrical Com			8			
					•						
					Battery	•		2			
viscna	rge Behavior			т	herapy Function	Compromised		11			
erforr	mance note or	ICD Battery			Possible Early	Battery Depletion	on	17			
erfor	mance Note:	See page 154	_		Software/Firm	iware		1			
lorma	l Battery Depl	etions (US)	4	,123	Electrical Com	ponent		9	Estimated Longev	vity	See page
stima	ted Active US	Implants	1,	.000	Battery			1	Max Delivered En	ergy	30 J
egiste	ered US Implar	nts	20,	,000 T	herapy Function	Not Compromi	sed	28	Serial Number Pre	efix	PJM
	rket Release		Nov	/-00 Ma	alfunctions (US)			39	NBD Code		VVED

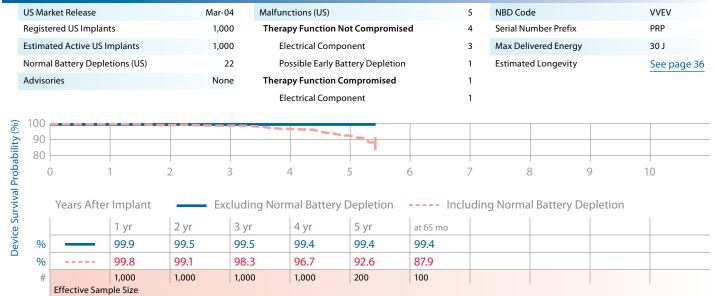
7278 Maximo DR

US Mar	rket Release		0	ct-03	Malfun	ctions (US)			40	NBD Code			VVED
Registe	ered US Implant	S	3	8,000	Thera	py Function N	ot Compromi	sed	32	Serial Numb	er Prefix		PRM
Estima	ted Active US In	nplants	18	8,000	Ele	ectrical Compo	nent		15	Max Deliver	ed Energy		35 J
Norma	l Battery Deplet	tions (US)		1,744	Po	ssible Early Ba	ttery Depletio	n	17	Estimated Lo	ongevity		See page 3
Adviso	ories: See page	144 – 2005 Po	otential		Thera	py Function Co	ompromised		8				
Premat	ture Battery De				Ele	ctrical Compo	nent		7				
Battery	y Short					ssible Early Ba		n	1				
100						•	, ,						
90 80 70 60 50 40													
80													
70													
60													
50								1					
40								1					
30								1					
() 1		2	3		4	5	6	7	8	9		10
	Years After	Implant		Excludir	ng Norr	nal Battery	Depletion		Includir	ig Normal B	attery Dep	etion	
		1 yr	2 yr	3 yr		4 yr	5 yr	6 yr	at	76 mo			
%		100.0	99.9	99.9)	99.9	99.8	99.8	99	.8			
%		99.9	99.6	99.1		97.4	88.3	57.4	36	.9			
#		33,000	29,000	25,00		19,000	10,000	1,000	20				
	Effective Samp										'		1



7288 Intrinsic **Product Characteristics**

56 IIIIIIISIC						Product Characteristics	
US Market Release	Aug-04	Malfunctions (US)			50	NBD Code	VVED
Registered US Implants	31,000	Therapy Function	Not Compromise	ed	43	Serial Number Prefix	PUB
Estimated Active US Implants	17,000	Battery			2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	1,030	Electrical Comp	oonent		15	Estimated Longevity	See page 3
Advisories	None	Software/Firm	ware		1		
		Possible Early E	Battery Depletion	n	25		
		Therapy Function	Compromised		7		
100		Electrical Comp	oonent		7		
100							
80							
70							
60			1				
50							
0 1 2	3	4	5	6	7	8 9	10
Years After Implant	Exclud	ling Normal Battery	/ Depletion	In	cludin	g Normal Battery Depleti	on
1 yr	2 yr 3 y	/r 4 yr	5 yr	at 68 mo			
	99.9 99		99.8	99.7			
% 99.9	99.6 99	.1 98.0	87.4	66.0			
# 28,000	26,000 22,	000 18,000	7,000	200			
Effective Sample Size							

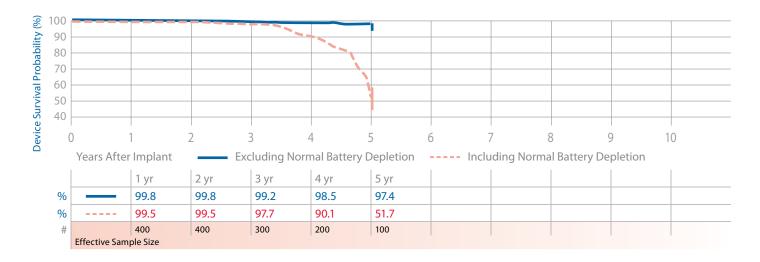




D153ATG, D153DRG EnTrust

Product Characteristics

US Market Release	Jun-05	Malfunctions (US)	7	NBD Code	DDED, VVED
Registered US Implants	500	Therapy Function Not Compromised	6	Serial Number Prefix	PNR
Estimated Active US Implants	100	Possible Early Battery Depletion	6	Max Delivered Energy	30 J
Normal Battery Depletions (US)	71	Therapy Function Compromised	1	Estimated Longevity	See page 37
Advisories	None	Electrical Component	1		



D154ATG, D154DRG EnTrust

Product Characteristics

	rket Release		Jun-05 Malfunctions (US)					64	NBD Code		DDED, VVEI
Registe	ered US Implan	ts	28,0	00 T ł	Therapy Function Not Compromised			56	Serial Number	Prefix	PNR
Estima	ted Active US Ir	mplants	18,0	00	Electrical Component			14	Max Delivered	Energy	35 J
Norma	l Battery Deple	tions (US)	2	200 Software/Firmware			2	Estimated Long	jevity	See page	
Adviso	ries		No	ne	Possible Early	Battery Deple	tion	40			
				Tł	erapy Function	n Compromis	ed	8			
					Electrical Con	nponent		8			
90 80						•					
80											
() .	1	2	3	4	5	6	7	8	9	10
90 80	Years After	Implant	E>	cluding N	lormal Batte	ry Depletio		Includir	ng Normal Bati	ery Depletio	on
%		100.0	99.9	99.8	99.7	99.6					
%		99.9	99.7	99.2	97.6	91.6					

Effective Sample Size



D154AWG, D164AWG Virtuoso DR **Product Characteristics** (N) (A) **US Market Release** May-06 Malfunctions (US) 52 1,043 **NBD** Code VVED PVV, PUL Registered US Implants 75,000 **Therapy Function Not Compromised** 30 1,040 Serial Number Prefix **Estimated Active US Implants** 59,000 1,040 Max Delivered Energy 35 J **Electrical Component** 9 Normal Battery Depletions (US) **Estimated Longevity** 88 **Electrical Interconnect** 1 See page 37 Advisories: See page 138 – 2009 Potential Reduced Device Longevity Possible Early Battery Depletion 20 **Therapy Function Compromised** 22 3 22 3 **Electrical Component**

Performance Note: See page 148

- Anomalies in MOSFET Integrated Circuit Technology





D154VRC EnTrust

Product Characteristics

154VIIC LIIIIUSC						Froduct Ch	iracteristics	
US Market Release	Jun-05	Jun-05 Malfunctions (US)				NBD Code		VVEV
Registered US Implants	14,000	Therapy Function	23	Serial Number	Prefix	PNT		
Estimated Active US Implants	10,000	Battery			2	Max Delivered	Energy	35 J
Normal Battery Depletions (US)	40	Electrical Component			9	Estimated Long	gevity	See page 3
Advisories	None	Possible Early	Battery Depletion	on	12			
		Therapy Function	Compromised		7			
		Electrical Com	nponent		7			
90 80 0 1 Years After Implant 1 yr 99.9	1	ling Normal Batter		6	7 Includir	8 ng Normal Batt	9 rery Depletio	10 on
1 yr	2 yr 3 y	yr 4 yr	at 57 mo					
99.9	99.9 99	99.7	99.6					
% 99.9	99.5 99	98.8	97.7					

200

4,000

D154VWC, D164VWC Virtuoso VR

Effective Sample Size

13,000

12,000

10,000

Product Characteristics

347 W	C, D104	VVVC VII	tuoso vk						Product	Character	ISTICS	
US Market	Release		May-06	Malfun	ctions (US)			18	NBD Code			VVEV
Registered	d US Implant	S	33,000	Thera	py Function No	ot Comprom	ised	8	Serial Nun	nber Prefix		PUN, PUP
Estimated	Active US In	nplants	27,000	El	ectrical Compo	nent		4	Max Deliv	ered Energy		35 J
Normal Ba	attery Deple	tions (US)	25	Ele	ectrical Intercor	nnect		1	Estimated	Longevity		See page 3
	Advisories: See page 138 – 2009			Po	ssible Early Bat	tery Depleti	on	3				
		vice Longevity		Thera	py Function Co	mpromised		10				
	ies in MOSFE	ee page 148 T Integrated Ci	ircuit	El	ectrical Compo	nent		10				
90 80 0 Ye												
0	1	1	2 3		4	5	6	7	8		9	10
Ye	ears After	Implant	Excl	uding Norr	mal Battery [Depletion		Includin	ig Normal	Battery De	epletion	
		1 yr	2 yr	3 yr	at 42 mo							
%		100.0	99.9	99.9	99.9							
%		99.9	99.7	99.6	99.5							
#		28,000	17,000	5,000	200							

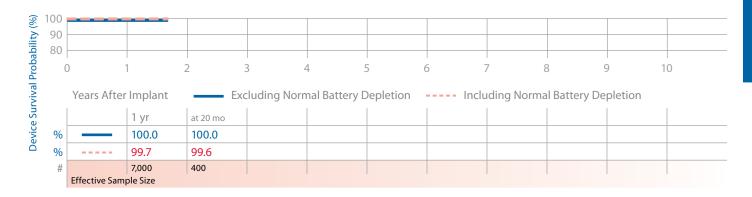
Effective Sample Size



D224DRG Secura DR

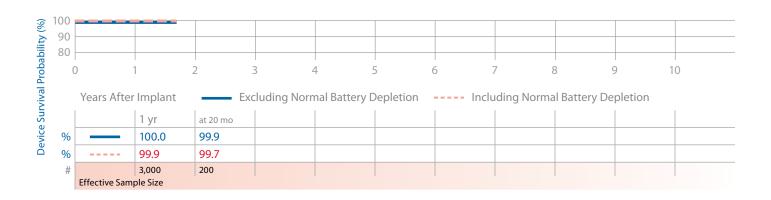
Product Characteristics

US Market Release	Aug-08	Malfunctions (US)	5	NBD Code	DDED
Registered US Implants	23,000	Therapy Function Not Compromised	2	Serial Number Prefix	DUH, PZE
Estimated Active US Implants	21,000	Electrical Component	2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	14	Therapy Function Compromised	3	Estimated Longevity	See page 37
Advisories	None	Electrical Component	2		
		Software/Firmware	1		



D224VRC Secura VR

US Market Release	Aug-08	Malfunctions (US)	3	NBD Code	VVEV
Registered US Implants	9,000	Therapy Function Not Compromised	1	Serial Number Prefix	PUX
Estimated Active US Implants	9,000	Possible Early Battery Depletion	1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	4	Therapy Function Compromised	2	Estimated Longevity	See page 37
Advisories	None	Electrical Component	1		
		Software/Firmware	1		

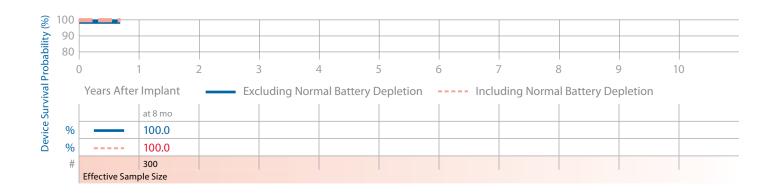




D274DRG Virtuoso II DR

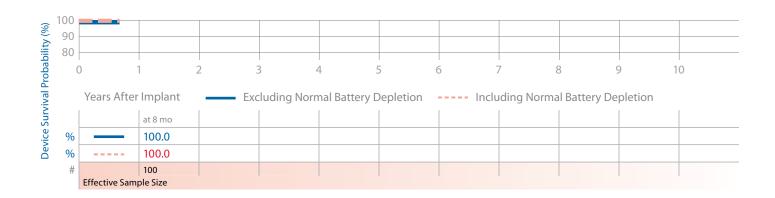
Product Characteristics

US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	VVED
Registered US Implants	7,000	Therapy Function Not Compromised	0	Serial Number Prefix	DUH, PZE
Estimated Active US Implants	7,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0			Estimated Longevity	See page 37
Advisories	None				



D274VRC Virtuoso II VR

US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	VVEV
Registered US Implants	3,000	Therapy Function Not Compromised	0	Serial Number Prefix	PUY, PZH
Estimated Active US Implants	3,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0			Estimated Longevity	See page 37
Advisories	None				

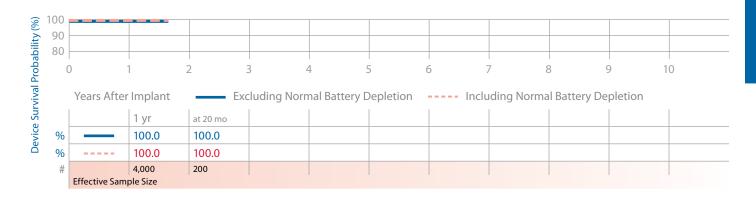




D284DRG Maximo II DR

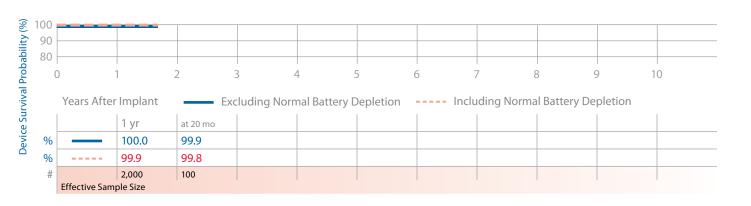
Product Characteristics

US Market Release	Mar-08	Malfunctions (US)	1	NBD Code	VVED
Registered US Implants	10,000	Therapy Function Not Compromised	0	Serial Number Prefix	PZM
Estimated Active US Implants	9,000	Therapy Function Compromised	1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0	Electrical Component	1	Estimated Longevity	See page 37
Advisories	None				



D284VRC Maximo II VR

US Market Release	Mar-08	Malfunctions (US)	3	NBD Code	VVEV
Registered US Implants	6,000	Therapy Function Not Compromised	0	Serial Number Prefix	PZN
Estimated Active US Implants	6,000	Therapy Function Compromised	3	Max Delivered Energy	35 J
Normal Battery Depletions (US)	1	Electrical Component	2	Estimated Longevity	See page 37
Advisories	None	Software/Firmware	1		





Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

						Malfur	Malfunctions (US)	(S)		Device S	urvival Pr	Device Survival Probability (%)	(%)					
		arket ase	stered nplants	bətar SU ə' stna	Val Battery (SU) snoite	apy Function promised	yqs toM not promised			Years Aft	Years After Implant	Ţ.						
Model Number	Family	geles NS N	igəЯ 11 SU	vitoA		тhег Сот		stoT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
7227	GEM	Oct-98	22,000	1,000	2,803	1	T	153	Excluding Normal Battery Depletion	99.7	99.6	99.5	99.4	99.2	99.2	99.1 +.1/2	99.0 +.2/2	99.0 +.2/2 at 112 mo
									Including Normal Battery Depletion	99.3	98.9	98.6	98.0	97.1 +.3/3	94.1	81.2 +.8/8	61.5	3.2 +.9/8 at 112 mo
7230	Marquis VR	Dec-02	19,000	2,000	362	25 +	27 =	52	Excluding Normal Battery Depletion	100.0	99.9	99.9	99.8	99.7	99.6	99.3 +.2/3	98.8 +.6/-1.1 at 89 mo	
	Advisories: <u>See page 144</u> – 2005 Potential Premature Battery Depletion Due to Battery Short	e page 144 – e to Battery SI	2005 Poten hort	ıtial Prematur	re Battery	(17) + (advisor	(17) + (0) (17) (advisory-related subset)	(17) ubset)	Including Normal Battery Depletion	99.8	99.5	99.2 +.1/2	98.9 +.2/2	98.2 +.2/3	94.3	84.4 +1.2/-1.3	79.1 +2.2/-2.5 at 89 mo	
7231	GEMIIIVR	Dec-00	17,000	3,000	2,062	6	27 =	36	Excluding Normal Battery Depletion	99.9	99.9	99.8 +.1/1	99.8 +.1/1	99.8 +.1/1	99.7	99.7	99.7	99.7 +.1/1 at 100 mo
	See page 154 – Performance note on ICD Battery Discharge Behavior	– Performanc navior	e note on l	CD Battery					Including Normal Battery Depletion	99.8	99.4	99.0	98.5	96.9	87.3 +.7/7	72.0	36.4 +1.5/-1.5	12.3 +1.7/-1.6 at 100 mo
7232	Maximo VR	Oct-03	44,000	26,000	320	12 +	35 =	47	Excluding Normal Battery Depletion	100.0	99.9	99.9	99.9	99.8	99.8	99.8 +.0/1 at 78 mo		
	Advisories: <u>See page 144</u> – 2005 Potential Premature Battery Depletion Due to <u>Battery</u> Short	e page 144 – e to Battery SI	2005 Poter hort	ntial Prematu	re Battery	(0) + (advisory	+ (0) = (0) isory-related subset)	(0) bset)	Including Normal Battery Depletion	99.9	99.8	99.5	99.2	97.4 +.3/3	89.9	87.9 +1.5/-1.7 at 78 mo		
7271	GEM DR	Oct-98	15,000	500	1,927	1	I	100	Excluding Normal Battery Depletion	99.9	99.8	99.7	99.5 +.1/2	99.3 +.1/2	99.1	99.0	98.8 +.2/3	98.8 +.2/3 at 105 mo
									Including Normal Battery Depletion	99.6	99.4	98.7	97.7	95.4 +.4/5	89.0	75.0	41.1	8.6 +1.5/-1.3 at 105 mo
7274	Marquis DR	Mar-02	48,000	5,000	5,069	+ + + +	18	185	Excluding Normal Battery Depletion	100.0	99.9	99.8	99.6	99.4	99.3 +.1/1	99.2 +.1/2	99.2 +.1/1 at 85 mo	
	Advisories: See page 144 – 2005 Potential Premature Battery Depletion Due to Battery Short	e page 144 – e to Battery SI	2005 Poter hort	ntial Prematu	re Battery	(71) + (advisory	(71) + (3) = (74) (advisory-related subset)	(74) bset)	Including Normal Battery Depletion	99.8	99.4	98.4	96.9	90.4	65.5	12.4	2.4 +.7/6 at 85 mo	

Device	Device Survival Summary continued	umma	ry contil	nued	ŀ	Malfunctions		Device	Device Survival Probability (%)	robability	(%)					
		Narket sase	istered mplants	bətem 2U əvi stnsl	mal Battery snoitelt	rapy Function npromised rapy ction Not npromised		Years A	Years After Implant	nt						
Model	Family	NS N	I SN Bəy	ıзэА		Con The		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
7275	GEM III DR	Nov-00	20,000	1,000	4,123	11 + 28 = 39	Excluding Normal Battery Depletion	99.9 y +.0/0	99.9	99.8 +.1/1	99.8	99.7	99.7	99.7 +.1/1 at 73 mo		
	See page 154 – Performance note on ICD Battery Discharge Behavior	- Performan avior	ce note on IC	CD Battery			Including Normal Battery Depletion	9 99.6 y +.1/1	99.0	96.9 +.3/3	90.2 +.5/5	64.7	11.8	2.3 +.6/5 at 73 mo		
7278	Maximo DR	Oct-03	38,000	18,000	1,744	8 + 32 = 40	Excluding Normal Battery Depletion	y +.0/0	99.9	99.9	99.9	99.8 +.0/1	99.8 +.0/1	99.8 +.0/1 at 76 mo		
	Advisories: <u>See page 144</u> – 2005 Potential Premature Battery Depletion Due to <u>Battery</u> Short	to Battery	- 2005 Poten short	itial Prematui	re Battery	(0) + (0) = (0) (advisory-related subset)	Including Normal Battery Depletion	99.9 y +.0/0	99.6	99.1	97.4	88.3 +.5/5	57.4 +1.6/-1.6	36.9 +3.1/-3.1 at 76 mo		
7288	Intrinsic	Aug-04	31,000	17,000	1,030	7 + 43 = 50	Excluding Normal Battery Depletion	g 100.0 y +.0/0	99.9	99.9	99.8 +.0/1	99.8 +.1/1	99.7 +.1/2 at 68 mo			
							Including Normal Battery Depletion	99.9 y +.0/0	99.6	99.1	98.0 +.2/2	87.4 +.6/6	66.0 +2.6/-2.8 at 68 mo			
7290	Onyx	Mar-04	1,000	1,000	22	+ + 5 = 5	Excluding Normal Battery Depletion	g 99.9 y +.1/7	99.5	99.5	99.4	99.4 +.4/9	99.4 +.4/9 at 65 mo			
							Including Normal Battery Depletion	99.8 y +.2/7 n	99.1	98.3 +.7/-1.2	96.7	92.6 +2.0/-2.7	87.9 +3.4/-4.6 at 65 mo			
D153ATG, D153DRG	EnTrust DR	Jun-05	200	100	77	1 + 6 = 7	Excluding Normal Battery Depletion	99.8 y +.2/-1.4	99.8	99.2 +.6/-1.7	98.5 +.9/-2.1	97.4 +1.4/-3.0				
							Including Normal Battery Depletion	g 99.5 y +.3/-1.4 n	99.5	97.7	90.1 +3.0/-4.2	51.7 +6.9/-7.4				
D154ATG, D154DRG	EnTrust DR	Jun-05	28,000	18,000	200	8 + 56 = 64	4 Excluding Normal Battery Depletion	y +.0/0	99.9	99.8	99.7	99.6 +.1/2 at 58 mo				
							Including Normal Battery Depletion	y +.0/1	99.7	99.2	97.6 +.2/3	91.6 +1.8/-2.2 at 58 mo				
D154AWG D164AWG (Non-advisory population)	Virtuoso DR	May-06	72,000	58,000	80	22 + 30 = 52	Excluding Normal Battery Depletion	y +.0/0	99.9	99.9	99.9 +.0/1 at 46 mo					
							Including Normal Battery Depletion	99.9 y +.0/0	99.7	99.3 +.1/1	98.9 +.3/3 at 46 mo					

		8 yr												
		7 yr												
		6 yr												
		5 yr				99.6 +.2/3 at 57 mo	97.7 +.7/-1.0 at 57 mo							
y (%)		4 yr	60.4 +2.0/-2.1 at 44 mo	16.2 +1.9/-1.8 at 44 mo		99.7	98.8 +.2/2	99.9 +.1/1 at 42 mo	99.5 +.1/2 at 42 mo					
Device Survival Probability (%)	ant	3 yr	90.6 +1.0/-1.1	80.8 +1.4/-1.4		99.8	99.2 +.1/2	99.9	99.6					
Survival	Years After Implant	2 yr	99.8	99.6		99.9	99.5	99.9	99.7		100.0 +.0/1 at 20 mo	99.6 +.1/2 at 20 mo	99.9 +.0/2 at 20 mo	99.7 +.1/2 at 20 mo
Device	Years A	1 yr	100.0	99.9		99.9	99.9	100.0	99.9		100.0	99.7	100.0	99.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le	.toT	1,043			30		18			5		ю	
ons	ction Not besimorqr		1,040 =			23 =		II ∞			5 =			
Malfunctions	npromised rapy	ЭЧΣ	+			+		+			+		+	
Ma	rapy Function		m			7		01			m		. 2	
	mal Battery Actions	Nor	- ∞	peo	c	40		25	peo	E	14		4	
	bətem SU əvi stnsi	itοΑ	1,000	ential Redu	Anomalies i y	10,000		27,000	ential Redu	Anomalies i y	21,000		0006	
	istered mplants	I SN Gəy	4,000	3 – 2009 Pot	ice note on Technolog	14,000		33,000	<u>s</u> – 2009 Pot	ice note on Technolog	23,000		000′6	
	Narket sase		May-06	e page 148 ity	- Performan ated Circuit	Jun-05		May-06	e page 138 ity	- Performan ated Circuit	Aug-08		Aug-08	
		Family	Virtuoso DR	Advisories: <u>See page 148</u> – 2009 Potential Reduced Device Longevity	See page 148 – Performance note on Anomalies in MOSFET integrated Circuit Technology	EnTrust VR		Virtuoso VR	Advisories: See page 138 – 2009 Potential Reduced Device Longevity	See page 148 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	Secura DR		Secura VR	
		_												

		6yr 7yr 8yr								
		5 yr								
ty (%)		4 yr								
robabili	nt	3 yr								
Device Survival Probability (%)	Years After Implant	2 yr					100.0 +.0/1 at 20 mo	100.0 +.0/1 at 20 mo	99.9 +.1/3 at 20 mo	99.8 +.1/3 at 20 mo
Device	Years A	1 yr	100.0 +.0/0 at 8 mo	100.0 +.0/0 at 8 mo	100.0 +.0/0 at 8 mo	100.0 +.0/0 at 8 mo	100.0	100.0 +.0/1	100.0	99.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion						
	Įe	toT	0		0		-		m	
ctions	rapy ction Not npromised	un⊣	0		0		0		0	
Malfunctions	rapy Function npromised		+		+		+		+ m	
,	mal Battery sletions	Nor	0		0		0		-	
	bətem SU əvi stnslı	iзэА	2,000		3,000		000′6		6,000	
	istered Implants	I SN ɓəy	2,000		3,000		10,000		000′9	
	Market ease		Aug-09		Aug-09		Mar-08		Mar-08	
		Family	Virtuoso II DR		Virtuoso II VR		Maximo II DR		Maximo II VR	
		Model	D274DRG		D274VRC		D284DRG		D284VRC	



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					E	stimate	d Longe	vity		Elective	Replacement	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing		Charge Time Time Time	End of Life (EOL) Battery Voltage
7227	GEM	B, Cx, D, E	49 cc* 90 g	35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	_	≤ 2.40 V [§]
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231	GEM III VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	-	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V [§]
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.4 6.1	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V	> 16-second charge time	≤ 2.40 V

^{*} Volume and mass differ by connector style.

 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

[§] For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If three consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.



Reference Chart continued

						stimate	d Longe	vity		Repla	nmended acement RT)***	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16 second charge time
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16 second charge time
D154AWG, D164AWG	Virtuoso	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 16 second charge time
D154VRC	EnTrust	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16 second charge time
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 16 second charge time
D224DRG	Secura DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.60 5.07 5.70	4.08 6.05 7.00	4.50 7.00 8.27	4.67 7.50 9.00	≤ 2.63 V	_	3 months after RRT or > 16 second charge time
D224VRC	Secura VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.33 6.67 7.76	4.67 7.45 8.85	4.92 8.05 9.79	5.00 8.41 10.25	≤ 2.63 V	_	3 months after RRT or > 19 second charge time
D274DRG	Virtuoso II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.0 5.7	4.0 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16 second charge time
D274VRC	Virtuoso II VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.0 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19 second charge time
D284DRG	Maximo II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.60 5.07 5.70	4.08 6.05 7.00	4.50 7.00 8.27	4.67 7.50 9.00	≤ 2.63 V	_	3 months after RRT or > 16 second charge time
D284VRC	Maximo II VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.33 6.67 7.76	4.67 7.45 8.85	4.92 8.05 9.79	5.00 8.41 10.25	≤ 2.63 V	_	3 months after RRT or > 19 second charge time

^{*} Volume and mass differ by connector style.

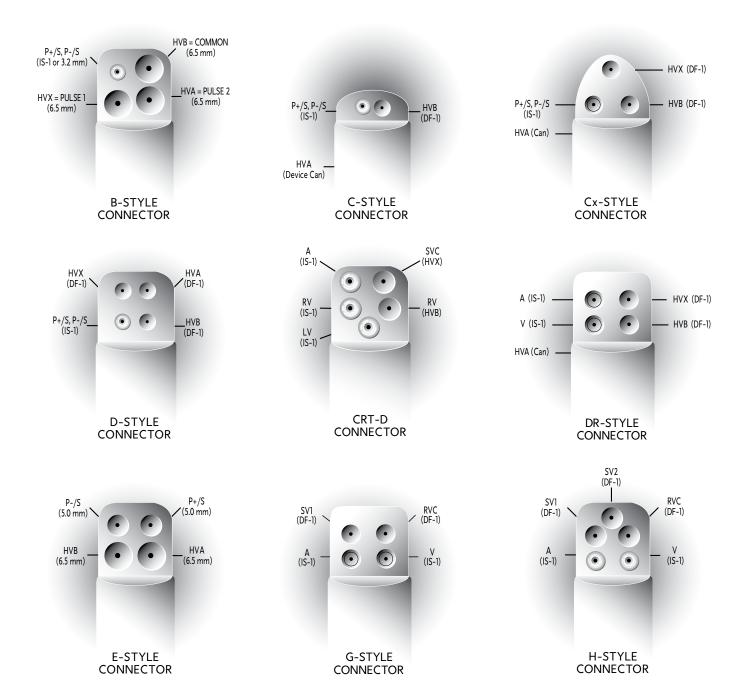
^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

^{***} The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel.



ICD Connector Styles

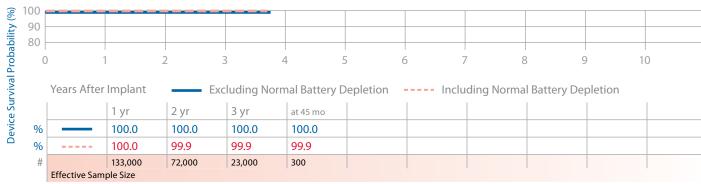




Adapta DR ADDR01, ADDR03, ADDR06, ADD01

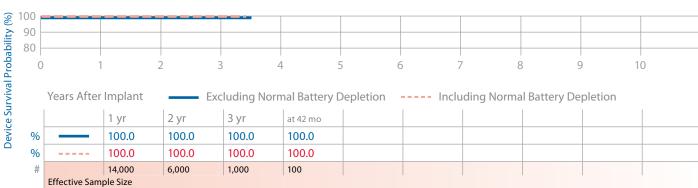
Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	28	NBG Code	DDDR, DDD
Registered US Implants	202,000	Therapy Function Not Compromised	19	Serial Number Prefix	PWB, PWD,
Estimated Active US Implants	168,000	Electrical Component	19		PWC, PWF, NWB, NWC,
Normal Battery Depletions (US)	22	Therapy Function Compromised	9		NWD
Advisories	None	Electrical Component	9	Estimated Longevity	See page 72
Advisories	None	Electrical Component	9	Estimated Longevity	See pa



Adapta DR ADDRL1

US Market Release	Jul-06	Malfunctions (US)	3	NBG Code	DDDR
Registered US Implants	27,000	Therapy Function Not Compromised	2	Serial Number Prefix	PWE, NWE
Estimated Active US Implants	24,000	Electrical Component	2		
Normal Battery Depletions (US)	0	Therapy Function Compromised	1	Estimated Longevity	See page 72
Advisories	None	Electrical Interconnect	1		
3 100					
§ 100					



Adapta DR ADDRS1

Product Characteristics

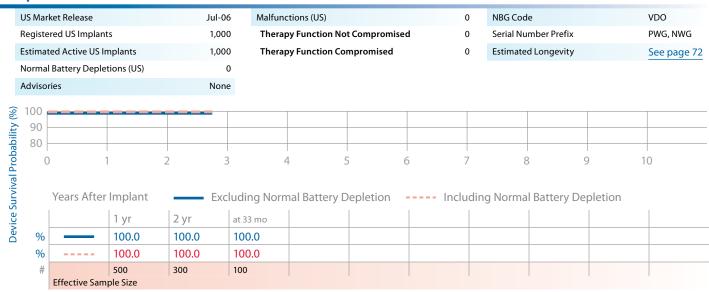
uapta	I DK ADDI	(5)							Product Cha	racteristics	
US Mai	rket Release		Jul-(06 Malfu	unctions (US)			2	NBG Code		SSIR
Registe	ered US Implant	ts .	19,00	00 The	rapy Function N	lot Compro	mised	1	Serial Number I	Prefix	PWA
Estima	ted Active US Ir	nplants	16,00	00	Electrical Comp	onent		1			
Norma	l Battery Deple	tions (US)		12 The	rapy Function C	Compromise	ed	1	Estimated Long	evity	See page 72
Adviso	ries		Nor	ne	Electrical Comp	onent		1			
Device Survival Probability (%) 8 00 00) 1		2	3	4	5	6	7	8	9	10
urvival	Years After	Implant	1		ormal Battery	Depletion	n	Includin	g Normal Batt	ery Depletio	n
S		1 yr	2 yr	3 yr	at 43 mo						
% exi		100.0	100.0	100.0	100.0						
۵ %		100.0	99.8	99.7	99.0						
#		12,000	6,000	2,000	200						
	Effective Sam	ple Size									

Adapta SR ADSR01, ADSR03, ADSR06

US Mark	ket Release		Jul-	06 Ma	lfunctions (US)			2	NBG Code		SSIR
Registe	red US Implant	is	38,00	00 Th	erapy Function	Not Comp	promised	0	Serial Numbe	r Prefix	NWN, NWM,
Estimate	ed Active US In	nplants	29,00	00 T h	erapy Function	Compron	nised	2			NWP
Normal	Battery Deple	tions (US)		13	Electrical Comp	onent		1	Estimated Lo	ngevity	See page 7
Advisor	ies		Noi	ne	Electrical Interc	onnect		1			
100 🕳											
90 -											
80 -											
0	1		2	3	4	5	6	7	8	9	10
90 - 80 - 0											
	Years After	Implant	Ex	cluding N	lormal Battery	Deplet	ion	 Includin 	g Normal Ba	ttery Deplet	ion
		1 yr	2 yr	3 yr	at 44 mo						
%		100.0	100.0	100.0	100.0						
%		100.0	100.0	99.7	99.6						
#		24,000	13,000	4,000	200						
	Effective Sam	ple Size									

Adapta VDD ADVDD01

Product Characteristics

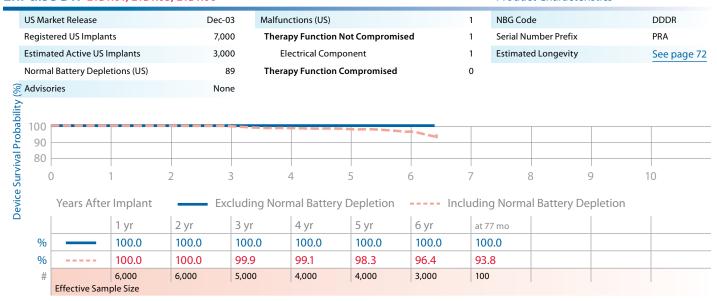


AT500 AT501, 7253 US Market Release

JS Market Release		Mar-03	Malfun	ctions (US)			10	NBG Code	DDDRP
gistered US Implants		11,000) Thera	py Function No	t Compromise	d	5	Serial Number Prefix	IJF
stimated Active US Impl	ants	1,000	1,000 Electrical Component			2	Estimated Longevity	See page 72	
lormal Battery Depletions (US)		1,608	B Po	ossible Early Bat	tery Depletion		3		
erformance Note: <u>See pa</u> erformance note on AT5	age 152 -		Thera	py Function Co	mpromised		5		
ystem Follow-Up Protoc			Electrical Component						
			El	ectrical Intercor	nect		1		
			Po	ossible Early Bat	tery Depletion		1		
100									
90									
70									
60									
50									
40									
30									
20						1			
10						1			
0									
0 1	2	3		4 !	5	6	7	8 9	10
Years After Im	plant •	Exc	luding Norr	mal Battery [epletion	In	cludin	g Normal Battery Depletion	
1	yr 2	2 yr	3 yr	4 yr	5 yr	6 yr	at	77 mo	
	_	100.0	100.0	99.9	99.9	99.9	99	.9	
% 99	9.9	99.8	99.5	97.4	82.6	42.7	10	.3	
# 10	0,000 9	9,000	8,000	7,000	5,000	1,000	10)	
Effective Sample	Size								

EnPulse DR E1DR01, E1DR03, E1DR06

Product Characteristics



EnPulse DR E1DR21

d US Implant I Active US In attery Deple	nplants	2,0 4			Not Compromise	d	0	Serial Number Prefix	PPT
attery Deple		4	00 The			-	U	Serial Number Prefix	PPT
	tions (US)		oo iiie	rapy Function Compromised			0	Estimated Longevity	See page
	(03)	1	60						
S		No	ne						
						I			
1		2	3	4	5	6	7	8 9	10
٠		_					, I I		
ears After	Implant	E>	cluding No	rmai Battery	Depletion	Inc	cluding	g Normal Battery Dep	letion
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 7	4 mo	
	100.0	100.0	100.0	100.0	100.0	100.0	100	0.0	
	99.9	99.6	98.9	96.4	91.9	61.2	56.	.1	
	2,000	1,000	1,000	1,000	1,000	300	100		
	ears After	1 ears After Implant 1 yr 100.0 99.9	1 2 ears After Implant	1 2 3 ears After Implant Excluding No 1 yr 2 yr 3 yr 100.0 100.0 100.0 99.9 99.6 98.9 2,000 1,000 1,000	1 2 3 4 ears After Implant Excluding Normal Battery 1 yr 2 yr 3 yr 4 yr 100.0 100.0 100.0 100.0 99.9 99.6 98.9 96.4 2,000 1,000 1,000 1,000	1 2 3 4 5 ears After Implant Excluding Normal Battery Depletion 1 yr	1 2 3 4 5 6 ears After Implant — Excluding Normal Battery Depletion ————————————————————————————————————	1 2 3 4 5 6 7 ears After Implant Excluding Normal Battery Depletion Including 1 yr	1 2 3 4 5 6 7 8 9 ears After Implant — Excluding Normal Battery Depletion Including Normal Battery Dep 1 yr

Feb-04

101,000

59,000

369

None



US Market Release

Advisories

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

EnPulse 2 DR E2DR01, E2DR03, E2DR06

Malfunctions (US)	20
Therapy Function Not Compromised	16
Electrical Component	14
Possible Early Battery Depletion	2
Therapy Function Compromised	4
Battery	1

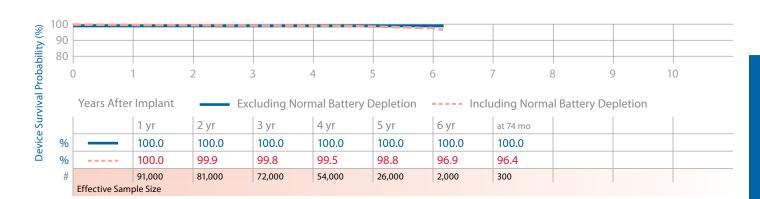
Electrical Component

Electrical Interconnect

Product Characteristics

2

NBG Code	DDDR
Serial Number Prefix	PNB, PNC, PNH
Estimated Longevity	See page 72



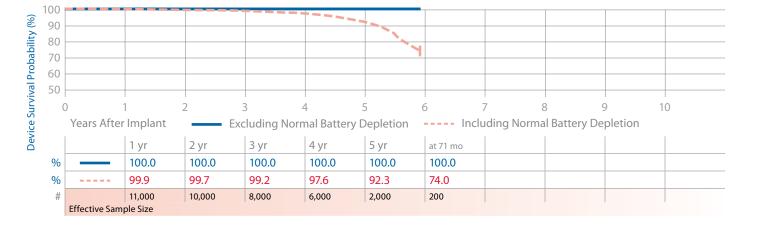
EnPulse 2 DR E2DR21

US Market Release Feb-04 Registered US Implants 12,000 **Estimated Active US Implants** 6,000 Normal Battery Depletions (US) 293 Advisories None

Malfunctions (US) **Therapy Function Not Compromised Therapy Function Compromised**

0 **Electrical Component**

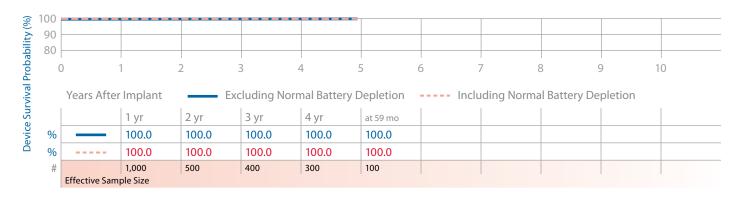
NBG Code	DDDR
Serial Number Prefix	PMU
Estimated Longevity	See page 72



EnPulse 2 DR E2DR31, E2DR33

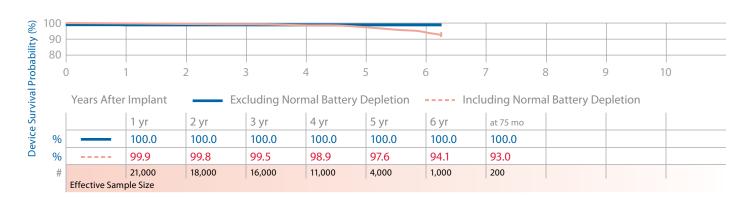
Product Characteristics

US Market Release	Feb-04	Malfunctions (US)	0	NBG Code	DDDR
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PNL
Estimated Active US Implants	300	Therapy Function Compromised	0	Estimated Longevity	See page 72
Normal Battery Depletions (US)	0				
Advisories	None				



EnPulse 2 SR E2SR01, E2SR03, E2SR06

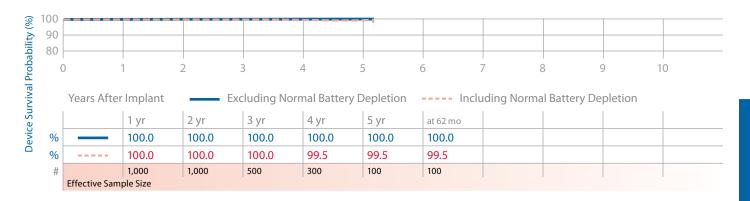
US Market Release	Dec-03	Malfunctions (US)	4	NBG Code	SSIR
Registered US Implants	25,000	Therapy Function Not Compromised	3	Serial Number Prefix	PMW, PMY,
Estimated Active US Implants	12,000	Electrical Component	2		PNA
Normal Battery Depletions (US)	161	Possible Early Battery Depletion	1	Estimated Longevity	See page 72
Advisories	None	Therapy Function Compromised	1		
		Other	1		



EnPulse 2 VDD E2VDD01

Product Characteristics

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PMV
Estimated Active US Implants	400	Therapy Function Compromised	0	Estimated Longevity	See page 72
Normal Battery Depletions (US)	8				
Advisories	None				



EnRhythm DR P1501DR

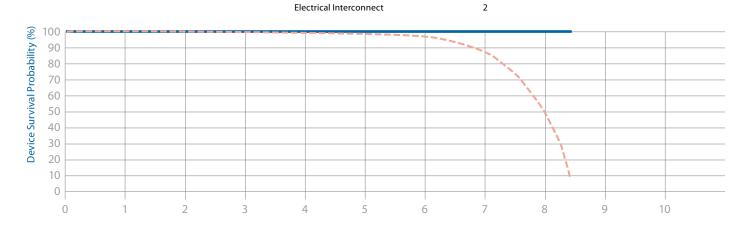
US Market Release		May-05	Ma	Ifunctions (US)			76	NBG Code			DDDRP	
Registered US Implant	ts	97,000) Th	erapy Function	Not Compron	nised	41	Serial Numb	er Prefix		PNP	
Estimated Active US In	mplants	70,000)	Battery			16	Estimated L	ongevity		See page 72	
Normal Battery Deple	tions (US)	38	3	Electrical Co	mponent		10					
Advisories: See page Voltage Displayed at D				Possible Earl	ly Battery Dep	letion	15					
De Comment Notes Co	140		Th	nerapy Function	Compromised	d	35					
Performance Note: Se Anomalies in MOSFET				Electrical Co	mponent		33					
Circuit Technology				Electrical Int	erconnect		1					
				Possible Earl	ly Battery Dep	letion	1					
90 80 90 Years After	1	2 3		4	5	6	7	8	(9	10	-
Years After		— Exc		lormal Battery	y Depletion	In	cludin	g Normal B	attery De	pletion	1	
	1 yr	2 yr	3 yr	4 yr	5 yr	at 61 mo						_
K % —	100.0	100.0	99.9	99.9	99.8	99.8						
%	100.0	99.9	99.8	99.6	98.9	98.9						_
#	76,000	58,000	42,000	20,000	1,000	100						
Effective Samp	ole Size											



Kappa 400 DR KDR401, KDR403

Library and a second			
US Market Release	Jan-98	Malfunctions (US)	22
Registered US Implants	47,000	Therapy Function Not Compromised	13
Estimated Active US Implants	2,000	Electrical Component	9
Normal Battery Depletions (US)	6,709	Electrical Interconnect	1
Advisories	None	Possible Early Battery Depletion	2
		Other	1
		Therapy Function Compromised	9
		Electrical Component	7

NBG Code	DDD/RO
Serial Number Prefix	PER, PET
Estimated Longevity	See page 72



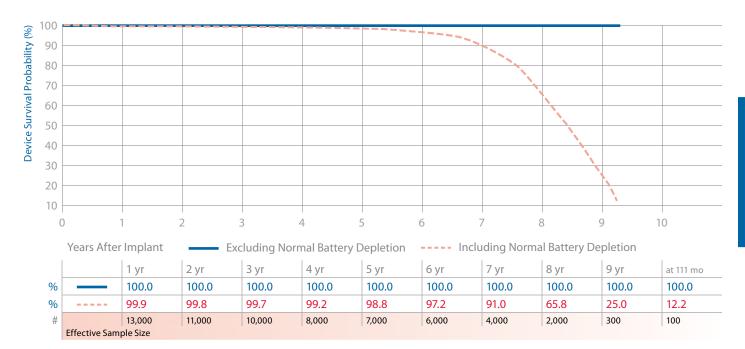
	Years After Implant		After Implant Excluding Normal Battery Depletion					Including Normal Battery Depletion				
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 101 mo		
%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9		
%		99.9	99.9	99.7	99.5	98.9	97.0	86.4	47.7	8.2		
#		42,000	38,000	34,000	30,000	26,000	22,000	15,000	5,000	1,000		
	Effective Sample Size											



Kappa 400 SR KSR401, KSR403

· ·		
US Market Release	Feb-98	Malfunctions (US)
Registered US Implants	15,000	Therapy Function Not Compromised
Estimated Active US Implants	1,000	Electrical Component
Normal Battery Depletions (US)	1,198	Possible Early Battery Depletion
Advisories	None	Therapy Function Compromised
		Electrical Interconnect

NBG Code	SSI/R
Serial Number Prefix	PEU, PGD
Estimated Longevity	See page 72



24,000

3,407

5

US Market Release Registered US Implants

Estimated Active US Implants

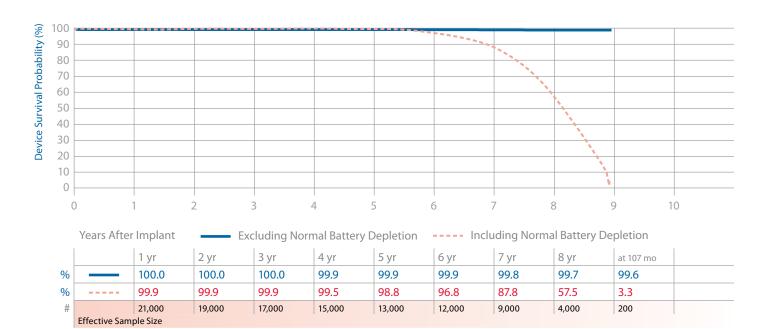
Normal Battery Depletions (US)

Advisories: See page 145 – 2002 Potential Fractured Power Supply Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires

Kappa 600 DR KDR601, KDR603, KDR606

Malfunctions (US)	39
Therapy Function Not Compromised	3
Electrical Component	3
Therapy Function Compromised	35
Electrical Component	2
Electrical Interconnect (33 malfunctions related to advisory)	33

NBG Code	DDD/RO
Serial Number Prefix	PHF, PHH, PHG
Estimated Longevity	See page 72



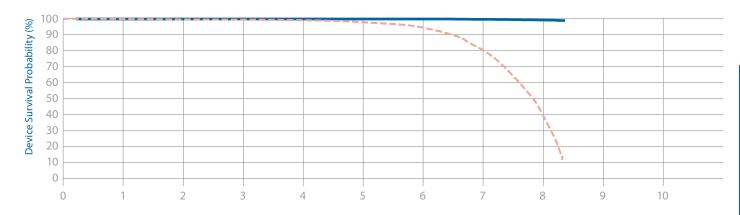


Kappa 600 DR KDR651, KDR653

US Market Release	Mar-01	Malfunctions (US)	32
Registered US Implants	14,000	Therapy Function Not Compromised	2
Estimated Active US Implants	1,000	Electrical Component	1
Normal Battery Depletions (US)	1,758	Possible Early Battery Depletion	1
Advisories: See page 145 – 2002 Potential		Therapy Function Compromised	30
Fractured Power Supply Wires; See also		Electrical Component	1
page 139 – 2009 Potential Separation of Interconnect Wires		Electrical Interconnect (21 malfunctions related to advisory)	29

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PLJ, PLK
Estimated Longevity	See page 72



	Years After Implant		Exc	luding Norn	nal Battery D	epletion	Inclu	ıding Norma	l Battery De	pletion
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 100 mo
%		100.0	100.0	100.0	100.0	100.0	99.9	99.7	99.5	99.4
%		99.9	99.9	99.8	99.4	98.1	94.8	80.5	40.4	13.5
#		13,000	11,000	10,000	9,000	8,000	7,000	5,000	1,000	200
	Effective Samp	ple Size								

Карра 700 D кр701, кр703, кр706

US Marl	ket Release		Jai	n-99	Malfunctions (US)			0	NBG Code		DDD
Registe	red US Implant	is		300	Therapy Function Not Compromised		0	Serial Number Prefi	x	PHK	
Estimat	ed Active US In	mplants		40	Therapy Function	Compromised		0	Estimated Longevit	у	See page 73
Normal	Battery Deplet	tions (US)		17							
Fracture page 1	ries: See page ed Power Supp 39 – 2009 Pote nnect Wires	ly Wires; See a	also								
							_				
100								_+	`		
100 90 80 0) 1	 	2	3	4	5	6	7	8	9	10
100 90 80 0	1 Years After				4 g Normal Battery	5	6	7	8 g Normal Battery		
100 90 80 0		Implant	E	Excludin	g Normal Battery	5 / Depletion	6 In	7	8 g Normal Battery at 91 mo		
90 - 80 -		Implant	2 yr	Excluding 3 yr	g Normal Battery 4 yr 100.0	5 Depletion 5 yr	6 In 6 yr	7 cludin	g Normal Battery r at 91 mo 0.0 100.0		

Feb-99

192,000

26,000

22,803



US Market Release

Registered US Implants

Estimated Active US Implants

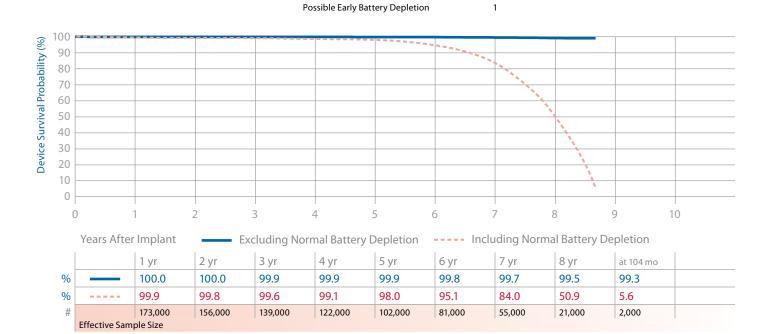
Normal Battery Depletions (US)

Kappa 700 DR KDR701, KDR703, KDR706

Advisories: See page 145 – 2002 Potential Fractured Power Supply Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires

Malfunctions (US)	464
Therapy Function Not Compromised	31
Battery	1
Electrical Component	24
Electrical Interconnect	1
Possible Early Battery Depletion	3
Other	2
Therapy Function Compromised	433
Electrical Component	15
Electrical Interconnect (330 malfunctions related to advisory)	417

NBG Code	DDD/RO
Serial Number Prefix	PGU, PGY, PGW
Estimated Longevity	See page 73





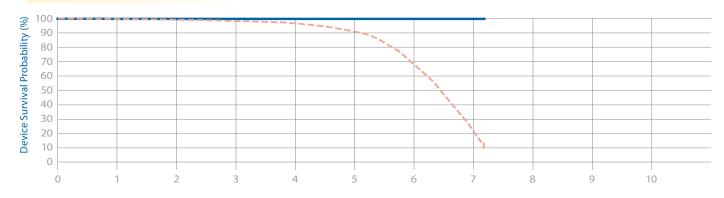
Kappa 700 DR KDR721

US Market Release	Feb-99	Malfunctions (US)
Registered US Implants	10,000	Therapy Function Not Compromised
Estimated Active US Implants	0	Electrical Component
Normal Battery Depletions (US)	1,301	Therapy Function Compromised
Advisories: See page 145 – 2002 Potential Fractured Power Supply Wires; See also		Electrical Interconnect (4 malfunctions related to advisory)

Fractured Power Supply Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires

Product Characteristics

tions (US)	5	NBG Code	DDD/RO
y Function Not Compromised	1	Serial Number Prefix	PGR
ctrical Component	1	Estimated Longevity	See page 73
y Function Compromised	4		



	Years After	Implant	Exc	luding Norn	nal Battery D	epletion	Inclu	iding Norma	l Battery De	pletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 86 mo		
%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9		
%		99.9	99.6	98.8	96.7	91.0	68.7	22.1	11.7		
#		8,000	7,000	7,000	6,000	4,000	2,000	300	100		
	Effective Sam	ple Size									

Kappa 700 SR KSR701, KSR703, KSR706

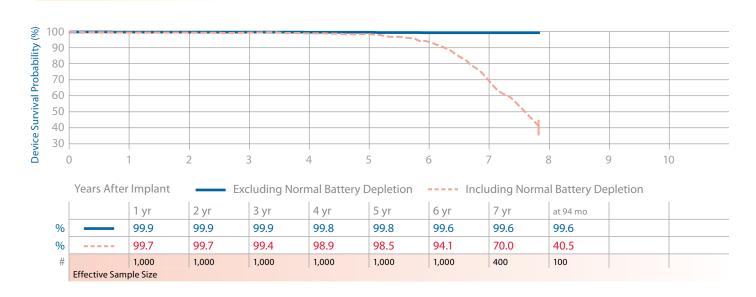
Product Characteristics

JS Mark	ket Release		Feb-	.99	Malfun	ctions (US)			28	NBG Co	de		SSI/R
egiste	red US Implar	nts	55,0	00	Thera	py Function No	t Compromise	d	3	Serial N	umber Prefix		PHT, PHW,
stimate	ed Active US	Implants	7,0	00	Ele	ectrical Compo	nent		2				PHU
Iormal	Battery Depl	etions (US)	3,7	'83	Po	ssible Early Bat	tery Depletion		1	Estimat	ed Longevity		See page
		<u>je 139</u> – 2009 P	otential		Thera	py Function Co	mpromised		25				
eparat	ion of Interco	nnect Wires			Ele	ectrical Compo	nent		4				
					Ele	ectrical Interco	nnect		21				
100 -				T									
90 -													
80													
70										1			
60													
50 -													
40											1		
30 -											1		
20											\		
10											\		
0		1	2	3	_	ļ. <u>.</u>	5 6		7	8	3	9	10
	Years Afte	r Implant	Ex	cludir	ng Norr	mal Battery I	Depletion	Inc	ludin	g Norm	al Battery D	epletion	
		1 yr	2 yr	3 yr		4 yr	5 yr	6 yr	7 y	r	8 yr	9 yr	at 112 mc
%		100.0	100.0	100		100.0	100.0	100.0	99.		99.8	99.8	99.8
%		99.9	99.8	99.4		98.6	97.1	93.6	83.	9	58.4	22.0	8.8
#		46,000	39,000	33,00	00	27,000	21,000	16,000	11,0	00	5,000	1,000	200

Effective Sample Size

Kappa 700 VDD KVDD701

• •					
US Market Release	Jan-99	Malfunctions (US)	4	NBG Code	VDD/RO
Registered US Implants	2,000	Therapy Function Not Compromised	0	Serial Number Prefix	PHP
Estimated Active US Implants	30	Therapy Function Compromised	4	Estimated Longevity	See page 73
Normal Battery Depletions (US)	167	Electrical Interconnect	4		
Advisories: See page 145 – 2002 Potential Fractured Power Supply Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires		(4 malfunctions related to advisory)			



ppa	800 DR	KDR801, KL	JK8U3					PI	roduct Characte	ristics	
US Ma	rket Release		Jan-	02 Mal	functions (US)			3 NI	BG Code		DDD/RO
Regist	ered US Implan	its	4,000 Therapy Function Not Compromised			sed	0 Se	erial Number Prefix		PKW, PKY	
Estima	ated Active US I	mplants	1,0	00 Th	erapy Function (Compromised		3 Es	timated Longevity		See page 7
Norma	al Battery Deple	etions (US)	2	204 Electrical Interconnect				3			
Adviso	ories		No	ne							
100									_		
90											
80											
70											
60								•			
50											
40											
30											
90 80 70 60 50 40 30	0	1	2	3	4	5	6	7	8	9	10
	Years After	r Implant	Ex	cluding N	ormal Battery	Depletion	In	cluding N	lormal Battery D	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 92 mo		
%		100.0	100.0	100.0	100.0	100.0	100.0	99.8	99.8		
%		100.0	99.9	99.8	99.6	98.6	96.3	83.4	59.7		
#		4,000	3,000	3,000	3,000	2,000	2,000	1,000	100		
	Effective Sam	ple Size									

Jan-02 125,000

49,000

4,890

None



US Market Release

Advisories

Registered US Implants **Estimated Active US Implants**

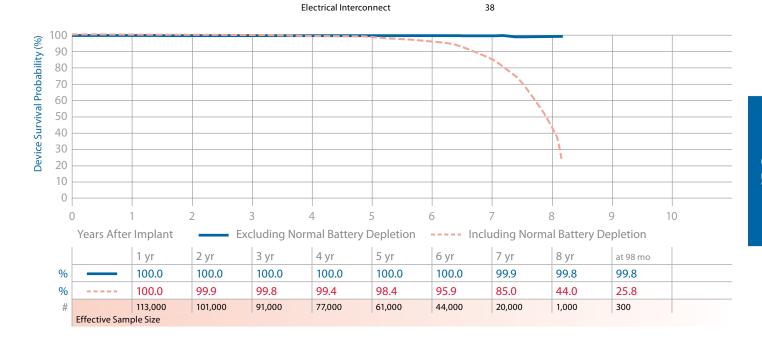
Normal Battery Depletions (US)

Kappa 900 DR KDR901, KDR903, KDR906

Malfunctions (US)	62
Therapy Function Not Compromised	15
Electrical Component	14
Electrical Interconnect	1
Therapy Function Compromised	47
Electrical Component	9

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PKM, PKN, PK
Estimated Longevity	See page 73



Kappa 900 SR KSR901, KSR903, KSR906

US Market Release	Jan-02	Malfunctions (US)		14	NBG Code		VVEV
Registered US Implants	37,000	Therapy Function N	ot Compromised	8	Serial Number Prefix		PLF, PLG, PLH
Estimated Active US Implants	12,000	Electrical Compo	onent	7			
Normal Battery Depletions (US)	948	Possible Early Ba	ttery Depletion	1	Estimated Longevity		See page 73
See page 139 – 2009 Potential		Therapy Function C	ompromised	6			
Separation of Interconnect Wires		Electrical Interco	onnect	6			
100							
90							
80							
70							
60							
50							
40					1		
30							
0 1	2 3	4	5 6	7	8	9	10
Years After Implant	Exclu	ding Normal Battery	Depletion	Includin	g Normal Battery [Depletion	
1 yr	2 yr 3	yr 4 yr	5 yr 6 yr	7 y	r 8 yr	at 97 mo	
% 100.0		00.0 100.0	100.0 99.9	99.	-	99.9	
% 99.9	99.8 9	9.6 98.9	97.4 94.5	84.	3 50.9	43.2	
# 30,000		2,000 18,000	12,000 8,000	3,00		200	
Effective Sample Size							

Kappa 900 VDD KVDD901

Product Characteristics

abba	700 100	KVDDJO	•						TTOGG	Charac	ceristies	
US Ma	rket Release		Jan-0	02 Mal	functions (US)			0	NBG Cod	de		VDD
Regist	Registered US Implants 1,000			00 Th	erapy Function	Not Comprom	ised	0	Serial Nu	ımber Prefix	ĸ	PLE
Estima	estimated Active US Implants 100			00 Th	Therapy Function Compromised			0	Estimate	ed Longevity	y	See page 7
Norma	al Battery Deplet	tions (US)	(55								
	o <mark>age 139</mark> – 2009 ation of Intercon											
§ 100												
90												
Geo 70							The state of the s					
90 Pro												
Survival Probability 00 00 00 00 00 00 00 00 00												
Sur	0 1		2	3	4	5	6	7		8	9	10
Device	Years After	Implant	Ex	cluding N	ormal Battery	y Depletion	In	ncludin	g Norma	al Battery	Depletion	
Δ		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 7	79 mo			
%		100.0	100.0	100.0	100.0	100.0	100.0	10	0.0			
%		100.0	100.0	100.0	99.0	97.8	90.2	73	.9			

Карра 920 DR кDR921

1,000

Effective Sample Size

500

400

400

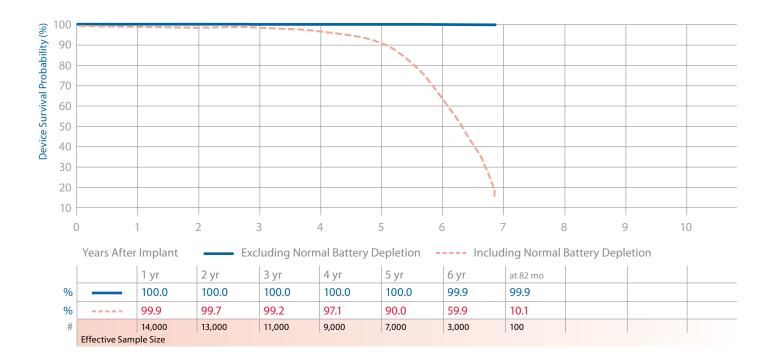
Product Characteristics

US Market Release	Jan-02	Malfunctions (US)	4	NBG Code	VVEV
Registered US Implants	16,000	Therapy Function Not Compromised	1	Serial Number Prefix	PLF, PLG, PLH
Estimated Active US Implants	2,000	Electrical Component	1		
Normal Battery Depletions (US)	2,022	Therapy Function Compromised	3	Estimated Longevity	See page 73
See page 139 – 2009 Potential Separation of Interconnect Wires		Electrical Interconnect	3		

300

200

100



None

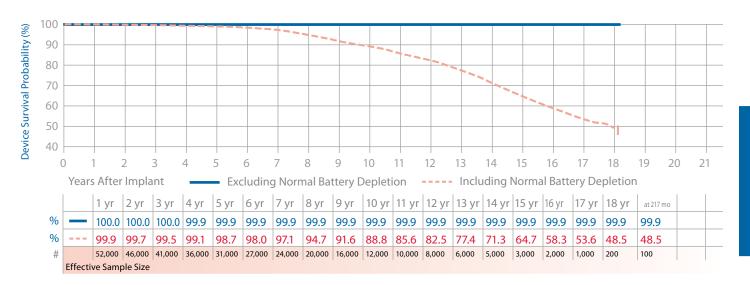


Advisories

Legend II 8424, 8426, 8427

Product Characteristics

US Market Release	Nov-91	Malfunctions (US)	34	NBG Code	SSIRO
Registered US Implants	58,000			Serial Number Prefix	2P, 2T, 2U
Estimated Active US Implants	2,000			Estimated Longevity	See page 73
Normal Battery Depletions (US)	2,451				

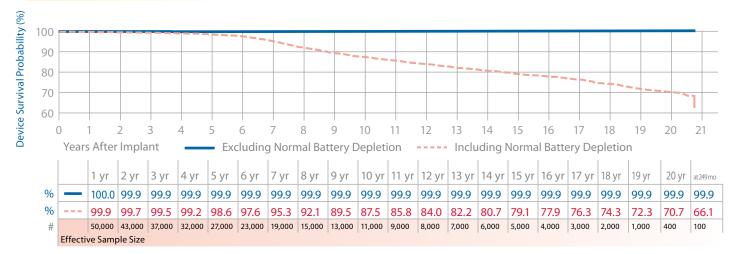


Minix/Minix ST 8340, 8341, 8341M, 8342, 8330, 8331, 8331M

Product Characteristics

US Market Release	Dec-89	Malfunctions (US)	49	NBG Code	SSIRO
Registered US Implants	58,000			Serial Number Prefix	2P, 2T, 2U
Estimated Active US Implants	3,000			Estimated Longevity	See page 73
Normal Battery Depletions (US)	1,667				

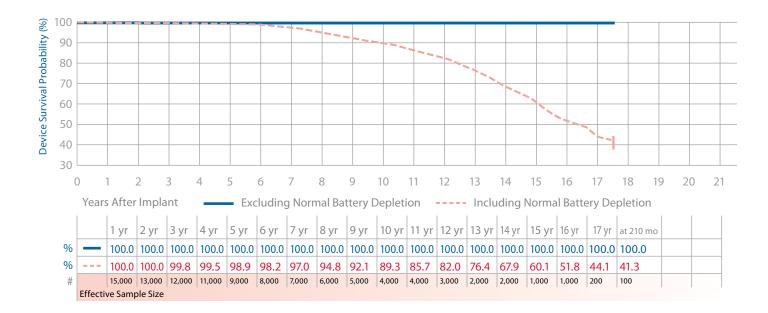
Advisories: See page 146-1991 Potential Delayed Restoration of Permanent Settings



Minuet 7107, 7108

Product Characteristics

US Market Release	Mar-92	Malfunctions (US)	4	NBG Code	DDDCO
Registered US Implants	17,000			Serial Number Prefix	1Z1, 2G1
Estimated Active US Implants	1,000			Estimated Longevity	See page 73
Normal Battery Depletions (US)	889				
Advisories	None				



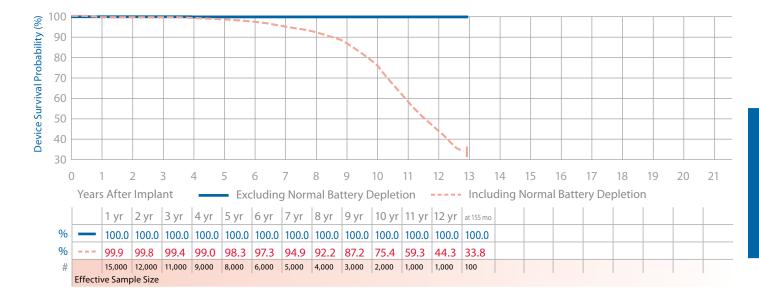
Preva DR 7088, 7089

	US Mai	rket Rel	ease				Jul-9	6	Malfund	tions (l	JS)				4	NBG Co	de				DDD	/RO
	Registe	ered US	Implan	ts			26,00	0								Serial N	umber	Prefix			PGJ, I	PGK
	Estima	ted Act	ive US Ir	mplants			1,00	0								Estimat	ed Long	gevity			See	page 73
	Norma	al Batter	y Deple	tions (U	S)		2,52	7														
	Adviso	ries					Non	e														
	100																					
Device Survival Probability (%)	100																					
babil	80																					
l Prol	70																					
viva	60																					
e Sui	50											-										
evic	40																					
	30												-\-									
	20																					
	10													<u> </u>								
	()	1 :	2	3	4	5	6	7	8	9	10	11	12	13 14	15	16	17	18	19	20	21
		Year	s After	Impla	int		E xc	luding	g Norn	nal Ba	ttery D	epleti	ion		Includin	g Norm	al Bat	tery [Deple	tion		
			1 yr	2 vr	3 yr	4 yr	5 yr	6 vr	7 yr	8 vr	9 vr	10 vr	11 vr	12 vr	at 148 mo							
	%	_	-	100.0		_	_				_				100.0							
	%		99.9	99.8			98.8				84.5		42.0		9.4							
	#			20,000										300	100							
		Effecti	ve Samp	ole Size																		

Preva SR 8088, 8089

Product Characteristics

US Market Release	Jul-96 M	alfunctions (US)	1	NBG Code	SSI/R
Registered US Implants	18,000			Serial Number Prefix	PGL, PGM
Estimated Active US Implants	1,000			Estimated Longevity	See page 73
Normal Battery Depletions (US)	944				
Advisories	None				



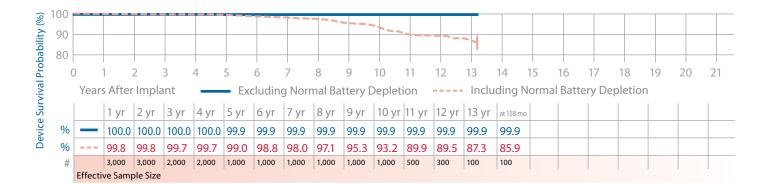
Prevail S 8085, 8086

Advisories

Product Characteristics

US N	larket Release	Oct-95	Malfunctions (US)	1	NBG Code	SSI
Regi	stered US Implants	4,000			Serial Number Prefix	PGL, PGM
Estin	nated Active US Implants	400			Estimated Longevity	See page 73
Norn	nal Battery Depletions (US)	47				

None

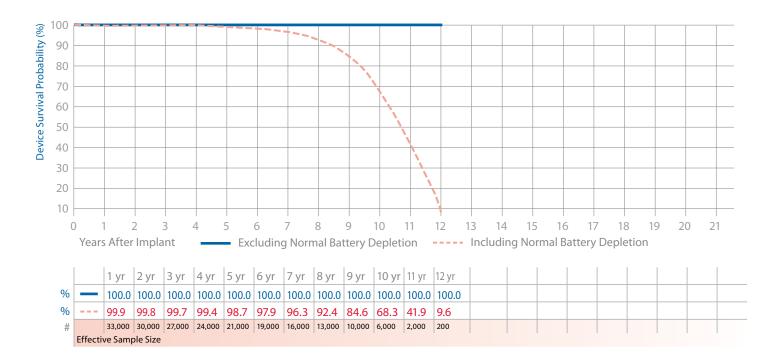




Prodigy DR 7860, 7861, 7862

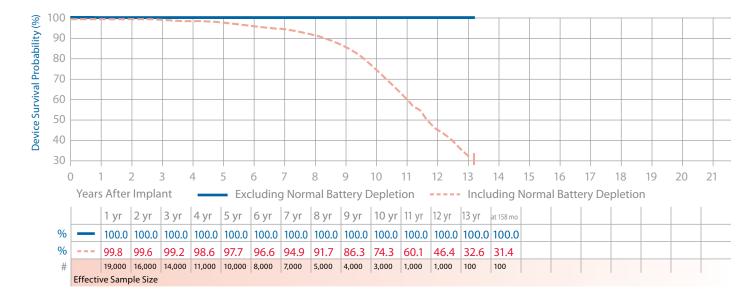
Product Characteristics

		14.15			
US Market Release	Oct-95	Malfunctions (US)	11	NBG Code	DDD/RO
Registered US Implants	38,000			Serial Number Prefix	PDH, PDJ, PDK
Estimated Active US Implants	1,000				
Normal Battery Depletions (US)	3,510			Estimated Longevity	See page 74
Advisories	None				



Prodigy SR 8158, 8160, 8161, 8162

US Market Release	Oct-95	Malfunctions (US)	4	NBG Code	SSI/R
Registered US Implants	22,000			Serial Number Prefix	PEM, PED, PEE,
Estimated Active US Implants	2,000				PEF
Normal Battery Depletions (US)	1,140			Estimated Longevity	See page 74
Advisories	None				

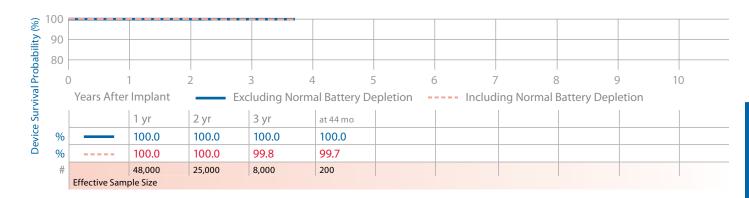




Sensia DR SEDR01, SED01

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	6	NBG Code	DDD, DDDR
Registered US Implants	74,000	Therapy Function Not Compromised	4	Serial Number Prefix	PWL, PWK,
Estimated Active US Implants	61,000	Electrical Component	4		NWL
Normal Battery Depletions (US)	17	Therapy Function Compromised	2	Estimated Longevity	See page 74
Advisories	None	Electrical Component	2		



Sensia SR SESR01, SES01

Effective Sample Size

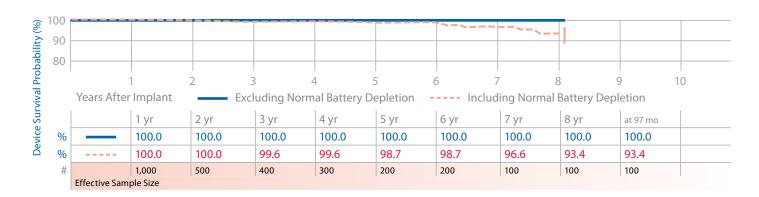
US Mai	rket Release		Jul-06	Malfunct	ions (US)			2	NBG Code			SSIR, SSI
Registe	ered US Implant	ts	48,000	Therapy	Function Not	Compromised		1	Serial Num	ber Prefix		PWR, PWS,
Estima	ited Active US Ir	mplants	36,000) Elec	trical Compone	ent		1				NWR
Norma	al Battery Deple	tions (US)	11	Therapy	Function Com	npromised		1	Estimated I	ongevity		See page 74
Adviso	ories		None	e Elec	trical Interconn	nect		1				
§ 100												
<u>¥</u> 90												
idec 80												
Prok) 1	1	2 :	3 4		5	і б	7	8		9	10
Survival Probability (%) 08 06 00	Years After	Implant	Exc	luding Norm				udin		Battery Dep		
se Su		1 yr	2 yr	3 yr	at 44 mo							
Device 8		100.0	100.0	100.0	100.0							
□ %		100.0	99.9	99.8	99.5							
#		28,000	14,000	4,000	100							

Sigma 100 S SS103, SS106

Product Characteristics

US Market Release	Aug-99	Malfunctions (US)	0	NBG Code	SSI
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PJG, PJH
Estimated Active US Implants	100	Therapy Function Compromised	0	Estimated Longevity	See page 7
Normal Battery Depletions (US)	13				

Advisories: See page 143 – 2005 Potential Separation of Interconnect Wires



Sigma 200 DR SDR203

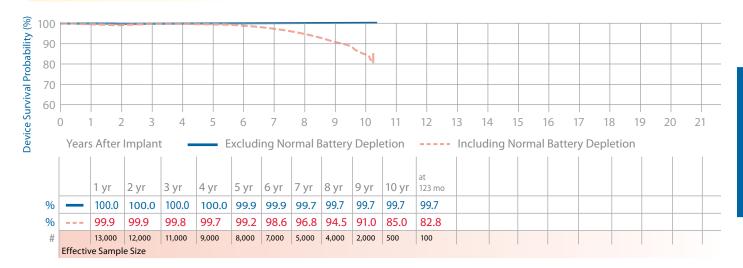
S Mar	ket Rel	ease			A	ug-99	Ma	lfunctio	ns (US)					25	NBG	Code					DDD/R0	C
egiste	ered US	Implant	:S		1	6,000	Tŀ	erapy F	unctio	n Not C	omproi	nised		1	Seria	al Numb	oer Pref	ix			DID	
stimat	ted Act	ive US In	nplants			5,000		Electr	ical Cor	nponen	t			1	Estir	nated L	.ongevi	ty			See pa	ge 7
orma	l Batter	y Deplet	tions (US	5)		297	Th	erapy F	unctio	n Comp	romise	d		24								
	_			005 Pote				Electr	ical Cor	nponen	t			1								
				res; See a						rconne				23								
	nnect \		ilitiai se	Jaration	Oi			(14 m)	illunctio	ons relat	ea to ac	visory)										
00							1															
90																						
80																						
70																						$^{+}$
60																					-	+
0)	1 2	2 3	4	5	6	7	8	9	10	11	12	13	3 14	15	16	5 1	7 1	8	19	20	21
	Years	s After	Implar	nt •		Exclu	ding N	lormal	Batte	ry Dep	oletion			ncludi	ng No	rmal B	Battery	y Depl	letion			
												at										
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	124 mo										4
%	_	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9										
%		100.0	99.9	99.9	99.8	99.5	99.0	97.3	93.6	88.6	78.7	73.9										
#		13,000	12,000	11,000	9,000	8,000	7,000	5,000	4,000	2,000	500	100										
			le Size																			



Sigma 200 SR SSR203

<u> </u>					
US Market Release	Sep-99	Malfunctions (US)	13	NBG Code	SSI/R
Registered US Implants	12,000	Therapy Function Not Compromised	0	Serial Number Prefix	PJG
Estimated Active US Implants	3,000	Therapy Function Compromised	13	Estimated Longevity	See page 74
Normal Battery Depletions (US)	134	Electrical Interconnect (10 malfunctions related to advisory)	13		

Advisories: See page 143 – 2005 Potential Separation of Interconnect Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires



Sigma 300 DR SDR303, SDR306

Product Characteristics

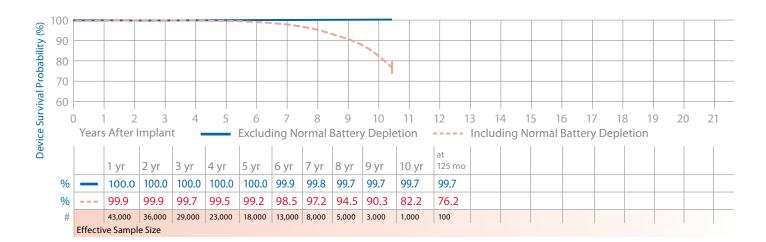
iiia	300	JI 3	טונטט	, JUI	500											oduci	Criai	actei	istics	,		
US Ma	rket Rel	ease				Aug-99) 1	Malfunc	tions (U	S)				181	N	3G Code	•				DDD	/RO
Regist	ered US	Implant	S			107,000)	Therap	y Funct	ion Not	Compro	mised		6	Se	rial Nur	nber Pı	efix			PJD,	PJE
Estima	ted Act	ive US Ir	nplants			42,000)	Ele	ctrical C	ompone	ent			5	Es	timated	Longe	vity			See	page 74
Norma	l Batter	y Deple	tions (U	S)		1,097	7	Pos	ssible Ea	rly Batte	ry Deple	etion		1								
	_	ee page						Therap	y Funct	ion Com	promis	ed		175								
		Intercor 009 Pote						Ele	ctrical C	ompone	nt			8								
	onnect \		entiai se	paratio	11 01					nterconn octions re		advisory)		167								
100																						
90																						
80																						
70											ì											
60																						
00) ,	1 -) :) /	1 1	 		7	8 (9 10	11	12	13	14		15	16	17	18	19	20	21
		s After	Impla	nt 		Exc	luding			tery De	epletio	n	I	ncludi		ormal 	Batte 	ery De			20	
		1 yr	2 yr	3 yr	4 yr	5 yr	буг	7 yr	8 yr	9 yr	10 yr	at 126 mo										
%		100.0	100.0	100.0	99.9	99.9	99.8	99.7	99.5	99.5	99.5	99.5										
%		100.0	99.9	99.8	99.6	99.4	98.8	97.8	95.0	90.1	81.9	73.6										
#		92,000		72,000	60,000	48,000	37,000	25,000	16,000	8,000	2,000	200										
	Effecti	ve Samp	ole Size																			

Sigma 300 SR SSR303, SSR306

-			
US Market Release	Sep-99	Malfunctions (US)	35
Registered US Implants	54,000	Therapy Function Not Compromised	1
Estimated Active US Implants	16,000	Electrical Component	1
Normal Battery Depletions (US)	438	Therapy Function Compromised	34
Advisories: See page 143 – 2005 Potential		Electrical Component	3
Separation of Interconnect Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires		Electrical Interconnect (20 malfunctions related to advisory)	31

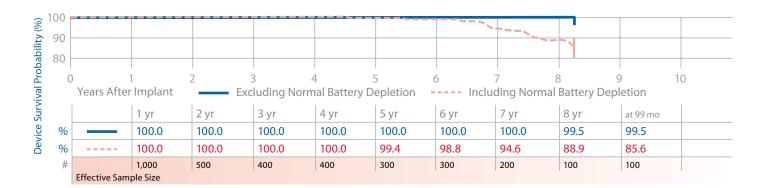
Product Characteristics

SSI/R
PJG, PJH
See page 74



Sigma 300 VDD svDD303

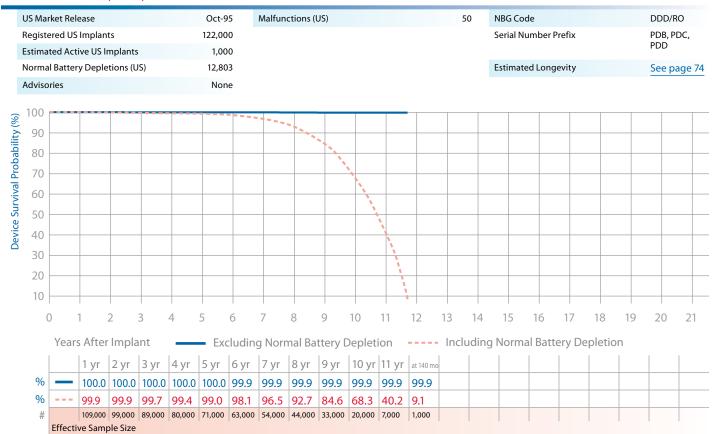
US Market Release	Sep-99	Malfunctions (US)	1	NBG Code	VDDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PJD
Estimated Active US Implants	100	Therapy Function Compromised	1	Estimated Longevity	See page 74
Normal Battery Depletions (US)	27	Electrical Interconnect	1		
Advisories: See page 143 – 2005 Potential		(1 malfunction related to advisory)			





Thera-i DR 7960i, 7961i, 7962i

Product Characteristics



Thora-i SP onen: onen: onen:

adust Charastoristics

era-i SR 8960i, 8961i, 8962	2i						F	roduc	t Cha	racter	ristics			
US Market Release	Oct-95	Malfunction	ns (US)				7 N	IBG Cod	e				SSIR	
Registered US Implants	S Implants 50,000						S	erial Nu	mber F	refix			PDU, P	DV,
Estimated Active US Implants	2,000												PDW	
Normal Battery Depletions (US)	2,610						E	stimate	d Long	evity			See pa	age :
Advisories	None													
100		+												
90													_	
80														
70														
60														
50														
40														
30	4 5 6	7 0		10 1	1 10	12	1.4	15	16	17	10	10	20	7
	4 5 6	7 8	_	10 1		13	14	15	16	17	18	19	20	21
Years After Implant		ding Normal				Inclu			l Batt	ery De	epletic	n		
1 yr 2 yr 3 yr	4 yr 5 yr 6 y	/r 7 yr 8 y	yr 9 yr	10 yr 1	1 yr 12 y	/r 13 yr	14 yr							
% <u>100.0</u> 100.0 100.0	100.0 100.0 10	0.0 100.0 10	0.0 100.0	100.0 1	00.0 100	.0 100.0	100.0							
% 100.0 99.9 99.6	99.4 98.9 98	96.9 94	88.7	80.0 6	6.1 51.4	38.8	30.6							
# 42,000 37,000 32,000	27,000 23,000 20,0	000 17,000 14,0	000 11,000	8,000 5,	.000 2,000	1,000	100							

Effective Sample Size

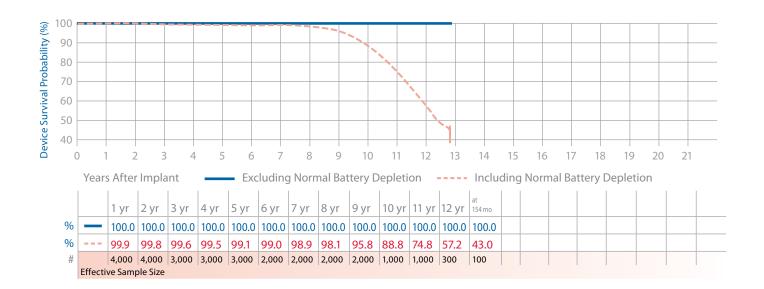
None

Thera-i VDD 8968i

Advisories

Product Characteristics

US Market Release	Mar-96	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	5,000			Serial Number Prefix	PEC
Estimated Active US Implants	400			Estimated Longevity	See page 74
Normal Battery Depletions (US)	273				



Versa DR VEDRO1

US Market Release	Jul-	06 Malfur	ictions (US)		5	NBG Code			DDDR	
Registered US Implants	62,0	00 Thera	py Function Not Com	promised	3	Serial Num	Serial Number Prefix			
Estimated Active US Implant	s 51,0	00 EI	ectrical Component		3	Estimated I	Estimated Longevity			
Normal Battery Depletions (US)	13 Thera	py Function Compro	mised	2					
Advisories	No	ne El	ectrical Component		2					
90										
80 0 1	2	3	4 5	6	7	8		9	10	
80 0 1 Years After Impl	2 ant — Ex		4 5 mal Battery Deple	_	7		Battery Depl		10	
80 0 1 Years After Impl	2 ant 2 Ex			_	7 ncludin				10	
0 1 Years After Impl	2 yr	cluding Nor	mal Battery Deple	_	7 ncludin				10	
0 1 Years After Impl 1 yr 100. 100.	2 yr 0 100.0	3 yr	mal Battery Deple	_	7 Includin				10	

Device Survival Summary (95% Confidence Interval)

The following table shows IPG device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included

16 yr 14 yr 12 yr 10 yr 8 yr 93.8 +1.0/-1.2 at 77 mo 100.0 +.0/-.0 at 74 mo 10.3 +2.1/-1.9 at 77 mo 100.0 +.0/-.1 at 77 mo 7 yr 61.2 +3.6/-3.8 42.7 +1.6/-1.7 100.0 96.4 +.5/-.6 100.0 6 yr 99.9 91.9 +1.4/-1.7 82.6 +.9/-1.0 5 yr 100.0 100.0 99.9 98.3 Device Survival Probability (%) 100.0 +.0/-.0 at 42 mo 100.0 +.0/-.0 at 45 mo +.0/-.0 at 42 mo 100.0 +.0/-.1 at 43 mo 99.0 +.5/-.9 at 43 mo 100.0 +.0/-.1 at 44 mo +.0/-.0 at 45 mo 99.6 +.2/-.3 at 44 mo 96.4 +.9/-1.2 0.001 4 yr 97.4 100.0 99.1 100.0 99.9 100.0 +.0/-.0 at 33 mo +.0/-.0 at 33 mo 9.66 100.0 100.0 100.0 100.0 3 yr 100.0 0.00 100.0 99.7 +.1/-.2 100.0 100.0 98.9 **Years After Implant** 99.5 99.7 99.9 100.0 9.66 100.0 100.0 100.0 100.0 100.0 100.0 100.0 100.0 100.0 2 yr 100.0 100.0 99.6 99.8 99.8 100.0 100.0 100.0 100.0 100.0 100.0 100.0 100.0 100.0 100.0 0.-/0.+ 100.0 100.0 100.0 100.0 99.9 1 yr 99.9 Including Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Including mal Battery Depletion Including mal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Depletion Excluding mal Battery Depletion Excluding Normal Battery Depletion Including mal Battery Depletion Including Normal Battery Depletion Normal Battery Depletion mal Battery Depletion Including Including Nor 28 9 Total 3 7 7 0 0 Malfunctions (US) Compromised Function Not 19 0 0 2 0 Тһегару + + + + + Compromised 7 0 2 0 0 Therapy Function 1,608 Depletions (US) 160 0 13 0 See page 152 – Performance note on AT500 Pacing System Follow-Up Protocol 89 12 Normal Battery 168,000 lmplants 16,000 29,000 24,000 1,000 1,000 400 Estimated 202,000 38,000 27,000 19,000 11,000 2,000 etnaldmi 2U 1,000 7,000 Registered Dec-03 Mar-03 Dec-03 90-Inf 90-Inf 90-Inf Jul-06 90 Release 늘 US Market ADVDD01 ADDR01, ADDR03, E1DR01, E1DR03, E1DR06 **ADDRS1** ADDRL1 E1DR21 Mumber IəboM Adapta DR Adapta DR Adapta DR Adapta SR EnPulse DR Adapta VDD **EnPulse** AT500 Family

	F)	
		ì	

						,													
		16 yr																	
		14 yr																	
		12 yr																	
		10 yr														99.9 +.0/0 at 101 mo	8.2 +.9/9 at 101 mo	100.0 +.0/1 at 111 mo	12.2 +2.2/-2.0 at 111 mo
		8 yr														99.9	47.7 +.9/9	100.0	65.8 +1.5/-1.6
		7 yr	100.0 +.0/0 at 74 mo	96.4 +.5/6 at 74 mo					100.0 +.0/0 at 75 mo	93.0 +1.4/-1.7 at 75 mo						99.9	86.4 +.5/5	100.0	91.0
		6 yr	100.0	96.9	100.0 +.0/1 at 71 mo	74.0 +3.1/-3.4 at 71 mo			100.0	94.1 +1.0/-1.1	100.0 +.0/0 at 62 mo	99.5 +.4/-1.5 at 62 mo	99.8 +.1/1 at 61 mo	98.9 +.3/4 at 61 mo		9.99.9	97.0 +.2/2	100.0	97.2
		5 yr	100.0	98.8	100.0	92.3	100.0 +.0/0 at 59 mo	100.0 +.0/0 at 59 mo	100.0	97.6	100.0	99.5	99.8	98.9		99.9	98.9	100.0	98.8
lity (%)		4 yr		99.5 + +.0/1	100.0 ++.0/1	97.6 9.4.4.4.4.4	100.0 +.0/0 a	100.0 +.0/0 a	100.0 + +.0/0	98.9 +.2/2 +	100.0 +.0/0	99.5	99.9	99.6 + +1/+		100.0 + +.0/0 +	99.5	100.0 1	99.2 + +.2/2 +
Device Survival Probability (%)	ınt	3 yr 4	100.0 10+.0/0	96 8.66	100.0 10 +.0/1	99.2 97.	100.0 10+.0/0	100.0 10.0/0 +.0/0	100.0 10+.0/0	99.5 98.+.1/1 +.	100.0 10 +.0/0	100.0 99.	96.99	96 8.66		100.0 10.0/0 +	-	100.0 + .0/0	99.7 99.1+.1/1
rvival P	After Implant																		
vice Su	irs Afte	r 2 yr		0/0.+	100.0 +.0/1	99.7	100.0	100.0	0.00.0 +.0/0	99.8	100.0	100.0 +.0/0	100.0	0/0.+		0.001 0.00.0	0/0.+ 0.	0.0100.0	99.8
De	Years	1 yr	y +.0/0	y +.0/0	y +.0/0	g 99.9 y +.0/1	y +.0/0	y +.0/0	y +.0/0	99.9 y +.0/0	y +.0/0	g 100.0 y +.0/0	y +.0/0	y +.0/0		y +.0/0	g 99.9 y +.0/0	y +.0/0	g 99.9 y +.0/1
			Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion										
(6	le	stoT	20		-		0		4		0		76			22		2	
ons (US)	rapy ction Not opsimorqr	nn3 Con	16 =								= 0					II			
Malfunctions	npromised rapy		+		0 +		+		m +		+		+			+		+	
Ma	rapy Function	ЭЧТ	4		-		0		-		0		35			6		-	
	mal Battery letions (US)		369		293		0		161		∞		38	<u>></u>	nalies in	6,709		1,198	
•	bətsm 2U əv stnsi	itoA	29,000		000′9		300		12,000		400		70,000	Advisories: <u>See page 137</u> – 2010 Low Battery Voltage Displayed at Device Interrogation	See page 148 – Performance note on anomalies in MOSFET Integrated Circuit Technology	2,000		1,000	
	istered mplants	I SN ɓəy	101,000		12,000		1,000		25,000		1,000		97,000	137 – 201 Device Int	rmance n rcuit Tecl	47,000		15,000	
	Narket sase	N S N	Feb-04		Feb-04		Feb-04		Dec-03		Dec-03		May-05	See page played at [48 – Perfoi tegrated Ci	Jan-98		Feb-98	
	lel nber	ooM nuM	E2DR01, E2DR03, E2DR06		E2DR21		E2DR31, E2DR33		E2SR01, E2SR03, E2SR06		E2VDD01		P1501DR	Advisories: Voltage Dis	See page 1 MOSFET In	KDR401, KDR403		KSR401, KSR403	
	λli	mвЯ	EnPulse 2 DR		EnPulse 2 DR		EnPulse 2 DR		EnPulse 2 SR		EnPulse 2 VDD		EnRhythm DR			Kappa 400 DR		Kappa 400 SR	continued

Device Survival Summary continued

Mondale Wears Wear Wea		ן נ	College and Marie Longarines (79)		Same y	,							
Charles Sign Sign	psimore qq ion Not besimore		ars After Ir	nolant									
KDR601, Jan-99 24,000 5 3,407 36 + 3 9 Normal Battery Author Control of The Control of	Comp Thers Func Comp		r 2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Advisories: See page 145 - 2002 Potential Fractured Processing Separation of Interconnect Wires (33) + (0) = (33) (0) = (33) (30) <th< th=""><th>+ 3 = 39 Norm</th><th></th><th></th><th>100.0 +.0/0</th><th>99.9</th><th>99.9</th><th></th><th></th><th></th><th>99.6 +.1/2 at 107 mo</th><th></th><th></th><th></th></th<>	+ 3 = 39 Norm			100.0 +.0/0	99.9	99.9				99.6 +.1/2 at 107 mo			
KDR651, Mar-01 Mar-01 14,000 1,000 1,000 1,000 100.0	= (33) Norms			99.9	99.5	98.8 +.2/2	96.8	87.8	57.5 +1.1/-1.1	3.3 +.9/7 at 107 mo			
Advisories: See page 145 - 2002 Potential Fractured (21) + (0) = (21) Normal Battery (2000) 100.00 (2000) 99.9 (2000) 99.9 (2000) 99.9 (2000) 99.8 (2000)	+ 2 = 32			100.0	100.0	100.0	99.9	99.7 +1/2	99.5 + +.2/3	99.4 +.2/3 at 100 mo			
KD701, Jan-99 Jan-99 300 40 17 0 + 0 = 0 Excluding Depletion 100.0 100.	+ (0) = (21) isory-related subset)			99.8	99.4 +.1/2	98.1	94.8	80.5 + +.9/-1.0	40.4 +1.5/-1.5	13.5 +2.0/-1.9 at 100 mo			
Advisories: See page 145–2002 Potential Fractured Power Supply Wires; See also page 139 – 2009 (0) + (0) = (0) Power Supply Wires; See also page 139 – 2009 (0) + (0) = (0) Power Supply Wires; See also page 139 – 2009 (0) + (0) = (0) Popeletion Potential Separation of Interconnect Wires (0) + (0) = (0) Popeletion Po	0 = 0 +			100.0	100.0	100.0	100.0	100.0	100.0 +.0/0 at 91 mo				
Normal Battery Holy Holy	+ (0) = (0) visory-related subset)			100.0 +.0/0	99.0	97.8 +1.4/-3.5	95.3	93.9 +2.8/-4.9 +	90.7 +3.7/-6.0 at 91 mo				
Advisories: See page 145 – 2002 Potential Fractured Power Supply Wires; See also page 139 – 2009 Power Supply Wires; See also page 139 – 2009 RDR721 Feb-99 10,000 0 1,301 4 + 1 = 5	+ 31 = 464 Norm			99.9	99.9	0-/0.+	99.8	99.7	99.5	99.3 +.1/1 at 104 mo			
Column C	+ (0) = (330) ory-related subset)			9.66	99.1	98.0	95.1	84.0 +.3/3	50.9 +.4/4	5.6 +.4/4 at 104 mo			
Advisories: See page 145 – 2002 Potential Fractured Power Supply Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires page 700 KSR701, Feb-99 55,000 7,000 3,783 25 + 3 = 28 Normal Battery 100.0 100.0	+ 1 = 5			100.0	100.0	99.9	99.9	99.9	99.9 +.0/1 at 86 mo				
ppa 700 KSR701, Feb-99 55,000 7,000 3,783 25 + 3 = 28 Excluding 100.0 100.0 100.0 100.0 100.0 100.0 100.0	= (4) subset)			98.8	96.7	91.0	68.7	22.1 +2.0/-1.9	11.7 +2.0/-1.9 at 86 mo				
Depletion	+ 3 = 28		0 100.0 +.0/0	100.0	100.0	100.0	100.0	99.9	99.8	99.8 +.1/1 at 112 mo			
Advisories: See also page 139 – 2009 Potential (0) + (0) = (0) Including 99.9 99.8 99.4 Separation of Interconnect Wires Separation of Interconnect Wires	+ (0) = (0) + Norm			99.4	98.6	97.1	93.6	83.9 5/9.+	58.4 +.9/9	8.8 +1.3/-1.2 at 112 mo			
Kappa 700 KVDD701 Jan-99 2,000 30 167 4 + 0 = 4 Excluding 99.9 99.9 99.9 99.9 VDD Normal Battery +:1/-:4 +:1/-:4 +:1/-:4 +:1/-:4 +:1/-:4 +:1/-:4 +:1/-:4 +:1/-:4 +:1/-:4	+ 0 = 4 Norm			99.9	99.8	99.8	99.6	99.6	99.6 +.2/7 at 94 mo				
Advisories: See page 145 – 2002 Potential Fractured Power Supply Wires; See also page 139 – 2009 Potential Separation of Interconnect Wires Advisories: 4 + (0) = (4) + (0) = (4)	+ (0) = (4)			99.4	98.9	98.5	94.1	70.0 ++3.3/-3.7 +	40.5 +4.8/-4.9 at 94 mo				

G	Implantab	le P	ulse G	enerat	ors, co	ntinue	ed				ı		ı		ı	
		16 yr											99.9 +.0/0 at 217 mo	48.5 +2.2/-2.2 at 217 mo	99.9 +.0/0 at 249 mo	66.1 +3.1/-3.3 at 249 mo
		14 yr											99.9	71.3	99.9	80.7
		12 yr											99.9	82.5	9.99.9	84.0
		10 yr			99.8 +.1/1 at 98 mo	25.8 +2.2/-2.1 at 98 mo	99.9 +.0/1 at 97 mo	43.2 +3.7/-3.8 at 97 mo					99.9	88.8 +.4/4	9.99.9	87.5
		8 yr	99.8 +.1/3 at 92 mo	59.7 +4.3/-4.6 at 92 mo	99.8 +.1/1	44.0 +1.3/-1.3	99.9	50.9					9.99.9	94.7	99.9	92.1
		7 yr	99.8	83.4 +1.7/-1.9	9.9.9	85.0	99.9	84.3 +.9/9	100.0 +.0/0 at 79 mo	73.9 +5.5/-6.7 at 79 mo	99.9 +.0/1 at 82 mo	10.1 +1.9/-1.7 at 82 mo	9.99.9	97.1	99.9	95.3
		6 yr	100.0	96.3	100.0	95.9	99.9	94.5	100.0	90.2 +2.9/-4.0	99.9	59.9 +1.3/-1.3	99.9	98.0	9.99.9	97.6
(9)		5 yr	100.0	98.6	100.0	98.4 +.1/1	100.0	97.4 +.2/3	100.0	97.8 +1.1/-2.1	100.0	9.0'0+	99.9	98.7	9.99.9	98.6 +.1/1
bility (%		4 yr	100.0	99.6	100.0	99.4 +.0/1	100.0	98.9	100.0	99.0	100.0	97.1 +.3/3	99.9	99.1	99.9	99.2
al Proba	plant	3 yr	100.0	99.8	100.0	99.8	100.0	99.6	100.0	100.0 +.0/0	100.0	99.2 +.1/2	100.0	99.5	99.9	99.5
Device Survival Probability (%)	Years After Implant	2 yr	100.0	99.9	100.0	9.999	100.0	99.8	100.0	100.0	100.0	99.7	100.0	99.7	99.9	99.7
Device	Years /	1 yr	100.0	100.0	100.0	100.0	100.0	9.66	100.0	100.0	100.0	99.9	100.0	99.9	100.0	99.9
			Excluding al Battery Depletion	Including al Battery Depletion	Excluding lal Battery Depletion	Including al Battery Depletion	Excluding lal Battery Depletion	Including al Battery Depletion	Excluding al Battery Depletion	Including al Battery Depletion	Excluding lal Battery Depletion	Including al Battery Depletion	Excluding nal Battery Depletion	Including al Battery Depletion	Excluding nal Battery Depletion	Including lal Battery Depletion
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	ĮE	otoT	3 Exclu Normal Ba Depl	Incli Normal Ba Depl	62 Excl Normal Ba Dep	Ind Normal B Dep	14 Excli Normal Ba Depl	Incl Normal Ba Dep	0 Excl Normal Ba	Incl Normal Ba Dep	4 Excl Normal Ba	Indl Normal Ba Depl	34 Excl Normal Ba Depl	Incl Normal Ba Depl	49 Excl Normal Bi	Incl Normal B
ctions	ubromised	иоэ	Norm	Incli Normal Ba Depl		Ind Normal B Dep		Ind Normal B Dep		Incl Normal Ba Depi	Norm	Incl Normal Ba Depl	Norm	Incl Normal Ba Dep	Nor	— — Ind Normal B Dep
Malfunctions		The The Con	= 3 Norm	Indi Normal Ba Depl	= 62	Incl Normal B Dep	14	Ind Normal B: Dep	0	Incl Normal Ba Depi	= 4 Norm	Indi Normal Bs Depi	34 Norm	Incl. Normal B. Depl	Nor	— — Normal B: Dep
Malfunctions	rapy rapy ction Not npromised	The The The The Ton	+ 0 = 3	Indi Normal Ba Depl	+ 15 = 62	Incl Normal B Dep	+ 8 = 14	Norm	0 = 0 +		+ 1 = 4 Norm		— 34 Norm	Incl. Normal Ba	Nor	Ind Normal B
Malfunctions	ive US illants mal Battery soletions repy Function npromised repy repy repy npromised	Mori The Con The To To To To To To	204 3 + 0 = 3 Norm	Incl Normal Ba Depl	4,890 47 + 15 = 62	ind Normal B Dep	948 6 + 8 = 14	Norm	0 = 0 + 0 = 0		2,022 3 + 1 = 4 Norm		2,451 — — 34 Norm	Incl. Normal B. Depi	1,667 — — 49 Norm	1
Malfunctions	mated Jours Jents Jetions Jetions Jetion Jetion Jetion Mot Ction Mot Ction Mot Ction Mot	Esti Acti Imp Mon Dep The Con	1,000 204 3 + 0 = 3 Norm	Incl Normal Ba Depti	49,000 4,890 47 + 15 = 62	Ind Normal B Dep	12,000 948 6 + 8 = 14	Norm	100 65 0 + 0 = 0		2,000 2,022 3 + 1 = 4 Norm		2,000 2,451 — — 34 Norm	Incl. Normal B	3,000 1,667 — — 49 Norm	1
Malfunctions	mated mplants instered mated ive US instered instruction mal Battery strong malestrons instruction may Function mpromised instruction work instruction was instruction was instruction was instruction mpromised instruction managed instruction managed instruction managed instruction managed instruction was instructed instruction in the managed instruction was instructed in the managed in the m	Regous USI	4,000 1,000 204 3 + 0 = 3 Norm	Incl Normal Ba Dept	125,000 49,000 4,890 47 + 15 = 62	Ind Normal B Dep	37,000 12,000 948 6 + 8 = 14	Norm	1,000 100 65 0 $+$ 0 $=$ 0		16,000 2,000 2,022 3 + 1 = 4 Norm		58,000 2,000 2,451 — — 34 Norm	Incl. Normal B	58,000 3,000 1,667 — — 49 Norm	1
Malfunctions	malead ive US ive US ilants mal Battery storins rapy Function myromised rapy resy very	Reld Regular R	1,000 204 3 + 0 = 3 Norm	Incl Normal Ba Dept	49,000 4,890 47 + 15 = 62	Ind Normal B Dep	Jan-02 37,000 12,000 948 6 + 8 = 14	Norm	100 65 0 + 0 = 0		2,000 2,022 3 + 1 = 4 Norm		2,000 2,451 — — 34 Norm	Incl. Normal B. Depi	3,000 1,667 — — 49 Norm	1
Malfunctions	Market Jesse Jistered Instered Malester Mal Battery Jistion Mal Battery Mal Ba	Registration of the control of the c	4,000 1,000 204 3 + 0 = 3 Norm	Incl Normal Ba Depti	125,000 49,000 4,890 47 + 15 = 62	Ind Normal B Dep	37,000 12,000 948 6 + 8 = 14	See page 139 – 2009 Potential Separation of Interconnect Wires Dep	1,000 100 65 0 $+$ 0 $=$ 0	See page 139 – 2009 Potential Separation of Interconnect Wires Depi	16,000 2,000 2,022 3 + 1 = 4 Norm	See page 139 – 2009 Potential Separation of Interconnect Wires Dep	58,000 2,000 2,451 — — 34 Norm	Incl. Normal B. Depi	58,000 3,000 1,667 — — 49 Norm	Advisories: See page 146 – 1991 Potential Delayed — — — Normal B. Restoration of Permanent Settings Dep

Device Survival Summary continued

J	Implantab	le P	ulse G	enerat	ors, co	ntinue	ed.					
		16 yr	100.0 +.0/1 at 210 mo	41.3 +3.0/-3.0 at 210 mo								
		14 yr	100.0	67.9	100.0 +.0/1 at 148 mo	9,4 +1.5/-1.3 at 148 mo	100.0 +.0/1 at 155 mo	33.8 +2.7/-2.7 at 155 mo	99.9 +.1/4 at 158 mo	85.9 +3.0/-3.7 at 158 mo		
		12 yr	100.0	82.0 +1.0/-1.1	100.0	16.3 +1.4/-1.4	100.0	44.3 +2.1/-2.1	99.9	89.5 +2.0/-2.5	100.0	9.6 +1.3/-1.2
		10 yr	100.0	89.3	100.0	66.9 +1.0/-1.1	100.0	75.4 +1.3/-1.4	99.9	93.2 +1.5/-1.9	100.0	68.3
		8 yr	100.0	94.8 +.5/5	100.0	92.4	100.0	92.2	99.9	97.1	100.0	92.4
		7 yr	100.0	97.0	100.0	96.2 +.3/3	100.0	94.9	99.9	98.0	100.0	96.3
		6 yr	100.0	98.2 +.2/3	100.0 +.0/0	97.8 +.2/2	100.0	97.3	99.9	98.8	100.0	97.9
(%		5 yr	100.0	98.9 +.2/2	100.0	98.8 +.2/2	100.0	98.3 +.2/3	99.9	99.0	100.0	98.7
Device Survival Probability (%)		4 yr	100.0	99.5	100.0	99.3	100.0	99.0	100.0	99.7	100.0	99.4 +.1/1
ival Prob	mplant	3 yr	100.0	99.8	100.0	99.6	100.0	99.4 +.1/2	100.0	99.7	100.0	99.7
ice Survi	Years After Implant	2 yr	100.0	100.0	100.0	99.8	100.0	99.8	100.0	99.8 +.1/2	100.0	99.8
Dev	Year	1 yr	100.0	100.0	100.0	99.9	100.0	99.9	100.0	99.8	100.0	99.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion								
	Įŧ	5toT	4		4		-		-		=	
Malfunctions	rapy ction Not npromised	un	I		I		I		I		I	
Malfur	rapy Function opromised		T		T		T		T		1	
	mal Battery eletions		889		2,527		944		47		3,510	
	bətem SU əv stnsi	itoA	1,000		1,000		1,000		400		1,000	
	istered mplants		17,000		26,000		18,000		4,000		38,000	
	Narket sase		Mar-92		96-Inf		96-Inf		Oct-95		Oct-95	
	del nber	ooM	7107, 7108		7088, 7089		8088,		8085, 8086		7860, 7861, 7862	
	بالع	твЯ	Minuet		Preva DR		Preva SR		Prevail S		Prodigy DR	

ָ ע	Implantab	le l	Pulse Gen	erator	s, cont	inued										
		16 yr														
		14 yr	100.0 +.0/0 at 158 mo	31.4 +2.9/-2.9 at 158 mo												
		12 yr	100.0+.0/0	46.4							99.6 +.1/2 at 124 mo	73.9 +3.0/-3.3 at 124 mo	99.7 +.1/3 at 123 mo	82.8 +2.5/-2.9 at 123 mo	99.5 +.1/1 at 126 mo	73.6 +2.7/-2.9 at 126 mo
		10 yr	100.0	74.3 +1.2/-1.3					100.0 +.0/0 at 97 mo	93.4 +3.0/-5.2 at 97 mo	99.6 +.1/2	78.7 +2.0/-2.1	99.7	85.0 +2.0/-2.2	99.5	81.9
		8 yr	100.0	91.7 +.6/6					100.0	93.4 +3.0/-5.2	99.6 +.1/2	93.6 +.6/7	99.7	94.5	99.5	95.0
		7 yr	100.0	94.9					100.0	96.6	99.8	97.3 +.4/4	99.7	96.8	99.7	97.8
		6 yr	100.0	96.6					100.0	98.7	100.0	99.0	99.9	98.6	99.8	98.8
		5 yr	100.0	97.7 +.2/3					100.0	98.7 +.8/-2.2	100.0	99.5	99.9	99.2 +.2/3	9.99.9	99.4
bility (%		4 yr	100.0	98.6	100.0 +.0/0 at 44 mo	99.7 +.1/1 at 44 mo	100.0 +.0/0 at 44 mo	99.5 +.3/7 at 44 mo	100.0	99.6	100.0	99.8	100.0	99.7	9.999.0	99.6
Device Survival Probability (%)	plant	3 yr	100.0	99.2 +.1/1	100.0	99.8	100.0	99.8	100.0	99.6	100.0	99.9	100.0	99.8	100.0	99.8
Surviva	Years After Implant	2 yr	100.0	99.6	100.0	100.0	100.0	9.99.9	100.0	100.0	100.0	99.9	100.0	99.9	100.0	99.9
Device	Years	1 yr	100.0	99.8	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	99.9	100.0	100.0
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion						
			E Norma D	Norma	Norma	Norm	Nor	Norn	Nora	Norn	Nor	Nor	Nor	Norm	Norm	Nor
	ls	тот	4 Norma	Norma	6 Norma	Norm	2 Norm	Norm	0 Norm		25 Norr		13 Norm	-	181 Norm	æ
ctions	Vgers Moot Not Desimongr Je	Fur Cor	Norn	Norma		Norm		Norm		(0) ubset)		(14) ubset)		(10)		æ
Malfunctions	rction Not mpromised	The Turi Turi Too	Norn	Norma	9 =	Norm L	= 2	Norn	0	= (0) ed subset)	= 25	= (14) ed subset)	= 13	= (10) ed subset)	181	= (104) ed subset)
Malfunctions	pasimorqm yqara yoy noitot basimorqm	The Cor The The Turi	Norn	Norma	+ + 6	Norm	+ 1 = 2	Norn	0 = 0 +	$\frac{(0)}{(advisory-related subset)}$	+ 1 = 25	ation	+ 0 = 13	ation $(10) + (0) = (10)$ $(advisory-related subset)$	+ 6 = 181	ation (104) + (0) = (104) (advisory-related subset)
Malfunctions	pletions prepy Function mpromised srapy rction Not npromised	Action Month of Month	Могт	Norma	2 + 4 = 6	Norm	1 + 1 = 2	Norm	0 = 0 + 0	$\frac{(0)}{(advisory-related subset)}$	24 + 1 = 25	ation	13 + 0 = 13	ation $(10) + (0) = (10)$ $(advisory-related subset)$	175 + 6 = 181	ation (104) + (0) = (104) (advisory-related subset)
Malfunctions	ive US plants mal Battery pletions mpromised mpromised rotion Not propy	SU Act Implimation Mol Del The Con	1,140 — 4 Norm	Norma	17 2 + 4 = 6	Norm	11 + 1 = 2	Norm	13 0 + 0 = 0	$\frac{(0)}{(advisory-related subset)}$	297 24 + 1 = 25	ation	134 13 + 0 = 13	ation $(10) + (0) = (10)$ $(advisory-related subset)$	42,000 1,097 175 + 6 = 181	ation (104) + (0) = (104) (advisory-related subset)
Malfunctions	Implants inve US size	Regular Regula	2,000 1,140 — — 4 Norm	Norma	61,000 17 2 + 4 = 6	Norm	36,000 11 + 1 = 2	Norm	100 13 0 + 0 = 0	$\frac{43}{43}$ – 2005 Potential Separation (0) + (0) = (0) (advisory-related subset)	5,000 297 24 + 1 = 25	ation	3,000 134 13 + 0 = 13	ation $(10) + (0) = (10)$ $(advisory-related subset)$	1,097 175 + 6 = 181	ation (104) + (0) = (104) (advisory-related subset)
Malfunctions	gistered implants in a feed sive US solutions in a feet of the US solutions in a feet of the US solution is a feet on its of the US solution is a feet of the US	Nui Reg US Est Hag Imp Imp Imp Imp Imp Imp Imp Imp Imp Imp	22,000 2,000 1,140 — — 4 Norm	Norma Norma D	74,000 61,000 17 2 + 4 = 6	Norm	48,000 36,000 11 1 + 1 = 2	Norm	1,000 100 13 0 + 0 = 0	(0) ubset)	16,000 5,000 297 24 + 1 = 25	(14) ubset)	12,000 3,000 134 13 + 0 = 13	(10)	107,000 42,000 1,097 175 + 6 = 181	æ

Device Survival Summary continued

16 yr 100.0 +.0/-.0 at 154 mo 30.6 +2.0/-2.0 14 yr 100.0 99.9 +.0/-.0 at 140 mo 76.2 +3.2/-3.6 at 125 mo 57.2 +3.3/-3.4 12 yr 99.7 +.1/-.1 at 125 m 9.1 +.7/-.7 at 140 r 100.0 100.0 82.2 +1.6/-1.7 99.5 +.5/-3.3 at 99 mo 88.8 +1.4/-1.6 10 yr 99.9 100.0 68.3 +.5/-.5 100.0 99.7 80.0 88.9 +3.6/-5.2 99.5 +.5/-3.3 100.0 8 yr 94.5 99.9 92.7 100.0 94.5 99.7 98.1 100.0 99.9 100.0 100.0 97.2 +.3/-.3 96.9 98.9 99.8 +.1/-.1 96.5 98.8 6 yr 98.5 100.0 99.9 100.0 98.2 +.2/-.2 100.0 99.0 99.9 98.1 99.4 100.0 100.0 100.0 5 yr 100.0 100.0 99.2 99.0 98.9 99.1 Device Survival Probability (%) 100.0 +.0/-.0 at 44 mo 99.8 +.1/-.1 at 44 mo 100.0 100.0 100.0 100.0 100.0 100.0 4 yr 99.5 99.5 99.4 +.0/-.1 99.4 100.0 100.0 100.0 100.0 100.0 100.0 100.0 3 yr 99.7 Years After Implant 99.8 99.7 99.6 99.6 2 yr 100.0 99.9 100.0 100.0 100.0 99.9 100.0 99.9 100.0 100.0 100.0 99.8 +.1/-.2 100.0 100.0 100.0 100.0 99.9 100.0 100.0 99.9 100.0 100.0 100.0 1 yr 99.9 Including mal Battery Depletion Excluding Normal Battery Depletion Including rmal Battery Depletion Excluding Normal Battery Depletio Including Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletio Including mal Battery Depletion Excluding Normal Battery Depletion Including (20) (advisory-related subset) 0 Total 2 35 20 п II П Compromised Malfunctions Function Not 0 Тһегару + + Compromised (20) Therapy Function 7 12,803 2,610 Depletions 273 13 Advisories: See page 143–2005 Potential Separation of Interconnect Wires; See also page 139–2009 Potential Separation of Interconnect Wires Advisories: See page 143–2005 Potential Separation of Interconnect Wires Normal Battery 27 lmplants 16,000 51,000 2,000 1,000 **Active US** 100 400 Estimated 122,000 62,000 50,000 54,000 1,000 5,000 US Implants Registered Sep-99 Oct-95 Oct-95 -96 90-Inf Release Mar-US Market SVDD303 VEDR01 7960i, 7961i, 7962i 8960i, 8961i, 8962i 8968i Иптрег IəboM Sigma 300 Sigma 300 Thera-i DR Thera-i SR Versa DR Thera-i VDD VDD

Family



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated I	ongevity					
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators			
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.3 6.0	**			
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**			
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**			
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**			
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**			
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.			
EnPulse DR	E1DR01, E1DR03, E1DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**			
EnPulse DR	E1DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**			
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**			
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**			
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**			
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**			
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**			
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.6 8.0 5.4	12.3 10.3 7.8	**			
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**			
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**			
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**			
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**			

^{**}Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

		Estimated Long	evity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 920 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g., VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g., VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (A, RV) Nominal 4.0 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.

 $[\]ensuremath{^{**}}\text{Telemetry}$ indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

Estimated	l Longe	vity
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Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera-i DR	7960i, 7961i, 7962i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Thera-i SR	8960i, 8961i, 8962i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Thera-i VDD	8968i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	11.5 9.6 7.7	12.4 11.1 9.7	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**

 $^{^{**}\}mbox{Telemetry}$ indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 27 years with its multicenter, global chronic lead studies.

Leads Performance Analysis

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted, nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

Returned Product Analysis Shortfalls

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads that are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although returned product analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

System Longevity Study (SLS)

The SLS is a prospective, non-randomized multicenter, global study designed to monitor the performance of market-released cardiac therapy products. Medtronic has been monitoring the performance of its cardiac therapy products with a multicenter study for 27 years and has evaluated the performance of more than 75,000 leads, with data reported from 14 countries on four continents.

The primary purpose of the SLS is to evaluate and publish the long-term reliability and performance of Medtronic market-released cardiac therapy products by analyzing product survival probabilities. Productrelated adverse events, indicating the status of the product, are collected to measure survival probabilities. The data gathered in this study may also be used to support the design and development of investigational plans for new cardiac therapy products. The SLS is designed to continue indefinitely, encompassing new products as they become commercially available.

Eligible products for study enrollment include all Medtronic market-released cardiac therapy products. Medtronic may limit overall enrollment of any product when the number of enrollments provides an adequate number to effectively assess product survivability. Medtronic reserves the right to close enrollment of a product at a site level in order to ensure all participating sites have an equal opportunity to enroll.

To ensure a sufficiently large and representative source of data, participating clinical centers must meet specific selection criteria. In addition, centers are selected to be representative of the range of clinical environments in which Medtronic conducts business.

Investigators enroll qualified subjects with specific Medtronic market-released cardiac therapy products and follow these subjects from their implant date until they can no longer be followed (e.g., death and lost to follow-up). Using a Clinical Investigation Plan, each center monitors and reports on the performance of specific Medtronic market-released cardiac therapy products (e.g., product-related adverse events, replacements and abandonments) and subject status (e.g., subject death and subject withdrawal from the study). Subjects will be followed by their respective center in accordance with the center's established practices for routine follow-up.

Patients are eligible for enrollment in the study if:

- 1. They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2. They participated in a qualifying study of a marketreleased Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

The Standard Actuarial Method is used to determine estimates of lead survival.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. The follow-up schedule for this study is based on utilizing routine, scheduled office/clinic visits and unscheduled office/ clinic visits prompted by symptoms or complaints. Data collected at each follow-up includes routine clinical electrical data, any system modifications, and any lead or generator adverse events.

Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is abandoned or explanted, the patient is no longer available for follow-up, or more than 24 months have passed since last follow-up. The data analyses assume that the patient is still part of the study and no lead complications had occurred as of the report cutoff date unless specifically reported by the center.

Medtronic evaluates center compliance with study protocol through clinical monitoring at each study site. Additionally, study center personnel must be trained in the study procedures prior to participating, and they must adhere to the policies and procedures of their local ethics boards.

Lead Complications

All adverse events are critically evaluated by a Medtronic technical review committee and the investigator is asked to assess the relationship of the adverse event to the presence or performance of the implanted system, generator and/or lead(s).

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

Clinical Observations

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3,000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance
- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Data Analysis Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

Survival times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, subject leaves the study, the lead is no longer being used, or no data has been reported within a specified time interval), or the cutoff date of the report. If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are in the tables in this report.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve.

Although the report provides tabular data in 1-year intervals, the curves are actually computed and plotted using 3-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, including data from 14 countries on four continents, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report for at least 20 years as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

Medtronic, at its discretion, may stop providing updated performance information on lead models that received original US market-release approval 20 or more years ago. These models may be removed from this report at that time.

Returned Product Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

The results of the analysis is presented in four categories. The lead reporting categories are:

• Conductor Fracture: Conductor malfunction with complete or intermittent loss of continuity that could interrupt current flow (e.g., fractured conductors), including those associated with clavicle flex fatigue or crush damage.

- Insulation Breach: A malfunction of the insulation allowing inappropriate entry of body fluids or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions, abrasions, and material degradation.
- Crimps/Welds/Bonds: Any malfunction in a conductor or lead body associated with a point of connection.
- Other: Malfunctions of specific lead mechanical attributes, such as sensors, connectors, seal rings, or malfunction modes not included in the three categories

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis from the United States. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS centers around the world.

US Reports of Acute Lead Observations (Occurring within First Month of Service)

In the first weeks following lead implantation, physiologic responses and lead performance can vary until longterm lead stability is attained. Acute (defined as the first month after implant) lead performance may be subject to a number of factors, including patient-specific anatomy,

clinical conditions and/or varying implant conditions/ techniques. After a period of time, the implant and the lead performance stabilizes. It is for this reason that the System Longevity Study results, which are intended to measure long-term performance, do not include complications that occur within the first 30 days after implant.

Information about the clinical experience in the first month of service is included in this report. The source for this information is Medtronic's complaint handling system database. The information is summarized in tables titled "US Reports of Acute Lead Observations." To be included in this summary of observations, a lead must first be successfully implanted and registered in Medtronic's Device and Registrant Tracking system.

Each Event Report received by Medtronic's complaint handling system is assigned one or more Reason for Report codes based on the information received. The Reason for Report codes have been grouped into Acute Lead Observation categories. The categories used for this product performance report are drawn from the "FDA Guidance for Submission of Research and Marketing Applications for Permanent Pacemaker Leads and for Pacemaker Lead Adapter 510(k) Submissions." The categories are:

- 1. Cardiac Perforation
- 2. Conductor Fracture
- 3. Lead Dislodgement
- 4. Failure to Capture
- 5. Oversensing
- 6. Failure to Sense
- 7. Insulation Breach
- 8. Impedance Abnormal
- 9. Extracardiac Stimulation
- 10. Unspecified

Although multiple observations are possible for any given lead, only one observation is reported per lead. The observation reported is the observation highest on the list. For example, if an Event Report includes observations for both Lead Dislodgement and Failure to Sense, Lead Dislodgement is reported.

The lead event reported to Medtronic may or may not have involved clinical action or product returned to Medtronic. The lead may have remained implanted and in service.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides the number of leads registered as implanted and the number remaining active in the United States based on the status recorded in the Medtronic Device and Registrant Tracking system.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Returned Product Analysis results for these models are included here for reference and comparison.

Left-Heart Leads

2187 Attain LV

Product Characteristics

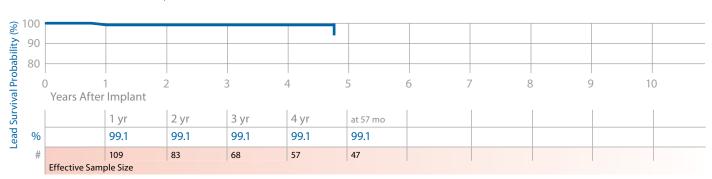
US Market Release	Aug-01	Serial Number Prefix	LEY	US Returned Product Ana	alysis
Registered US Implants	12,000	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Continuous Curve	Conductor Fracture Crimp/Weld/Bond	0
Estimated Active US Implants	3,600	Polarity	Unipolar	Insulation Breach	0
Advisories	None	Steroid	No	Other	16

System Longevity Study Results

Qualifying Complications

1 Total Failure to Capture

Number of Leads Enrolled in Study 134 Cumulative Months of Follow-Up 6,220 27 Number of Leads Active in Study



2188 Attain CS

Product Characteristics

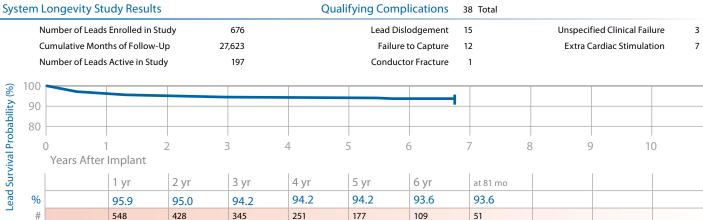
	tetuiii G5			T TO GGC CT	iaracteristic.						
U	S Market Release		Aug-01	Serial Numbe	r Prefix	LEB			US Retu	rned Product Ai	nalysi
Re	egistered US Imp	lants	1,800	Type and/or F	ixation	Transvenous, C Cardiac Vein, C		nus/		nductor Fracture rimp/Weld/Bond	
Es	stimated Active U	IS Implants	400	Polarity		Bipolar				nsulation Breach	
A	dvisories		None	Steroid		No				Other	
tem L	ongevity Stu	dy Results			Qualifyir	ng Complicati	ons	1 Total			
N	umber of Leads E	nrolled in Study	15	i	Extr	a Cardiac Stimula	ation	1			
Ci	umulative Month	s of Follow-Up	460)							
N	umber of Leads A	Active in Study	C)							
90 80	Survival estim	nate not available o	due to insuffici	ent sample size	2						
90											
80											-
	0	1 2	3	4	L	5 6	5	7	8	9	10
		_	J					,	O		10
	Years After I	mplant									
		at 0 mo									
%		100.0									
#		13									
	Effective Sample	e Size									

4193 Attain OTW

Product Characteristics

US Market Release	May-02	Serial Number Prefix	BAA	US Returned Product Ana	alysis
Registered US Implants	100,600	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Conductor Fracture Crimp/Weld/Bond	32 0
Estimated Active US Implants	46,400	Polarity	Unipolar	Insulation Breach	2
Advisories	None	Steroid	Yes	Other	71

Effective Sample Size



4194 Attain OTW

Lead Survival Probability (%)

Product Characteristics

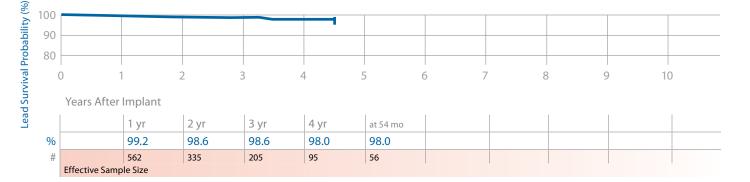
US Market Release	Aug-04	Serial Number Prefix	LFG	US Returned Product Ana	alysis
Registered US Implants	91,800	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Conductor Fracture	4
Estimated Active US Implants	63,500	Polarity	Bipolar	Crimp/Weld/Bond Insulation Breach	0 24
Advisories	None	Steroid	Yes	Other	13

System Longevity Study Results

100

Qualifying Complications 10 Total

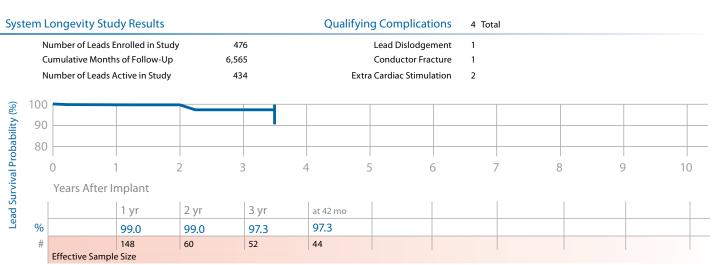
Number of Leads Enrolled in Study	847	Lead Dislodgement	7
Cumulative Months of Follow-Up	20,563	Failure to Capture	2
Number of Leads Active in Study	642	Insulation (ESC)	1



4195 Attain StarFix

Product Characteristics

US Market Release	Aug-08	Serial Number Prefix	AAD	US Returned Product Ana	lysis
Registered US Implants	8,600	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Deployable Lobe Fixation	Conductor Fracture Crimp/Weld/Bond	1 0
Estimated Active US Implants	7,500	Polarity	Unipolar	Insulation Breach	1
Advisories	None	Steroid	Yes	Other	19



4196 Attain Ability

Product Characteristics

7130	Attaili Abii	псу		Product Ci	iaracteristics							
	US Market Release	2	May-09	Serial Numbe	r Prefix	PVI			US Retui	ned Product Ar	nalysis	
	Registered US Imp	olants	18,700	Type and/or F	ixation	Transvenous, Le Preformed Bod			Conductor Fracture		0	
	Estimated Active U	JS Implants	17,100	Polarity		Bipolar			Crimp/Weld/Bond Insulation Breach			
	Advisories		None	Steroid		Yes			"	Other	13	
Syster	m Longevity Stu	dy Results			Qualifyin	g Complicati	ons 0 Tota	al				
	Number of Leads I	Enrolled in Study	668	;								
	Cumulative Month	ns of Follow-Up	4,786	i								
	Number of Leads A	Active in Study	638	;								
<u> </u>	00											
× (%												
oilit	90											
obal	80											
Lead Survival Probability (%)	0	1 2	3	4	1	5 6		7	8	9	10	
urviv	Years After I	mplant										
ad S		1 yr										
Le	%	100.0										
	#	50										
	Effective Sampl	e Size										

Lead Survival Summary (95% Confidence Interval)

		US Market Release	rolled	Leads Active in Study	ng ations	Cumulative Months of Follow-Up in Study	Device Survival Probability (%) Years After Implant								1	
Model Number	Family	US Mark	Leads Enrolled	Leads Ac	Qualifying Complications	Cumulat Follow-U	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
2187	Attain LV	Aug-01	134	27	1	6,220	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1 at 57 mo.					
2188	Attain CS	Aug-01	15	0	1	460	100.0 at 0 mo									
4193	Attain OTW	May-02	676	197	38	27,623	95.9 +1.3/-1.8	95.0 +1.4/-2.1	94.2 +1.7/-2.2	94.2 +1.7/-2.2	94.2 +1.7/-2.2	93.6 +1.9/-2.6	93.6 +1.9/-2.6 at 81 mo.			
4194	Attain OTW	Aug-04	847	642	10	20,563	99.2 +0.4/-1.0	98.6 +0.7/-1.4	98.6 +0.7/-1.4	98.0 +1/-2.1	98.0 +1/-2.1 at 54 mo.					
4195	Attain StarFix	Aug-08	476	434	4	6,565	99.0 +0.7/-2.3	99.0 +0.7/-2.3	97.3 +2/-6.8	97.3 +2/-6.8 at 42 mo.						
4196	Attain Ability	May-09	668	638	0	4,786	100.0									

Source: System Longevity Study Data as of July 31, 2010

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
2187	Attain LV	Aug-01	12,000	3,600	0	0	0	16
2188	Attain CS	Aug-01	1,800	400	1	0	0	0
4193	Attain OTW	May-02	100,600	46,400	32	0	2	71
4194	Attain OTW	Aug-04	91,800	63.500	4	0	24	13
4195	Attain StarFix	Aug-08	8,600	7,500	1	0	0	19
4196	Attain Ability	May-09	18,700	18,700	0	0	1	13

Source: Returned Product Analysis Data as of July 31, 2010

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
2187	Attain LV	12,000	1	0	8	3	0	1	0	0	1	0
2188	Attain CS	1,800	0	0	2	0	0	0	0	0	0	0
4193	Attain OTW	100,600	0	1	49	14	0	0	0	1	17	0
4194	Attain OTW	91,800	0	2	46	15	1	0	0	3	9	3
4195	Attain StarFix	8,600	0	0	12	7	0	0	0	0	6	0
4196	Attain Ability	18,700	0	0	21	2	0	0	2	4	10	1

Report Cutoff Date: July 31, 2010

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain LV	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain CS	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 BI
4193	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI
4195	Attain StarFix	Transvenous Cardiac Vein Deployable Lobes	Polyurethane (55D)	MP35N	Platinum Alloy	IS-1 Uni
4196	Attain Ability	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D), SI polyimide	Ag core – MP35N	Tapered, Annualar, Titanium nitride	IS-1 BI

0

0

0

Defibrillation Leads

6721, 6921 Epicardial Patch **Product Characteristics** US Market Release Feb-93 Serial Number Prefix TBH, TBG, TBB, TAD, TAC, or TAB **US Returned Product Analysis** Registered US Implants 8,500 Type and/or Fixation Epicardial Defib Patch, Suture Conductor Fracture Crimp/Weld/Bond **Estimated Active US Implants** 1,400 Polarity Defib Electrode only Insulation Breach 10 Advisories None Steroid Other **Qualifying Complications** System Longevity Study Results 52 Total Number of Leads Enrolled in Study 407 Failure to Capture Impedance Out of Range 8 4 Cumulative Months of Follow-Up 19,695 Conductor Fracture 21 Oversensing 16 Insulation (not further defined) Number of Leads Active in Study 8 3 Lead Survival Probability (%) 90 80 70 0 2 3 5 6 8 9 10 Years After Implant 7 yr at 93 mo 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr % 96.5 95.0 92.3 91.3 88.1 81.0 78.9 78.9

121

84

66

0 Total

54

6930 Sprint Fidelis Product Characteristics US Market Release Sep-04 Registered US Implants 400

Effective Sample Size of Lead Group Overall

282

209

Steroid

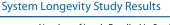
158

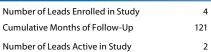
Serial Number Prefix LFK Type and/or Fixation Transvenous, Vent, Defib and Pace/Sense, Tines Polarity True Bipolar/One Coil

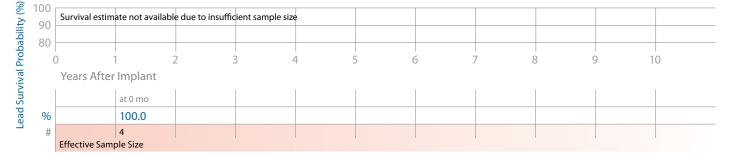
Yes

Qualifying Complications

Estimated Active US Implants 200 Advisories See page 141 - 2007 Potential Conductor Wire Fracture







US Returned Product Analysis

Conductor Fracture

Crimp/Weld/Bond

Insulation Breach

Other

6931 Sprint Fidelis

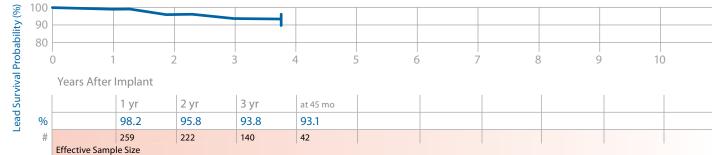
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFL	US Returned Product An	alysis
Registered US Implants	8,100	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture Crimp/Weld/Bond	312 0
Estimated Active US Implants	5,100	Polarity	True Bipolar/One Coil	Insulation Breach	Ö
Advisories	1	Steroid	Yes	Other	2
See page 141 – 2007 Potential Co Fracture	onductor Wire				

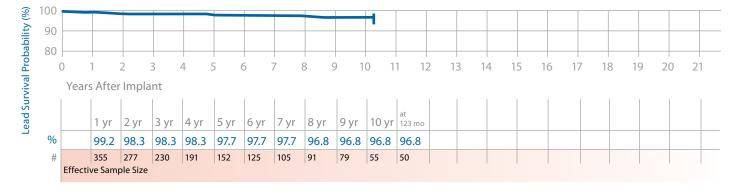
System Longevity Study Results

Qualifying Complications 19 Total

Number of Leads Enrolled in Study	294	Lead Dislodgement	2	Impedance Out of Range	6
Cumulative Months of Follow-Up	9,947	Failure to Capture	3	Oversensing	3
Number of Leads Active in Study	195	Conductor Fracture	3	OTH	1
		Failure to Sense	1		



6932	2 Sprint		Product Character	ristics			
	US Market Release	Aug-96	Serial Number Prefix	TCA		US Returned Product Ana	alysis
	Registered US Implants	15,000	Type and/or Fixation	Transvenous, Vent, De Tines	efib and Pace/Sense,	Conductor Fracture Crimp/Weld/Bond	19 0
	Estimated Active US Implants	5,200	Polarity	True Bipolar/One Coil		Insulation Breach	22
	Advisories	None	Steroid	Yes		Other	8
Syster	m Longevity Study Results		Qua	alifying Complications	11 Total		
	Number of Leads Enrolled in Study	411		Failure to Capture	2	Extra Cardiac Stimulation	1
	Cumulative Months of Follow-Up	23,680)	Failure to Sense	2	Oversensing	4
	Number of Leads Active in Study	63	3	Impedance Out of Range	2		



6933, 6937, 6937A, 6963 SVC/CS

Product Characteristics

<i>333</i> , 0	,,,,,,,	377.	0,00		,		Todac	.c Citai	acteris	rtics										
US	Market Rele	ase			Dec-93		Serial Nu	ımber Pr	efix	TA	T, TBU, c	or TAF				US R	eturne	d Proc	duct Ar	nalysis
Re	egistered US	mplants			16,000	1	ype and	l/or Fixa	tion	Tr	ansveno	us CS or S\	/C Defi	b					racture	
Es	timated Acti	ve US Im	plants		2,700	F	Polarity One Defib Coil				Coil						•	d/Bond		
Ac	dvisories				None	9	steroid			No)						Ins	ulation	Breach Other	
ystem Lo	ongevity S	Study R	esults						Quali	fying	Compl	ications	57	Total						
Νι	umber of Lea	ds Enroll	ed in Stu	ıdy		966				Le	ad Dislo	dgement	1			lm	pedano	e Out of	f Range	4
Cu	umulative Mo	nths of F	ollow-U	р	49	,714					Failure t	o Capture	8			Uns	pecified	Clinical	Failure	4
Νι	umber of Lea	ds Active	e in Study	y		27				C	onducto	r Fracture	20			Ex	tra Card	iac Stim	ulation	5
											Failure	e to Sense	1					Overs	sensing	12
									Insula	ation (no	t furthe	r defined)	2							
100																				
90																				
80 -											•									
0	1	2	3 4	4 5	5 6		7	8	9 1	0 1	1 1	2 13	14	15	16	17	18	19	20	21
2	Years After	Impla	nt																	
90 - 80 - 0	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 135 mo								
g %	98.4	97.5	97.2	96.6	-	94.4	93.2		91.3	90.2	90.2									
#	809	629	501	403		249	179	141	95	71	53	48								
	Effective San	nple Size																		· ·

6935 Sprint Quattro Secure

Product Characteristics

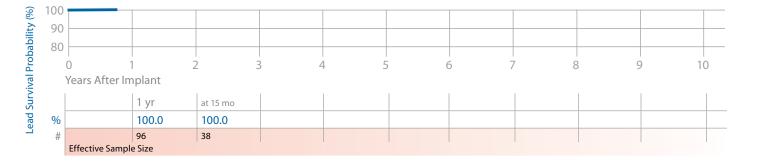
US Market Release	Nov-08	Serial Number Prefix	TAU	US Returned Product Analysis
Registered US Implants	11,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 1 Crimp/Weld/Bond 0
Estimated Active US Implants	11,000	Polarity	True Bipolar/One Coil	Insulation Breach 0
Advisories	None	Steroid	Yes	Other 14

Performance Note: <u>See page 147</u> – Helix Retraction

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study 445 Cumulative Months of Follow-Up 3,898 Number of Leads Active in Study 430



6936, 6966 Transvene

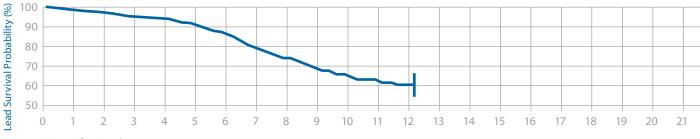
Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TAV or TAL	US Returned Product Analysis
Registered US Implants	23,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 178 Crimp/Weld/Bond 0
Estimated Active US Implants	2,900	Polarity	True Bipolar/One Coil	Insulation Breach 334
Advisories	None	Steroid	No	Other 22

System Longevity Study Results

Qualifying Complications 198 Total

Number of Leads Enrolled in Study	1,349	Failure to Capture	18	Impedance Out of Range	8
Cumulative Months of Follow-Up	70,071	Conductor Fracture	23	Unspecified Clinical Failure	5
Number of Leads Active in Study	29	Failure to Sense	6	Extra Cardiac Stimulation	7
		Insulation (not further defined)	13	Oversensing	118



Years After Implant

		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 147 mo				
%		98.2	97.0	95.1	94.1	90.4	85.8	78.1	73.8	67.8	63.8	61.6	59.8	58.7				
#		1,140	906	734	580	458	359	248	188	132	99	74	54	50				
	Effecti	ve Sam	ole Size															

TBA or TAP

6939, 6999 Sub-Q Patch

US Market Release

Product Characteristics

Serial Number Prefix

Dec-93

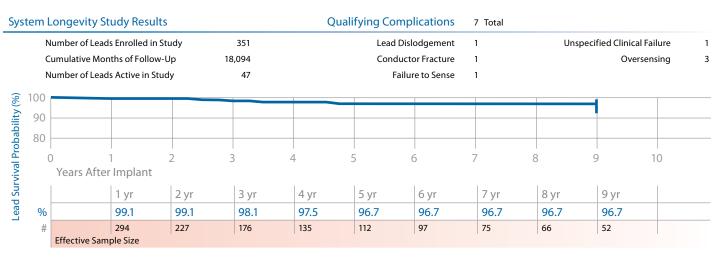
	Registered US Im	plants	3,60	00 Ty	ype and/or Fixation	Subcutaneou	s Defib Pa	atch, Suture	Cond	uctor Fracture	2
	Estimated Active	US Implants	30	00 P	olarity	Defib Electro	de Only			np/Weld/Bond	
	Advisories		Non	ne St	teroid	No			Ins	ulation Breach Other	
sten	n Longevity Stu	udy Results			Quali	fying Complica	tions	47 Total		other	
	Number of Leads	Enrolled in Stu	dy	384		Failure to C	apture	11	Impedar	ice Out of Range	
	Cumulative Mont	hs of Follow-U	p 1	18,079		Conductor Fr	acture	12	Unspecifie	d Clinical Failure	
	Number of Leads	Active in Study	/	3		Failure to	Sense	1	Extra Car	diac Stimulation	
					Insula	tion (not further de	efined)	4		Oversensing	
10	0 =										
100	U										
				_							
9(0						_				
9(~				
9(2	3	4	5 6	~	7	8	9 10	
		l mplant	2	3	4	5 6	_	7	8	9 10	
81	0	l mplant	2 yr	3 3 yr			6 yr	7 7 yr	8 at 93 mo	9 10	
91 81	0		_		r 4 yr	5 yr	6 yr 88.3	7 yr 86.0	1	9 10	

US Returned Product Analysis

6942 Sprint

Product Characteristics

US Market Release	Jul-97	Serial Number Prefix	ТСВ	US Returned Product Ana	lysis
Registered US Implants	17,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture Crimp/Weld/Bond	14 1
Estimated Active US Implants	6,600	Polarity	Integrated Bipolar/Two Coils	Insulation Breach	21
Advisories	None	Steroid	Yes	Other	8



6943 Sprint

US Market Release

Product Characteristics

Serial Number Prefix

Oct-97

										00111		0.0.00	, 55
	Registered US Implants Estimated Active US Implants			20,800	Type and	d/or Fixation		ous, Vent, De se, Screw-in	fib and		Conductor Crimp/We		54 1
				7,900	Polarity		True Bipo	olar/One Coil			Insulation		23
		Advisories		None	Steroid		Yes				msalation	Other	9
Syste	m	Longevity St	udy Results			Qual	ifying Comp	lications	84 Total				
		Number of Lead	s Enrolled in St	udy 1,	312		Lead Dis	odgement	1	Insulatio	n (not further o	defined)	1
		Cumulative Mor	nths of Follow-U	Jp 75,2	232		Failure	to Capture	11	Im	pedance Out o	of Range	8
		Number of Lead	s Active in Stud	ly :	307		Conduct	or Fracture	18	Unsp	pecified Clinica	l Failure	3
							Failu	re to Sense	6		Ovei	sensing	36
% 1	00												
Lead Survival Probability (%)	90												
abi	80												
Prok		0	1	2 3		4	 5	1 6	7	8	9	10	
val		Years After	•	2 3		7	5	0	/	O		10	
urvi		rears Arter	ППРІАПІ			1	I	ı	ı	1	1		
<u>d</u> S			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 y	r
Lea	%		98.7	97.7	96.5	95.5	93.5	92.2	91.5	91.2	90.1	90.1	

591

447

316

211

TCE

967

859

722

1,148

Effective Sample Size

116

52

US Returned Product Analysis

2 yr

123

100.0

1 yr

187

Effective Sample Size

100.0

3 yr

99.1

101

6944 Sprint Quattro

Product Characteristics

US Market Release	Dec-00	Serial Number Prefix	TDC	US Returned Product Analysis
Registered US Implants	36,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture 47 Crimp/Weld/Bond 2
Estimated Active US Implants	21,000	Polarity	True Bipolar/Two Coils	Insulation Breach 2
Advisories	None	Steroid	Yes	Other 10

System Longevity Study Results Qualifying Complications 5 Total Number of Leads Enrolled in Study 302 Failure to Sense 1 Cumulative Months of Follow-Up 10,399 Impedance Out of Range 1 Number of Leads Active in Study 171 **Unspecified Clinical Failure** 1 Oversensing Lead Survival Probability (%) 100 90 80 2 3 5 6 7 8 9 4 10 Years After Implant

5 yr

94.3

61

6945 Sprint

%

Product Characteristics

4 yr

97.0

75

US Market Release	Sep-97	Serial Number Prefix	TDA	US Returned Product Analysis
Registered US Implants	42,800	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 105 Crimp/Weld/Bond
Estimated Active US Implants	16,000	Polarity	Integrated Bipolar/Two Coils	Insulation Breach 27
Advisories	None	Steroid	Yes	Other 14

System Longevity Study Results

Qualifying Complications

6 yr

94.3

56

at 78 mo

94.3

50

Number of Leads Enrolled in Study	1,154	Failure to Capture	2	Unspecified Clinical Failure	1
Cumulative Months of Follow-Up	62,445	Conductor Fracture	7	Extra Cardiac Stimulation	1
Number of Leads Active in Study	168	Failure to Sense	4	Oversensing	17
		Impedance Out of Range	5		





6947 Sprint Quattro Secure

Product Characteristics

US Market Release	Nov-01	Serial Number Prefix	TDG	US Returned Product Analysis
Registered US Implants	281,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 171 Crimp/Weld/Bond 4
Estimated Active US Implants	203,700	Polarity	True Bipolar/Two Coils	Insulation Breach 11
Advisories	None	Steroid	Yes	Other 117

Performance Note: See page 147 -Helix Retraction

System Longevity Study Results

Qualifying Complications 31 Total

Number of Leads Enrolled in Study	2,690	Lead Dislodgement	3	Impedance Out of Range	6
Cumulative Months of Follow-Up	84,784	Failure to Capture	1	Unspecified Clinical Failure	2
Number of Leads Active in Study	1,690	Conductor Fracture	5	Oversensing	10
		Failure to Sense	2		

Insulation (not further defined) 2



6948 Sprint Fidelis

Fracture

Lead Survival Probability (%)

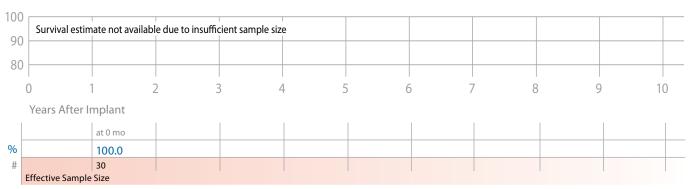
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFH	US Returned Product Ana	alysis
Registered US Implants	10,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture Crimp/Weld/Bond	60 0
Estimated Active US Implants	6,700	Polarity	True Bipolar/Two Coils	Insulation Breach	0
Advisories	1	Steroid	Yes	Other	6
See page 141 - 2007 Potential Co	nductor Wire				

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study 30 Cumulative Months of Follow-Up 1,141 Number of Leads Active in Study 19



6949 Sprint Fidelis

Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFJ	US Returned Product A	nalysis
Registered US Implants	186,800	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture Crimp/Weld/Bond	3,618
Estimated Active US Implants	112,800	Polarity	True Bipolar/Two Coils	Insulation Breach	9
Advisories	1	Steroid	Yes	Other	57
See page 141 – 2007 Potential Co Fracture	onductor Wire				

System Longevity Study Results

Qualifying Complications 44 Total

Number of Leads Enrolled in Study	797	Lead Dislodgement	1	Insulation (not further defined)	1
Cumulative Months of Follow-Up	30.789	Failure to Capture	2	Impedance Out of Range	7
Number of Leads Active in Study	457	Conductor Fracture	20	Oversensing	11
·		Failure to Sense	2	_	



6996 Sub-Q Lead

Product Characteristics

	L	JS Market Release		Jun-01	Serial Number	Prefix	TCR			US Retu	rned Product An	alysis
	R	Registered US Imp	lants	2,900	Type and/or Fi	xation	Subcutaneous	Defib Coil, Sut	ure		nductor Fracture	7
	Е	stimated Active U	JS Implants	1,800	Polarity		One Defib Coil				rimp/Weld/Bond nsulation Breach	0 0
	Δ	dvisories		None	Steroid		No				Other	0
Syste	m l	Longevity Stud	dy Results			Qualifyin	g Complicati	ons 1 To	otal			
	Ν	lumber of Leads E	inrolled in Study	26	j		Conductor Frac	cture 1				
	C	Cumulative Month	s of Follow-Up	705	i							
(%	Ν	lumber of Leads A	Active in Study	19)							
e it	100)										
abil	90	Survival estima	ate not available	due to insufficie	ent sample size							
rob	80											
ival F		0 1	1 2	3	4		 5 6	 5	7	8	9	10
Lead Survival Probability (%)		Years After In	mplant									
Lea			at 0 mo									
	%		100.0									
	#		26									
		Effective Sample	e Size									

		əseələ	pə	in Study با	su	Months o in Study	Device:	Survival	Device Survival Probability (%)	ty (%)									
βĻ		ket R	Iloau	evitoA	ing oitsoi		Years Af	Years After Implant	ant										
ləboM ədmuM	Family	isM 2U	l sbas l	r speə7	Qualify IqmoD		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr	18 yr
6721, 6921	Epicardial Patch	Feb-93	407	8	52	19,695	96.5 +1.5/-2.4	95.0	92.3 +2.5/-3.5	91.3	88.1 +3.6/-4.9	81.0 +5.1/-6.7	78.9 +5.6/-7.3	78.9 +5.6/-7.3 at 93 mo.					
6930	Sprint Fidelis	Sep-04	4	7	0	121	100.0												
	Advisories: See page 141 – 2007 Potential Conductor Wire Fracture	- 2007 Potenti	al Conduct	or Wire Fra	acture		at 0 mo												
6931	Sprint Fidelis	Sep-04	294	195	19	9,947	98.2 +1.1/-2.5	95.8 +1.9/-3.2	93.8 +2.4/-4	93.1									
	Advisories: See page 141 – 2007 Potential Conductor Wire Fracture	- 2007 Potenti	al Conduct	or Wire Fra	acture					at 45 mo.									
6932	Sprint	Aug-96	411	63	11	23,680	99.2 +0.5/-1.7	98.3 +0.9/-2.1	98.3 +0.9/-2.1	98.3 +0.9/-2.1	97.7 +1.3/-2.5	97.7	97.7 +1.3/-2.5	96.8 +1.7/-3.9	96.8 +1.7/-3.9	96.8 +1.7/-3.9 at 123 mo.			
6933, 6937, 6937A, 6963	svc/cs	Dec-93	996	27	57	49,714	98.4 +0.7/-1	97.5 +0.9/-1.3	97.2 +0.9/-1.4	96.6	95.0	94.4	93.2 +2/-2.8	92.7 +2.2/-3.1	90.2	90.2 +3.2/-4.7 at 135 mo.			
6935	Sprint Quattro Secure Nov-08 445 430 0 See page 147 – Performance note on Helix Retraction 6935 and 6947	Nov-08 nce note on He	445 elix Retracti	430 ion 6935 ar	0 nd 6947	3,898	100.0	100.0 at 15 mo.											
6936,	Transvene	Dec-93	1,349	59	198	170,07	98.2 +0.6/-1	97.0	95.1 +1.2/-1.5	94.1	90.4	85.8 +2.5/-3	78.1 +3.5/-3.9	73.8	63.8 +5.1/-5.7	59.8 +5.8/-6.4	58.7 +6.1/-6.7 at 147 mo.		
6669	Sub-Q Patch	Dec-93	384	ю	47	18,079	96.0	94.1 +2/-3.2	93.7 +2.1/-3.3	93.7	91.5	88.3 +3.8/-5.6	86.0 +4.6/-6.6	86.0 +4.6/-6.6 at 93 mo.					
6942	Sprint	76-Inf	351	47	7	18,094	99.1 +0.6/-1.9	99.1 +0.6/-1.9	98.1 +1.1/-2.8	97.5	96.7	96.7	96.7	96.7	96.7 +1.8/-3.8 at 108 mo.				
6943	Sprint	Oct-97	1,312	307	84	75,232	98.7 +0.5/-0.9	97.7 +0.7/-1.1	96.5 +0.9/-1.3	95.5	93.5	92.2 +1.6/-2.1	91.5 +1.8/-2.2	91.2 +1.9/-2.3	90.1 +2.2/-3				
6944	Sprint Quattro	Dec-00	302	171	ιΩ	10,399	100.0	100.0	99.1 +0.8/-5.5	97.0	94.3	94.3 +3.3/-7.7	94.3 +3.3/-7.7 at 78 mo.						
6945	Sprint	Sep-97	1,154	168	37	62,445	99.4	98.7 +0.5/-1	98.3 +0.6/-1.1	97.7 +0.8/-1.3	96.8 +1.1/-1.6	96.1	95.5	94.3 +1.8/-2.6	93.1 +2.3/-3.3	93.1 +2.3/-3.3 at 123 mo.			
6947	Sprint Quattro Secure Nov-01 2,690 1,690 31 See page 147 – Performance note on Helix Retraction 6935 and 6947	Nov-01 nce note on He	2,690 elix Retracti	1,690 ion 6935 ar	31 nd 6947	84,784	99.5 +0.2/-0.4	99.3	99.0	98.6	98.3 +0.6/-1	97.9 +0.8/-1.2	97.1 +1.2/-1.9	97.1 +1.2/-1.9					
6948	Sprint Fidelis	Sep-04	30	19	0	1,141	100 .0 at 0 mo												
	Advisories: See page 141 – 2007 Potential Conductor Wire Fracture	– 2007 Potenti	al Conduct	or Wire Fra	acture														
6949	Sprint Fidelis Sep-04 797 457 44 Advisories: See page 141 – 2007 Potential Conductor Wire Fracture	Sep-04 - 2007 Potenti	797 ial Conduct	457 or Wire Fra	44 acture	30,789	98.8 +0.6/-1.1	97.1	95.2 +1.4/-1.9	94.2	92.8 +2.1/-2.8	92.8 +2.1/-2.8 at 63 mo.							
9669	Sub-Q Lead	Jun-01	26	61	-	705	100.0 at 0 mo												

Lead Survival Summary (95% Confidence Interval)

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
6721, 6921	Epicardial Patch	Feb-93	8,500	1,400	70	1	10	1
6930	Sprint Fidelis	Sep-04	400	200	3	0	0	0
6931	Sprint Fidelis	Sep-04	8,100	5,100	312	0	0	2
6932	Sprint	Aug-96	15,000	5,200	19	0	22	8
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	16,000	2,700	168	0	32	16
6935	Sprint Quattro Secure	Nov-08	11,600	11,000	1	0	0	14
6936, 6966	Transvene	Dec-93	23,700	2,900	178	0	334	22
6939, 6999	Sub-Q Patch	Dec-93	3,600	300	28	0	5	1
6942	Sprint	Jul-97	17,700	6,600	14	1	21	8
6943	Sprint	Oct-97	20,800	7,900	54	1	23	9
6944	Sprint Quattro	Dec-00	36,400	21,000	47	2	2	10
6945	Sprint	Sep-97	42,800	16,000	105	3	27	14
6947	Sprint Quattro Secure	Nov-01	281,700	203,700	171	4	11	117
6948	Sprint Fidelis	Sep-04	10,400	6,700	60	0	0	6
6949	Sprint Fidelis	Sep-04	186,800	112,800	3,618	2	9	57
6996	Sub-Q Lead	Jun-01	2,900	1,800	7	0	0	0

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense	Insulation Breach	Impedance Abnormal	Extracardiac Stimulation	Unspecified
6721, 6921	Epicardial Patch	8,500	0	1	0	0	0	0	2	3	0	4
6931	Sprint Fidelis	8,100	1	2	1	1	3	1	0	0	0	1
6932	Sprint	15,000	0	0	3	2	0	2	0	1	0	0
6933, 6937, 6937A, 6963	SVC/CS	16,000	0	0	2	0	1	0	2	1	0	1
6935	Sprint Quattro Secure	11,600	1	1	3	3	5	0	0	3	0	0
6936, 6966	Transvene	23,700	7	2	1	6	4	5	1	1	0	4
6939, 6999	Sub-Q Patch	3,600	0	0	0	0	0	0	0	1	0	1
6942	Sprint	17,700	1	0	2	4	1	0	0	2	0	1
6943	Sprint	20,800	1	0	0	2	1	1	1	3	0	0
6944	Sprint Quattro	36,400	1	1	6	9	6	2	0	6	0	6
6945	Sprint	42,800	0	1	4	6	8	2	2	1	1	3
6947	Sprint Quattro Secure	281,700	9	14	45	32	65	14	3	26	0	13
6948	Sprint Fidelis	10,400	0	1	7	6	1	0	0	1	0	0
6949	Sprint Fidelis	186,800	9	31	26	31	30	24	6	22	0	12
6996	SubQ	2,900	0	0	0	0	1	0	0	1	0	0

Report Cutoff Date: July 31, 2010

Reference Chart

			Pin Conf	figuration			
Model Number	Family	Туре	Pace/Sense	High Voltage	Lead Body Diameter	Insulation, Lead Body	Fixation, Steroid
6721	Epicardial Patch	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive
69345	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid
6935	Sprint Quattro Secure	Endo RV True Bipolar Sensing	IS-1	DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive
6939	Sub-Q Patch	SQ Patch	_	DF-1	One Size	Silicone, Single Lumen	Suture
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6963	SVC/CS	Endo SVC/CS Coil	_	6.5 mm	7 Fr	Silicone, Single Lumen	Passive
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active
6996	Sub-Q Lead	SQ Coil	_	DF-1	7.5 Fr	Silicone, Single Lumen	Passive
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture

Pacing Leads

3830 SelectSecure

Product Characteristics

US Market Release	Aug-05	Serial Number Prefix	LFF	US Returned Product Analysis
Registered US Implants	17,000	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 2
Estimated Active US Implants	14,200	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 5 Other 3



Ventricular Placement



Cumulative Months of Follow-Up 8,033 Number of Leads Active in Study 195



4023 CapSure SP

Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	LAK	US Returned Product Analysis
Registered US Implants	41,200	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 17
Estimated Active US Implants	8,900	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 3 Other 8
				outer 0

System Longevity Study Results

Qualifying Complications 21 Total

Number of Leads Enrolled in Study	1,158	Lead Dislodgment	2	Impedance Out of Range	1
Cumulative Months of Follow-Up	68,226	Failure to Capture	16	Extra Cardiac Stimulation	1
Number of Leads Active in Study	278	Insulation (not further defined)	1		



4024 CapSure SP

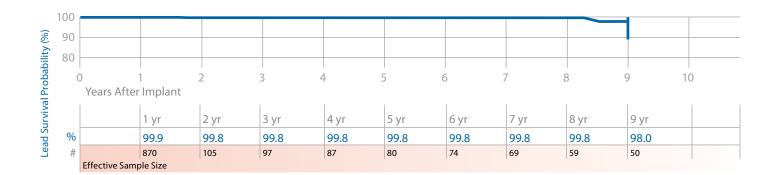
Product Characteristics

ix LAJ	US Returned Product Analysis
on Transvenous, Vent., Tines	Conductor Fracture 28
Bipolar	Crimp/Weld/Bond 0
Yes	Insulation Breach 136 Other 41
	Transvenous, Vent., Tines Bipolar

System Longevity Study Results

Qualifying Complications 4 Total

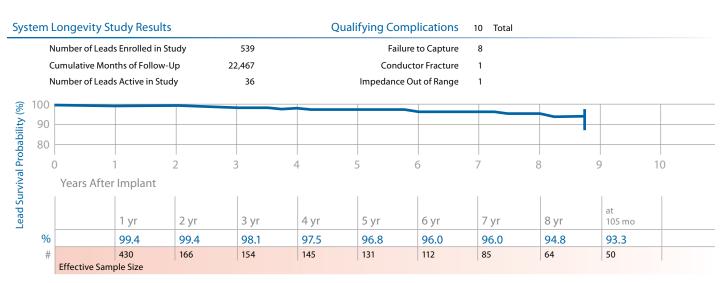
Number of Leads Enrolled in Study	1,215	Insulation (not further defined)	1
Cumulative Months of Follow-Up	30,110	Failure to Capture	3
Number of Leads Active in Study	19		



4033 CapSure Z

Product Characteristics

US Market Release	Not US	Serial Number Prefix	LCA	US Returned Product Analysis
Registered US Implants	released NA	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 0
Estimated Active US Implants	NA	Polarity	Unipolar	Crimp/Weld/Bond 0 Insulation Breach 0
Advisories	None	Steroid	Yes	Other 0

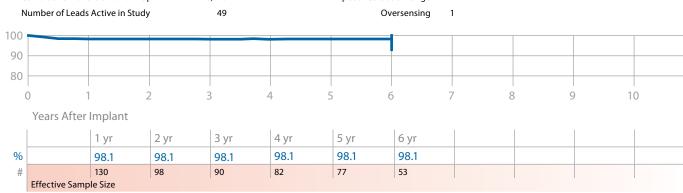


4067 CapSureFix

Product Characteristics

	Capoarerix		Troduct Character	istres			
	US Market Release	Jan-97	Serial Number Prefix	LCV		US Returned Product Ana	alysis
	Registered US Implants	1,000	Type and/or Fixation	Transvenous, V or A, Se	crew-in	Conductor Fracture	1
	Estimated Active US Implants	300	Polarity	Unipolar		Crimp/Weld/Bond	0
	Advisories	None	Steroid	Yes		Insulation Breach Other	0 1
Syste	m Longevity Study Results		Qua	lifying Complications	8 Total		
	Number of Leads Enrolled in Study	17	1	Failure to Capture	6		
	Cumulative Months of Follow-Up	10,14	0	Impedance Out of Range	1		





4068 CapSureFix

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCE	US Returned Product Analysis
Registered US Implants	124,200	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 39
Estimated Active US Implants	38,200	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 104
				Other 16

Qualifying Complications Co. Turk

Atrial Placement

Custom Langavity Ctudy Docults

	otal	56 I	lifying Complications		System Longevity Study Results
2	Insulation (ESC)	8	Lead Dislodgement	2,413	Number of Leads Enrolled in Study
2	Insulation (MIO)	21	Failure to Capture	122,006	Cumulative Months of Follow-Up
6	Impedance Out of Range	2	Conductor Fracture	464	Number of Leads Active in Study
3	Unspecified Clinical Failure	11	Failure to Sense		
2	Extra Cardiac Stimulation	2	lation (not further defined)		
7	Oversensing				



Ventricular Placement

System Longevity Study Results	Qualitying Complications	39 Total	

Number of Leads Enrolled in Study	1,799	Failure to Capture	21	Impedance Out of Range	5
Cumulative Months of Follow-Up	89,287	Conductor Fracture	2	Unspecified Clinical Failure	2
Number of Leads Active in Study	394	Failure to Sense	3	Extra Cardiac Stimulation	2
		Insulation (not further defined)	1	Oversensing	3
100 —					
100					



4073 CapSure Sense

Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBF	US Returned Product Analysis
Registered US Implants	600	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 0
Estimated Active US Implants	400	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0 Other 0



4074 CapSure Sense

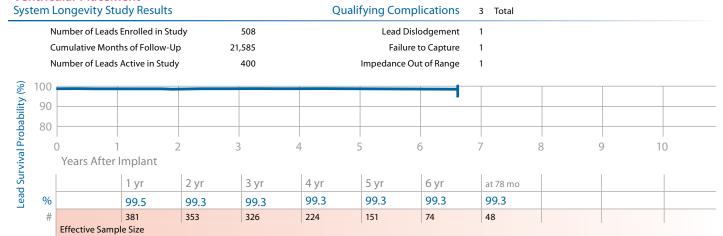
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBD	US Returned Product Analysis
Registered US Implants	75,800	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 1
Estimated Active US Implants	51,000	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 12
				Other 3

Atrial Placement



Ventricular Placement



4076 CapSureFix Novus

Product Characteristics

US Market Release	Feb-04	Serial Number Prefix	BBL	US Returned Product Analysis
Registered US Implants	290,200	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 12
Estimated Active US Implants	232,100	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 10
Advisories	None	Steroid	103	Other 18

Atrial Placement

System Longevity Study Results		Qualifying Complications	5 Total
Number of Leads Enrolled in Study	1,656	Lead Dislodgement	3
Cumulative Months of Follow-Up	37,245	Failure to Capture	1
Number of Leads Active in Study	1,404	Failure to Sense	1



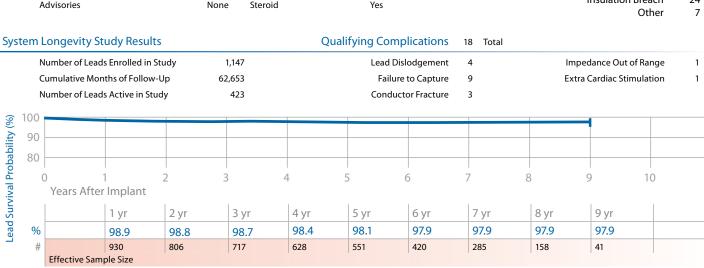
Ventricular Placement

sten	n Longev	rity Study Resu	JITS		Qi	ualifying Co	mplications	2 To	tal		
	Number o	of Leads Enrolled i	n Study	1,225		Fail	ure to Capture	2			
	Cumulativ	ve Months of Follo	ow-Up	32,496							
	Number o	of Leads Active in	Study	1,005							
10	00										
, ,	90										
	30										
C											
	0	1	2	3	4	5	6	7	8	9	10
	Years	After Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr	at 63 mo				
8	%	99.8	99.8	99.8	99.8	99.8	99.8				
	#	747	509	398	205	86	52				
	Effectiv	e Sample Size								,	,

4092 CapSure SP Novus

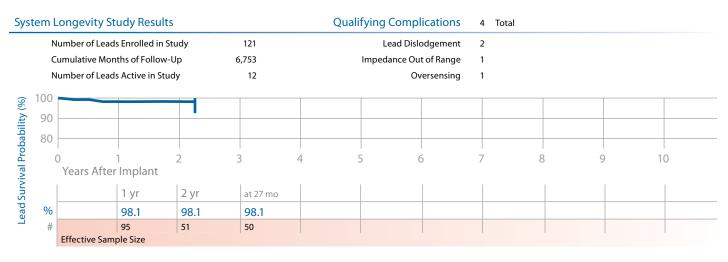
Product Characteristics

US Market Release	Sep-98	Serial Number Prefix	LEP	US Returned Product Analysis
Registered US Implants	163,200	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 6
Estimated Active US Implants	83,100	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 24 Other 7



4523 CapSure SP

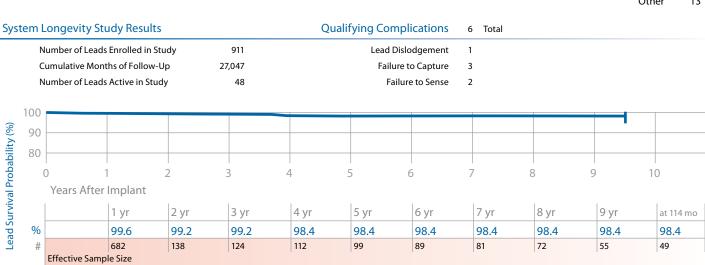
US Market Release	Aug-91	Serial Number Prefix	ZE	US Returned Product Analysis
Registered US Implants	11,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 1
Estimated Active US Implants	2,900	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 2
				Other 1



4524 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAR	US Returned Product Analysis
Registered US Implants	101,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 1
Estimated Active US Implants	29,200	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 42
				Other 13



4533 CapSure Z

ددر	Capsure	_		FIC	Juuct Charact	eristics				
	US Market Releas	se	Not US released		ial Number Prefix	LCB			US Returned Product An	alysis
	Registered US Im	plants	NA		e and/or Fixation	Trans	venous, Atrial-J,	Tines	Conductor Fracture	1
	Estimated Active	US Implants	NA	Pol	arity	Unipo	olar		Crimp/Weld/Bond	0
	Advisories		None	Ste	roid	Yes			Insulation Breach Other	0
stem	Longevity St	udy Results	i		Qı	ualifying Co	mplications	4 Total		
	Number of Leads	Enrolled in St	udy	206		Lead	Dislodgement	1	Oversensing	1
	Cumulative Mon	ths of Follow-	Up 10	,045		Fail	ure to Capture	1		
	Number of Leads	Active in Stud	dy	15		F	ailure to Sense	1		
10	0									
9	0									
8	0									
90 80	0	1	2 3	3	4	5	6	7 8	9 10	
	Years After	Implant								
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 75 mo		
9	6	100.0	99.4	98.4	97.2	97.2	97.2	97.2		
	#	176	96	88	78	66	52	49		
	Effective Samp	ole Size								

4558M Screw-In

Product Characteristics

	L	JS Market Releas	se	Nov-9	4 Seria	al Number Prefix	LDC			US Retu	ırned Produ	ct Ana	lysis
	R	Registered US Im	plants	20,00	0 Type	and/or Fixation	Transven	ous, Atrial-J, S	crew-in	Co	nductor Fract	ure	1
	Е	stimated Active	US Implants	4,80	0 Pola	rity	Bipolar				rimp/Weld/Bo		1
	Α	Advisories		Non	e Stere	oid	No			ı	nsulation Bre		19
											Ot	her	ı
Syst	em l	Longevity St	udy Results			Qua	alifying Comp	lications	12 Total				
	Ν	Number of Leads	s Enrolled in Stu	udy	539		Electrical Aba	ndonment	1	Insulation (not further defi	ned)	2
	C	Cumulative Mon	ths of Follow-L	Jp 1	8,189		Failure	to Capture	3	Impe	dance Out of R	ange	2
	N	Number of Leads	s Active in Stud	у	22		Failu	re to Sense	2		Overser	nsing	2
	100												
(%)	90										j		
ity (
abil	80											+	
rob		0	1	2	3	4	5	6	7	8	9	10	
al P		Years After	Implant										
Lead Survival Probability (%)			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr		
d S	%		99.3	99.3	99.3	99.3	99.3	97.2	95.9	95.9	91.1		
Lea	#		353	125	111	106	99	82	75	62	50		

5 3 6 8 9 10 Years After Implant 9 yr 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 97.2 95.9 95.9 91.1 % 99.3 99.3 99.3 99.3 99.3 353 125 111 82 75 50 106 99 62 Effective Sample Size

4568 CapSureFix

Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDD	US Returned Product Analysis
Registered US Implants	69,800	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture 3
Estimated Active US Implants	28,600	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 31 Other 6

System Longevity Study Results

Qualifying Complications 33 Total

Number of Leads Enrolled in Study	656	Lead Dislodgement	9	Impedance Out of Range	2
Cumulative Months of Follow-Up	30,531	Failure to Capture	18	Medical Judgment	1
Number of Leads Active in Study	183	Failure to Sense	3		
00					



4574 CapSure Sense

Product Characteristics

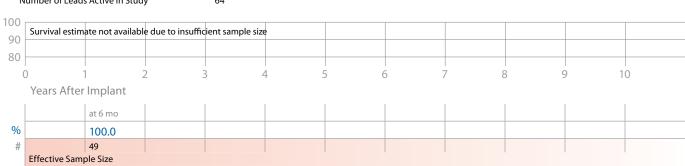
US Market Release	Jun-02	Serial Number Prefix	BBE	US Returned Product Analysis
Registered US Implants	49,000	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 4
Estimated Active US Implants	35,300	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 2
Advisories	Hone	Steroid	163	Other 0

System Longevity Study Results

Qualifying Complications 0 Total

71 Number of Leads Enrolled in Study 1,267 Cumulative Months of Follow-Up Number of Leads Active in Study 64





4592 CapSure SP Novus

Product Characteristics

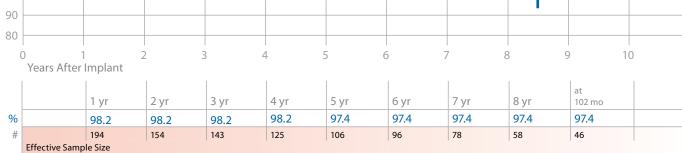
US Market Release	Oct-98	Serial Number Prefix	LER	US Returned Product Analysis
Registered US Implants	79,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 4
Estimated Active US Implants	43,100	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 7 Other 1
				Other

System Longevity Study Results

Qualifying Complications 5 Total

Number of Leads Enrolled in Study	283	Lead Dislodgement	2
Cumulative Months of Follow-Up	13,740	Failure to Capture	2
Number of Leads Active in Study	82	Failure to Sense	1





5023, 5023M CapSure SP

Product Characteristics

	US Mar	ket Relea	se			Nov-8	8	Serial Nu	ımber P	refix	SX	or LAS					US Re	turned	d Prod	uct Ar	alysis
	Registe	red US In	nplants			9,90	0	Type and	d/or Fixa	ation	Tr	ansvenou	ıs, Vent., T	ines			(Conduc	tor Fra	cture	6
	Estima	ted Active	US Imp	olants		2,40	0	Polarity			Ur	nipolar							/Weld/		C
	Adviso	ries				Non	e	Steroid			Ye	S						Insula	ation B		1
																			(Other	0
yster	n Long	evity St	udy Re	esults						Qua	lifying	Compli	cations	18	Total						
	Numbe	r of Lead	s Enrolle	ed in Stu	ıdy		1,354					Failure to	Capture	9			Ext	ra Cardia	ac Stimu	ılation	4
	Cumula	ative Mon	ths of F	ollow-L	lр	7	7,564				C	onductor	Fracture	3							
	Numbe	r of Lead	s Active	in Stud	у		402				Impeda	nce Out	of Range	2							
1 0	00																				
§ 10																					
ji ji	90																				_
bak 8	30																				
Pro	0	1	2	3	4	5	6	7	8	9	10	1 12	2 13	14	15	16	17	18	19	20	21
ival	Yea	rs After	Impla	nt																	
Lead Survival Probability (%)													at								
5 pe		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	138 mo								
Le	%	99.7	99.7	99.5	99.4	99.4	98.9	97.4	97.4	97.0	96.4	96.4	96.4								

68

46

5024, 5024M CapSure SP

1,077 818

Effective Sample Size

Product Characteristics

307

399

#		0,120	2,101	1,990	1,000	1,700	1,019	1,110	1,107	7,0	, 0,	300	132	303	221	131	100	70				
- 11		6,128	2,101	1,996	1,893	1,788	1,619	1,410	1,187	978	767	580	432	303	221	134	88	48				
%		99.6	99.5	99.3	99.2	99.1	99.0	98.8	98.6	98.4	98.3	98.2	98.2	97.9	97.9	96.4	96.4	94.8				
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr				
	Years	s After	Impla	nt																		
	0	1	2	3	4	5 (5	7	8	9 1	0 1	1 1	2 1.	3 1	4 1:	5 16	5 17	7 18	3 1	9 2	20	21
80																					-	
90																						
100																						
										Insula	tion (not		defined tion (ESC	•	5 1						OTH	
											. ,		to Sens		2				C	Oversen	_	
N	lumber	of Leads	Active	in Study	у		481				Co	nducto	r Fractur	re	3			Extra C	ardiac	Stimula	tion	
C	umulati	ive Mon	ths of F	ollow-U	р	328	,524				F	ailure to	Captur	re 2	8		ι	Inspecif	ied Cli	nical Fai	lure	
N	lumber	of Lead	Enrolle	ed in Stu	ıdy	8	3,154				Lea	ad Dislo	dgemer	nt	5			Imped	ance O	ut of Ra	nge	
tem l	_onge	vity St	udy Re	esults						Qualit	fying C	ompli	cation	IS 5	7 Tota	ıl						
Α	dvisorie	es				None	e S	teroid			Yes	5						In	sulatio	on Brea Oth		3
		d Active	US Imp	olants		51,900		Polarity				Bipolar			Crimp/Weld/Bond Insulation Breach							
R	egistere	ed US Im	plants			201,600) T	ype and	or Fixat	ion	Tra	nsveno	us, Vent	., Tines				Con	ductor	Fractu	re	
U	15 Marke	et Relea:	se			Mar-90	5	erial Nu	mber Pre	etix	SY	or LAT					US	Return	າed Pi	roduc	t Ana	alys

5033 CapSure Z

Lead Survival Probability (%)

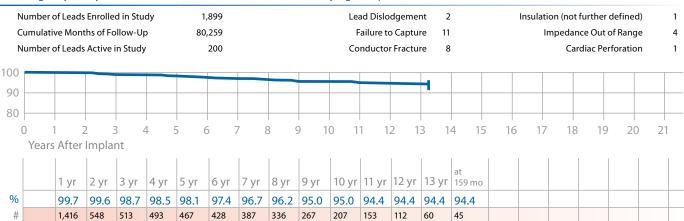
Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDK	US Returned Product Analysis
Registered US Implants	2,400	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 1
Estimated Active US Implants	600	Polarity	Unipolar	Crimp/Weld/Bond 0 Insulation Breach 0
Advisories	None	Steroid	Yes	Other 3

System Longevity Study Results

Effective Sample Size

Qualifying Complications 27 Total



5034 CapSure Z

Product Characteristics

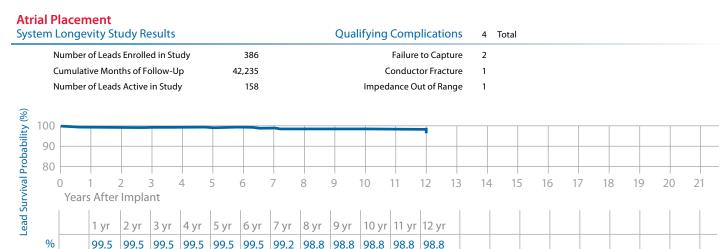
248

210

156

98

US Market Release	Feb-96	Serial Number Prefix	LDF	US Returned Product Analysis
Registered US Implants	56,100	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 14
Estimated Active US Implants	15,200	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 15
Advisories	None	Siciola	163	Other 13



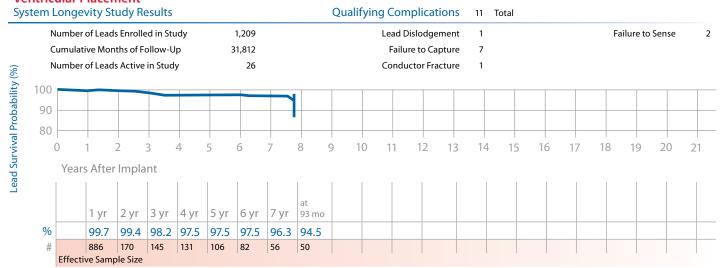
Ventricular Placement

383

Effective Sample Size

382

379



Number of Leads Active in Study

5054 CapSure Z Novus

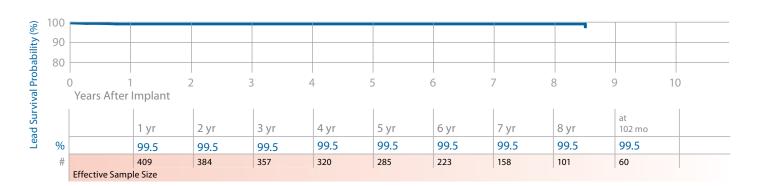
Product Characteristics

207

US Market Release	Jun-98	Serial Number Prefix	LEH	US Returned Product Analysis
Registered US Implants	90,500	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 5
Estimated Active US Implants	43,900	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 13
				Other 7

Atrial Placement

L	ongevity Study Results		Qualifying Complications	2	Total
	Number of Leads Enrolled in Study	424	Lead Dislodgement	1	
	Cumulative Months of Follow-Up	30,389	Failure to Capture	1	



Ventricular Placement

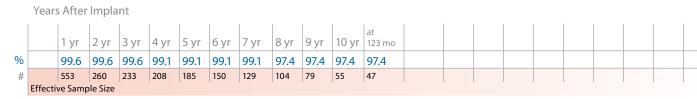
Syster	n L	Longevity Stu	ıdy Results			Qι	ualifying Cor	nplications	9 Total				
	Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study		o 3	967 33,513 146			Dislodgement ure to Capture ailure to Sense	1 Impedance Out of R 6		Range			
10	00									•			
	30												
obabil	(0 1 Years After	Implant	2	3	4	5	6	7	8	9	10	
Survival Probability (%)			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 105 mo		
Sur	%		99.5	99.4	99.4	99.0	99.0	97.6	97.6	97.6	97.6		
Lead	#		656	341	294	264	230	171	135	84	48		
Le		Effective Samp	le Size										

5068 CapSureFix

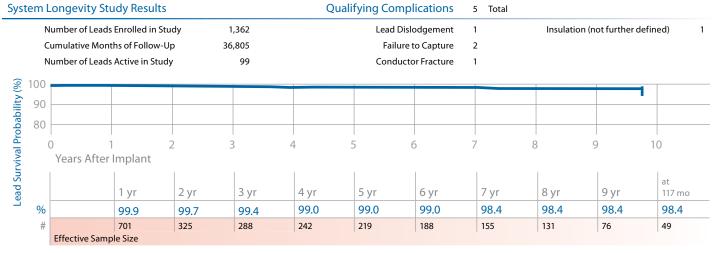
Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDJ	US Returned Product Analysis
Registered US Implants	103,200	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 35
Estimated Active US Implants	36,300	Polarity	Bipolar	Crimp/Weld/Bond 3
Advisories	None	Steroid	Yes	Insulation Breach 50 Other 16
al Diacomont				

Νι	umber	of Lead	s Enroll	ed in Stı	udy		968					Lead [islodg	ement	1			lm	pedanc	e Out o	f Range	
Cumulative Months of Follow-Up 30,053		Failure to Capture			2			Oversensing														
Νι	umber	of Lead	s Active	in Stud	ly		49			Insul	ation (not fur	ther de	efined)	1							
00								-			_											
90											1											_
80																						_
0)	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
			Impla																			

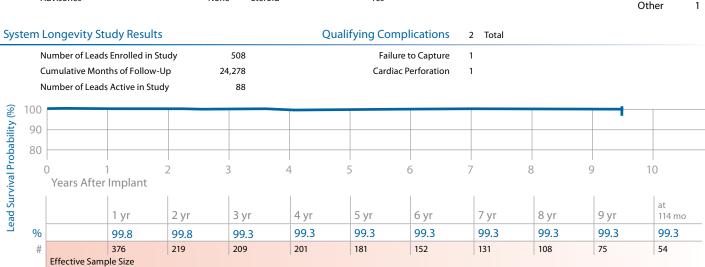


Ventricular Placement



5072 SureFix

US Market Release	Jun-98	Serial Number Prefix	LEM	US Returned Product Analysis
Registered US Implants	9,300	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 2
Estimated Active US Implants	4,400	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 5 Other 1



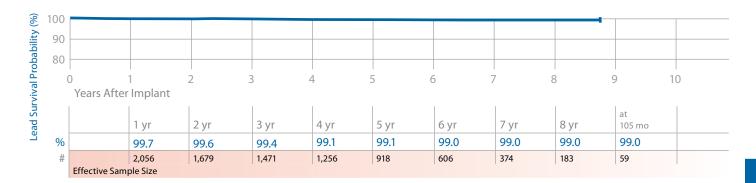
5076 CapSureFix Novus

Product Characteristics

US Market Release	Aug-00	Serial Number Prefix	PJN	US Returned Product Analysis
Registered US Implants	1,232,100	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture 219
Estimated Active US Implants	831,200	Polarity	Bipolar	Crimp/Weld/Bond C
Advisories	None	Steroid	Yes	Insulation Breach 217 Other 146

Atrial Placement

		17 Total	Qualifying Complications		System Longevity Study Results			
2	Impedance Out of Range	4	Lead Dislodgement	2,725	Number of Leads Enrolled in Study			
2	Extra Cardiac Stimulation	5	Failure to Capture	121,544	Cumulative Months of Follow-Up			
1	Oversensing	1	Conductor Fracture	995	Number of Leads Active in Study			
1	Cardiac Perforation	1	Insulation (not further defined)					



Ventricular Placement

System Longevity Study Results **Qualifying Complications** 10 Total Number of Leads Enrolled in Study 2 1,536 Lead Dislodgement Failure to Sense Cumulative Months of Follow-Up 61,827 Failure to Capture 3 Impedance Out of Range 2 Number of Leads Active in Study 443 Conductor Fracture Cardiac Perforation Lead Survival Probability (%) 100 90 80 3 5 7 8 9 4 6 10 Years After Implant 5 yr 1 yr 2 yr 3 yr 4 yr 6 yr 7 yr 8 yr 99 mo % 99.6 99.4 99.3 99.0 99.0 99.0 99.0 99.0 99.0

459

317

192

72

51

1,081

Effective Sample Size

856

725

594

5092 CapSure SP Novus

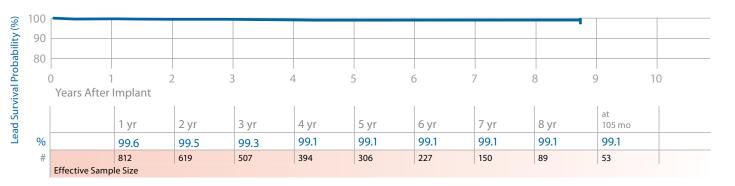
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	US Returned Product Analysis
Registered US Implants	121,400	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 6
Estimated Active US Implants	60,600	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 32
Advisories	Hone	Steroid	163	Other 12

System Longevity Study Results

Qualifying Complications 7 Total

Number of Leads Enrolled in Study	1,172	Lead Dislodgement	5
Cumulative Months of Follow-Up	45,286	Failure to Capture	1
Number of Leads Active in Study	190	Extra Cardiac Stimulation	1



5524, 5524M CapSure SP

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	XV or LAV	US Returned Product Analysis
Registered US Implants	60,600	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 10
Estimated Active US Implants	19,200	Polarity	Bipolar	Crimp/Weld/Bond 2
Advisories	None	Steroid	Yes	Insulation Breach 12
				Other 8

System Longevity Study Results

Qualifying Complications 38 Total

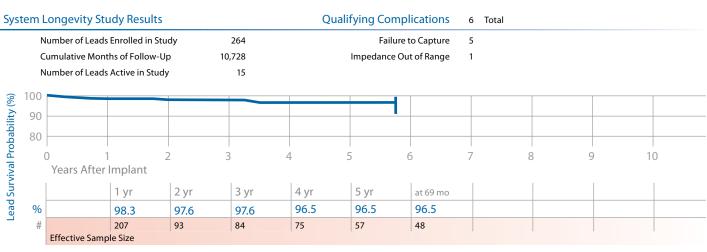
2	Insulation (not further defined)	3	Lead Dislodgement	4,497	Number of Leads Enrolled in Study
1	Impedance Out of Range	22	Failure to Capture	201,070	Cumulative Months of Follow-Up
4	Oversensing	1	Conductor Fracture	426	Number of Leads Active in Study
1	ОТН	4	Failure to Sense		



5534 CapSure Z

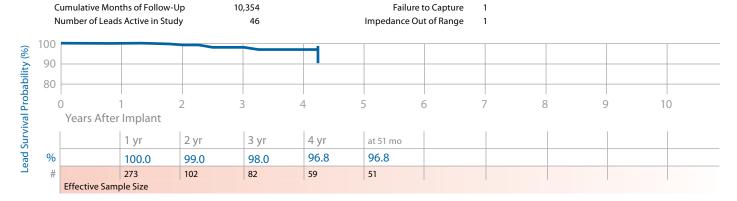
Product Characteristics

Feb-96	Serial Number Prefix	LDG	US Returned Product Analysis
26,100	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 3
lants 8,300	Polarity	Bipolar	Crimp/Weld/Bond 0
None	Steroid	Yes	Insulation Breach 5 Other 5
	26,100 lants 8,300	26,100 Type and/or Fixation lants 8,300 Polarity	26,100 Type and/or Fixation Transvenous, Atrial-J, Tines lants 8,300 Polarity Bipolar



5554 CapSure Z Novus

	US Market Release	Jun-98	Serial Number Pref	ix LEJ		US Returned Product Ana	alysis
	Registered US Implants	58,300	Type and/or Fixatio	n Transvenous, Atrial-J,	Tines	Conductor Fracture	6
	Estimated Active US Implants	31,000	Polarity	Bipolar		Crimp/Weld/Bond	0
	Advisories	None	Steroid	Yes		Insulation Breach Other	11 4
Syste	m Longevity Study Results		(Qualifying Complications	4 Total		
	Number of Leads Enrolled in Study	34	4	Lead Dislodgement	1	Oversensing	1



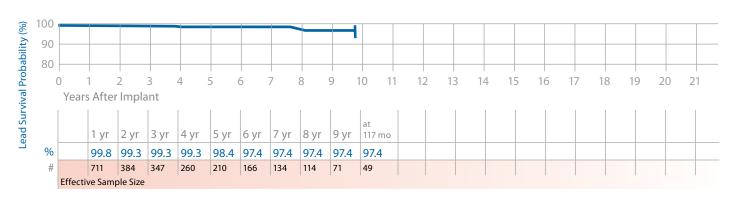
5568 CapSureFix

Product Characteristics

	US Market Release	Jan-97	Serial Number Prefix	LDN	US Returned Product Analy	ysis
	Registered US Implants	80,400	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture	6
	Estimated Active US Implants	49,100	Polarity	Bipolar	Crimp/Weld/Bond	0
	Advisories	None	Steroid	Yes	Insulation Breach Other	13 17
er	n Longevity Study Results		Qualifyi	ng Complications 11 Total		

System Longevity Study Results

Number of Leads Enrolled in Study	1,052	Lead Dislodgement	1	Failure to Sense	2
Cumulative Months of Follow-Up	37,005	Failure to Capture	5	Oversensing	1
Number of Leads Active in Study	169	Conductor Fracture	2		



5592 CapSure SP Novus

	US Market Relea	ise	Jun-98	Serial Nu	mber Prefix	LEU			US R	Returned Product An	alysis
	Registered US In	mplants	30,800	Type and	or Fixation	Transven	ous, Atrial-J, T	ines		Conductor Fracture	2
	Estimated Activ	e US Implants	18,700	Polarity		Bipolar				Crimp/Weld/Bond	0
	Advisories		None	Steroid		Yes				Insulation Breach Other	3 0
Syster	n Longevity S	tudy Results			Qua	lifying Comp	olications	4 Total			
	Number of Lead	ls Enrolled in St	udy 6	71		Lead Dis	lodgement	2			
	Cumulative Mo	nths of Follow-l	Jp 29,0	20		Failure	to Capture	2			
	Number of Lead	ls Active in Stud	dy 1	58							
© 10)()										
9											
bilit	90										
oba	30										
Pre	0	1	2 3		4	5	6	7	8	9 10	
/iva	Years Afte	r Implant									
Sur											
ad		1 yr	2 yr 3	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr		
Le	%	99.7		99.3	99.3	99.3	99.3	99.3	99.3		
	#	515		340	268	208	143	84	48		
	Effective Sam	1	1.22		1	1	1	1			

5594 CapSure SP Novus

Product Characteristics

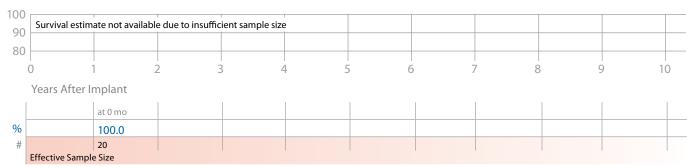
US Market Release	Jun-01	Serial Number Prefix	LFD	US Returned Product Analysis
Registered US Implants	13,100	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 4
Estimated Active US Implants	9,300	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 3 Other 0

System Longevity Study Results

Qualifying Complications

Number of Leads Enrolled in Study 20 1,396 Cumulative Months of Follow-Up Number of Leads Active in Study 13





6940 CapSureFix

	US Market Relea	ise	Oct-98	Serial Numb	er Prefix	TCP			US Re	eturned Prod	luct Ana	lysis
	Registered US Ir	mplants	25,500	Type and/or	Fixation	Transven	ous, A or V, Sci	rew-in		Conductor Fra	cture	10
	Estimated Activ	e US Implants	8,900	Polarity		Bipolar				Crimp/Weld/		0
	Advisories		None	Steroid		Yes				Insulation B	reacn Other	14 4
Syster	n Longevity Si Number of Leac Cumulative Mor Number of Leac	ls Enrolled in Stanta	udy 81 Jp 40,83	3	Qualify	Conduct	lodgement or Fracture re to Sense	11 Total 1		Overs	ensing	6
% 10												
billit	90											
roba	30											
Survival Probability (%)	0 Years Afte	1 r Implant	2 3	4	5		6	7	8	9	10	
Sur		1 yr	2 yr 3 y	/r 4	yr 5	yr	6 yr	7 yr	8 yr	9 yr	10 yr	
Lead	%	99.7	99.6 98	.3 98	8.0 98	8.0	98.0	98.0	98.0	98.0	98.0	
_	#	641	506 413	33	31 27	77	237	196	148	112	54	
	Effective Sam	ple Size										

(95% Confidence Interval)
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		20 yr														
		18 yr														
		16 yr														
		14 yr			95.7 +1.7/-2.7 at 156 mo.				90.4 +3.1/-4.4 at 153 mo.							
	. ,	12 yr			95.7				91.5	93.0 +2.9/-4.8 at 141 mo.						
		10 yr			96.4 +1.3/-2.2	98.0 +1.6/-9.1 at 108 mo.	93.3 +3.4/-6.7 at 105 mo.		94.3 +1.5/-2.1	94.6 +1.8/-2.6						97.9 +0.8/-1.3 at 108 mo.
		8 yr			96.8	99.8	94.8		95.7	96.0						97.9
		7 yr			97.0	99.8	96.0		96.8	96.6		99.1 +0.7/-2.8 at 75 mo.	99.3 +0.5/-1.6 at 78 mo.			97.9
		6 yr			98.0	99.8	96.0	98.1	96.9	97.3	100.0 at 69 mo.	99.1	99.3	99.6 +0.3/-0.5 at 63 mo.	99.8 +0.2/-0.5 at 63 mo.	97.9
		5 yr	99.7 +0.3/-1.5	100.0	98.4	99.8	96.8	98.1	97.2 +0.8/-1	97.8	100.0	99.1	99.3	99.6	99.8	98.1
lity (%)		4 yr	99.7	100.0	98.4	99.8	97.5	98.1	97.8	98.2	100.0	99.1	99.3	99.6	99.8	98.4
Probabi	lant	3 yr	99.7	100.0	98.6	99.8	98.1	98.1	98.1	98.7	100.0	99.1	99.3	99.6	99.8	98.7
Device Survival Probability (%)	Years After Implant	2 yr	99.7	100.0	99.2	99.8	99.4	98.1	98.7	98.7	100.0	99.1	99.3	99.6	99.8 +0.2/-0.5	98.8
Device	Years A	1 yr	99.7 +0.3/-1.5	100.0	99.8	99.9	99.4	98.1	98.9	99.3	100.0	99.1	99.5	99.7 +0.2/-0.4	99.8	98.9
Months o in Study			9,481	8,033	68,226	30,110	22,467	10,140	122,006	89,287	6,397	12,202	21,585	37,245	32,496	62,653
su	ying licatio	JilsuQ IqmoD	-	4	21	4	10	∞	99	39	0	2	m	5	7	18
γbu32 ni s	evitoA	reads	330	195	278	19	36	49	464	394	78	163	400	1,404	1,005	423
рə	Enroll	reads	418	279	1,158	1,215	539	171	2,413	1,799	102	213	208	1,656	1,225	1,147
əseələ	rket B	₆ M 2U	Aug-05	Aug-05	Aug-91	Oct-91	Not US released	Jan-97	Mar-96	Mar-96	Jun-02	Jun-02	Jun-02	Feb-04	Feb-04	Sep-98
	oer	Chaml	Atrial	Vent	Vent	Vent	Vent	Atrial	Atrial	Vent	Vent	Atrial	Vent	Atrial	Vent	Vent
	,	(lime7	SelectSecure	SelectSecure	CapSure SP	CapSure SP	CapSure Z	CapSureFix	CapSureFix	CapSureFix	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus
		leboM dmuM	3830	3830	4023	4024	4033	4067	4068	4068	4073	4074	4074	4076	4076	4092

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Cirig		Cut	45	contini	ueu											
		20 yr														
		18 yr									94.8 +2.6/-5.2 at 204 mo.					
		16 yr									96.4 +1.5/-2.5					
		14 yr									97.9	94.4 +1.9/-2.9 at 159 mo.				
		12 yr								96.4 +1.5/-2.7 at 138 mo.	98.2 +0.5/-0.8	9 4.4 +1.9/-2.9	98.8			
		10 yr		98.4 +1.1/-3.3 at 114 mo.		91.1 +4.6/-9.3 at 108 mo.	93.3 +2.1/-3 at 99 mo.		97.4 +1.5/-3.9 at 102 mo.	96.4 +1.5/-2.7	98.3	95.0	98.8 +0.8/-1.9		99.5 +0.4/-1.4 at 102 mo.	97.6 +1.3/-2.8 at 105 mo.
		8 yr		98.4		95.9 +2.5/-6.3	93.3 +2.1/-3		97.4 +1.5/-3.9	97.4	98.6	96.2	98.8	94.5 +3.1/-7.3 at 93 mo.	99.5	97.6
		7 yr		98.4	97.2 +1.9/-6 at 75 mo.	95.9	93.3 +2.1/-3		97.4 +1.5/-3.9	97.4	98.8	96.7	99.2 +0.5/-1.8	96.3 +2.1/-5	99.5	97.6 +1.3/-2.8
		6 yr		98.4 +1.1/-3.3	97.2 +1.9/-6	97.2	93.9 +1.9/-2.7		97.4 +1.5/-3.9	98.9 +0.5/-1.1	99.0	97.4 +1.1/-1.7	99.5	97.5 +1.4/-3.5	99.5	97.6 +1.3/-2.8
		5 yr		98.4 +1.1/-3.3	97.2 +1.9/-6	99.3	93.9		97.4 +1.5/-3.9	99.4	99.1	98.1 +0.8/-1.5	99.5	97.5	99.5	99.0
ity (%)		4 yr		98.4 +1.1/-3.3	97.2 +1.9/-6	99.3	94.6 +1.7/-2.5		98.2 +1.1/-3	99.4	99.2	98.5	99.5	97.5	99.5	99.0 +0.0.6/-1.4
Probabil	ant	3 yr	98.1 +1.4/-5.3 at 27 mo.	99.2 +0.5/-1.2	98.4 +1.2/-5.1	99.3	95.2 +1.5/-2.3		98.2 +1.1/-3	99.5	99.3	98.7	99.5	98.2 +1.1/-2.9	99.5	99.4 +0.3/-0.9
Device Survival Probability (%)	Years After Implant	2 yr	98.1	99.2	99.4	99.3	96.4		98.2	99.7	99.5	99.6	99.5	99.4	99.5	99.4
Device	Years A	1 yr	98.1	99.6	100.0	99.3 +0.5/-1.4	9 6.8 +1.2/-1.8	100.0 at 6 mo.	98.2 +1.1/-3	99.7 +0.2/-0.5	99.6	99.7 +0.2/-0.4	99.5	99.7 +0.2/-0.6	99.5	99.5
Months in Study	l əvital qU-wo	lumu2 llo1 ìo	6,753	27,047	10,045	18,189	30,531	1,267	13,740	77,564	328,524	80,259	42,235	31,812	30,389	33,513
su		TilsuQ qmoD	4	9	4	12	33	0	rv	18	57	27	4	=	2	6
in Study ا	evitoA	resqs	12	48	15	22	183	64	82	402	481	200	158	56	207	146
pə	llorna	reads	121	911	506	539	959	71	283	1,354	8,154	1,899	386	1,209	424	296
əseələ	rket Re	_B M 2U	Aug-91	Oct-91	Not US released	Nov-94	Jan-97	Jun-02	Oct-98	Nov-88	Mar-90	Feb-96	Feb-96	Feb-96	Jun-98	Jun-98
	per	Chaml	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Vent	Vent	Vent	Atrial	Vent	Atrial	Vent
	,	Family	CapSure SP	CapSure SP	CapSure Z	Screw-In	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure SP	CapSure Z	CapSure Z	CapSure Z	CapSure Z Novus	CapSure Z Novus
		laboM dmuM	4523	4524	4533	4558M	4568	4574	4592	5023, 5023M	5024, 5024M	5033	5034	5034	5054	5054

		20 yr													
		18 yr													
		16 yr							96.9 +1/-1.3 at 183 mo.						
		14 yr							96.9						
		12 yr	97.4 +1.6/-4.3 at 123 mo.						96.9						
		10 yr	97.4 +1.6/-4.3	98.4 +1/-2.7 at 117 mo.	99.3 +0.5/-2.2 at 114 mo.	99.0 +0.4/-0.6 at 105 mo.	99.0 +0.5/-0.9 at 99 mo.	99.1 +0.5/-1.2 at 105 mo.	97.1 +0.9/-1.2			97.4 +1.4/-2.9 at 117 mo.			98.0
		8 yr	97.4 +1.6/-4.3	98.4 +1/-2.7	99.3 +0.5/-2.2	99.0	99.0	99.1 +0.5/-1.2	97.9			97.4 +1.4/-2.9	99.3		98.0
		7 yr	99.1 +0.6/-1.9	98.4	99.3 +0.5/-2.2	99.0	99.0	99.1 +0.5/-1.2	98.5 +0.5/-0.8			97.4 +1.4/-2.9	99.3		98.0
		6 yr	99.1 +0.6/-1.9	99.0	99.3 +0.5/-2.2	99.0	99.0	99.1 +0.5/-1.2	98.8 +0.4/-0.7	96.5 +2/-4.9 at 69 mo.		97.4	99.3		98.0
		5 yr	99.1	99.0	99.3 +0.5/-2.2	99.1	99.0	99.1 +0.5/-1.2	98.9	96.5	96.8 +2.1/-5.9 at 51 mo.	98.4 +0.9/-2	99.3		98.0
lity (%)		4 yr	99.1 +0.6/-1.9	99.0	99.3	99.1	99.0	99.1 +0.5/-1.2	99 +0.4/-0.6	96.5	9 6.8 +2.1/-5.9	99.3	99.3		98.0
Probabil	ant	3 yr	99.6	99.4	99.3 +0.5/-2.2	99.4 +0.3/-0.4	99.3	99.3	99.3	97.6	98.0	99.3	99.3		98.3 +0.8/-1.6
Device Survival Probability (%)	Years After Implant	2 yr	99.6	99.7 +0.2/-0.9	99.8	99.6	99.4 +0.3/-0.6	99.5	99.7 +0.2/-0.2	97.6	99.0	99.3	99.3		99.6
Device	Years A	1 yr	99.6	99.9	99.8 +0.2/-1.4	99.7 +0.1/-0.4	99.6 +0.2/-0.5	99.6 +0.2/-0.7	99.8	98.3 +1.1/-2.7	100.0	99.8	99.7 +0.2/-1.1	100.0 at 0 mo.	99.7 +0.2/-0.8
Months o in Study			30,053	36,805	24,278	121,544	61,827	45,286	201,070	10,728	10,354	37,005	29,020	1,396	40,833
su		Qualif Compl	7	5	2	17	10	7	38	9	4	Ξ	4	0	Ξ
γbut2 ni e			49	66	88	995	443	190	426	15	46	169	158	13	116
pə	Ilorn∃	reads	896	1,362	208	2,725	1,536	1,172	4,497	264	344	1,052	671	20	816
əseələ	rket R	₆ M 2U	Jan-97	Jan-97	Jun-98	Aug-00	Aug-00	Jun-98	Mar-90	Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	Oct-98
) GE	Chaml	Atrial	Vent	Atrial	Atrial	Vent	Vent	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
	,	Kamily	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus	CapSure SP	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	CapSureFix
		qwnN qwnM	5068	5068	5072	5076	5076	5092	5524, 5524M	5534	5554	5568	5592	5594	6940

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
3830	SelectSecure	Aug-05	17,000	14,200	2	0	5	3
4023	CapSure SP	Aug-91	41,200	8,900	17	0	3	8
4024	CapSure SP	Oct-91	222,300	51,100	28	0	136	41
4033	CapSure Z	Not US released	NA	NA	0	0	0	0
4067	CapSureFix	Jan-97	1,000	300	1	0	0	1
4068	CapSureFix	Mar-96	124,200	38,200	39	0	104	16
4073	CapSure Sense	Jun-02	600	400	0	0	0	0
4074	CapSure Sense	Jun-02	75,800	51,000	1	1	12	3
4076	CapSureFix Novus	Feb-04	290,200	232,100	12	1	10	18
4092	CapSure SP Novus	Sep-98	163,200	83,100	6	0	24	7
4523	CapSure SP	Aug-91	11,200	2,900	1	0	2	1
4524	CapSure SP	Oct-91	101,800	29,200	1	0	42	13
4533	CapSure Z	Not US released	NA	NA	1	0	0	0
4558M	Screw-in	Nov-94	20,000	4,800	1	1	19	1
4568	CapSureFix	Jan-97	69,800	27,600	3	0	31	6
4574	CapSure Sense	Jun-02	49,000	35,300	4	0	2	0
4592	CapSure SP Novus	Oct-98	79,800	43,100	4	0	7	1
5023, 5023M	CapSure SP	Nov-88	9,900	2,400	6	0	1	0
5024, 5024M	CapSure SP	Mar-90	201,600	51,900	50	10	49	39
5033	CapSure Z	Feb-96	2,400	600	1	0	0	3
5034	CapSure Z	Feb-96	56,100	15,200	14	1	15	13
5054	CapSure Z Novus	Jun-98	90,500	43,900	5	1	13	7
5068	CapSureFix	Jan-97	103,200	36,300	35	3	50	16
5072	SureFix	Jun-98	9,300	4,400	2	0	5	1
5076	CapSureFix Novus	Aug-00	1,232,100	831,200	219	0	217	146
5092	CapSure SP Novus	Jun-98	121,400	62,000	6	0	32	12
5524, 5524M	CapSure SP	Mar-90	60,600	19,200	10	2	12	8
5534	CapSure Z	Feb-96	26,100	8,300	3	0	5	5
5554	CapSure Z Novus	Jun-98	58,300	31,000	6	0	11	4
5568	CapSureFix	Jan-97	80,400	49,100	6	0	13	17
5592	CapSure SP Novus	Jun-98	30,800	18,700	2	0	3	0
5594	CapSure SP Novus	Jun-01	13,100	9,300	4	0	3	0
6940	CapSureFix	Oct-98	25,500	8,900	10	0	14	4

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
3830	SelectSecure	17,000	6	0	12	7	2	1	1	0	0	0
4023	CapSure SP	41,200	0	1	3	3	1	0	3	0	1	0
4024	CapSure SP	222,300	15	11	51	107	0	15	1	8	2	16
4067	CapSure Fix	1,000	1	0	0	0	0	0	0	0	0	0
4068	CapSure Fix	124,200	5	3	30	28	0	5	1	2	1	1
4074	CapSure Sense	75,800	4	0	7	19	0	1	0	3	0	0
4076	CapSure Fix Novus	290,200	18	2	40	29	2	7	1	8	2	1
4092	CapSure SP Novus	163,200	1	5	12	21	0	0	0	2	0	1
4523	CapSure SP	11,200	0	0	2	2	0	1	0	0	0	0
4524	CapSure SP	101,800	0	2	23	16	0	5	2	1	0	8
4558M	Screw-in	20,000	2	0	4	3	0	1	0	2	0	0
4568	CapSure Fix	69,800	3	1	4	6	0	1	0	2	0	1
4574	CapSure Sense	49,000	0	0	13	4	1	4	0	0	0	3
4592	CapSure SP Novus	79,800	0	0	12	7	0	2	0	0	0	2
5023, 5023M	CapSure SP	9,900	0	1	2	0	1	0	0	0	0	1
5024, 5024M	CapSure SP	201,600	11	7	26	48	1	10	5	3	3	9
5033	CapSure Z	2,400	0	0	1	0	0	0	0	0	0	0
5034	CapSure Z	56,100	4	6	15	31	0	3	2	0	0	10
5054	CapSure Z Novus	90,500	1	1	5	19	0	2	2	0	0	9
5068	CapSure Fix	103,200	15	3	21	32	0	5	1	2	0	2
5072	SureFix	9,300	0	0	2	1	0	0	0	0	0	0
5076	CapSure Fix Novus	1,232,100	78	10	223	140	14	29	6	18	9	17
5092	CapSure SP Novus	121,400	4	1	22	24	0	7	2	2	1	7
5524, 5524M	CapSure SP	60,600	1	4	15	11	0	9	2	0	0	8
5534	CapSure Z	26,100	0	0	4	3	0	1	0	0	2	4
5554	CapSure Z Novus	58,300	0	1	18	15	0	1	0	0	0	3
5568	CapSure Fix	80,400	3	0	16	12	1	3	1	1	1	1
5592	CapSure SP Novus	30,800	0	0	15	2	0	0	0	0	0	1
5594	CapSure SP Novus	13,100	0	0	0	0	0	0	0	0	0	2
6940	CapSure Fix	25,500	0	1	5	1	0	0	0	0	0	1

Report Cutoff Date: July 31, 2010

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5023, 5023M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Porous Platinized/ Steroid	5 mm (5023) IS-1 UNI (5023M)
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
				MDOCN	Davassa Dlatinianal/	2.2 mans I am Durafila (5524)
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 BI (5524M)

continued

Data as of July 31, 2010

Reference Chart continued

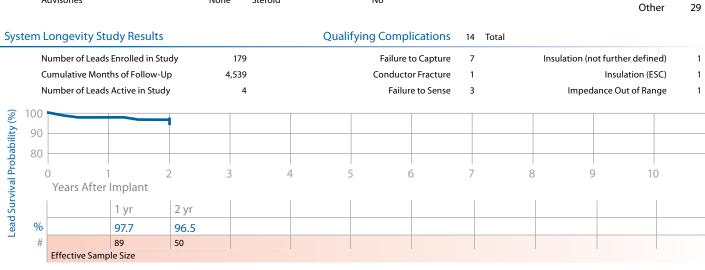
Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6940	CapSureFix	Transvenous A or V Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

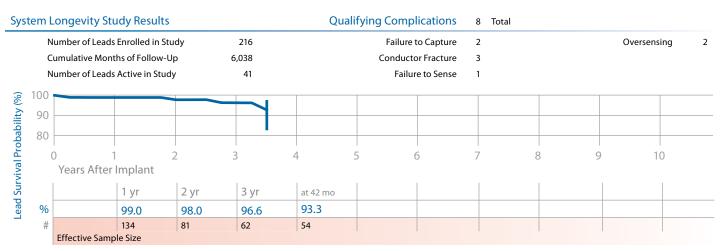
Product Characteristics

US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	US Returned Product Analysis
Registered US Implants	23,200	Type and/or Fixation	Myocardial Stab-in, V or A, Peds	Conductor Fracture 57
Estimated Active US Implants	3,100	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	No	Insulation Breach 39 Other 29



4965 CapSure Epi

US Market Release	Sep-96	Serial Number Prefix	LBT	US Returned Product Analysis
Registered US Implants	20,000	Type and/or Fixation	Epicardial Suture-On V or A	Conductor Fracture 114
Estimated Active US Implants	9,700	Polarity	Unipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 28 Other 2



Epi/Myocardial Pacing Leads continued

4968 CapSure Epi

Product Characteristics

US Market Release	Sep-99	Serial Number Prefix	LEN	US Returned Product Analysis
Registered US Implants	20,300	Type and/or Fixation	Epicardial Suture-On V or A	Conductor Fracture 12
Estimated Active US Implants	13,100	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 6
Advisories	Hone	Steroid	163	Other 0

System Longevity Study Results

Qualifying Complications 24 Total





5071 Screw-in

Product Characteristics

	US Market Relea	se	Dec-92	Serial Number Pre	efix l	_AQ			US Retur	ned Product Ana	alysis
	Registered US In	nplants	38,900	Type and/or Fixat	ion I	Myocardial Screw-in V	/ent.		Con	ductor Fracture	7
	Estimated Active	e US Implants	14,900	Polarity	ı	Jnipolar				imp/Weld/Bond	0
	Advisories		None	Steroid	1	No				sulation Breach Other	1 5
Syste	em Longevity St	udy Results			Qualifying	Complications	12	Total			
	Number of Lead	s Enrolled in Stu	dy 250			Failure to Capture	10				
	Cumulative Mor	ths of Follow-Up	5,749			Oversensing	2				
	Number of Lead	s Active in Study	43								
% 1	00										
lity (90										
babi	80										
Pro	0	1 3	2 3	4	5	6	7	8	9	10	
Survival Probability (%)	Years After	'Implant	. 3	7	5	0	/	0	J	10	
Surv		1 yr	2 yr								
Lead	%	96.8	93.9								
_	#	124	50								

Effective Sample Size

Lead Survival Summary (95% Confidence Interval)

				ı	ı	
		16 yr				
		14 yr				
		12 yr				
		10 yr			89.7 +4.2/-6.8 at 105 mo.	
		8 yr			93.9 +2.2/-3.4	
		7 yr			93.9	
		6 yr			93.9	
	ity (%)				94.5	
ity (%)				93.3 +3.9/-8.5 at 42 mo.	95.8	
Probabil	ant	3 yr		96.6	96.9	
Device Survival Probability (%)	fears After Implant	2 yr	96.5	98.0	97.9	93.9
Device	Years A	1 yr	97.7 +1.6/-4.8	99.0 +0.7/-3.1	99.8 +0.2/-1	96.8
wonths suj			4,539	6,038	30,046	5,749
	US Market Release Leads Enrolled Leads Active in Stud Complications Complative Months		41	∞	24 3	12
ipn3S ni s			4	14	385	43
pə			179	216	652	250
əseələ			Oct-81	Sep-96	Sep-99	Dec-92
Հլլա		(lime7	Spectraflex	CapSure Epi	CapSure Epi	(No brand name)
		laboM Ighan Ighan	4951, 4951M	4965	4968	5071

Epi/Myocardial Pacing Leads continued

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
4951, 4951M	Spectraflex	Oct-81	23,200	3,100	57	0	39	29
4965	CapSure Epi	Sep-96	20,000	9,700	114	1	28	2
4968	CapSure Epi	Sep-99	20,300	13,100	12	0	6	0
5071	Screw-in	Dec-92	38,900	14,900	7	0	1	5

Source: Returned Product Analysis Data as of July 31, 2010

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Impedance Abnormal	Extracardiac Stimulation	Unspecified
4951, 4951M	Spectraflex	23,200	1	1	0	13	0	0	2
4965	CapSure Epi	20,000	0	0	1	3	2	0	0
4968	CapSure Epi	20,300	1	0	3	4	2	0	0
5071	Screw-in	38,900	1	0	0	20	3	1	1

Report Cutoff Date: July 31, 2010

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture-On V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5069	(No brand name)	Myocardial Screw-In	Silicone	MP35N Multifilars	3-Turn Helix	IS-1 UNI
5071	(No brand name)	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI

VDD Single Pass Pacing Leads

5032 CapSure VDD

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCL, LCN, LCM	US Returned Product Analysis
Registered US Implants	5,400	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Conductor Fracture 6
Estimated Active US Implants	1,400	Polarity	Quadripolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 7 Other 0

System Longevity Study Results

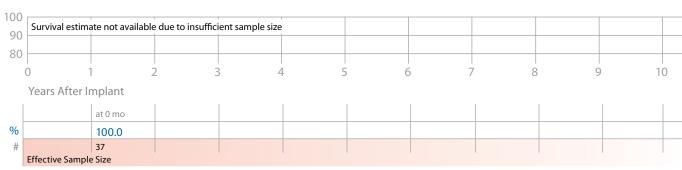
Lead Survival Probability (%)

Qualifying Complications 1 Total

Failure to Sense

Number of Leads Enrolled in Study 38 751 Cumulative Months of Follow-Up

Number of Leads Active in Study



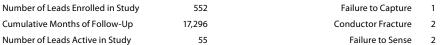
5038 CapSure VDD-2

Product Characteristics

US Market Release	Sep-98	Serial Number Prefix	LEE, LEG, or LEF	US Returned Product Analysis
Registered US Implants	8,600	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Conductor Fracture 3
Estimated Active US Implants	3,700	Polarity	Quadripolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 1
				Other 1



Qualifying Complications 5 Total





VDD Single Pass Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)

ā		US Market Release	Enrolled	Active in Study	Qualifying Complications	Cumulative Months of Follow-Up in Study		Survival I		ity (%)						
Model Number	Family	US Mar	Leads En	Leads	Qualify Compl	Cumul	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
5032	CapSure VDD	Mar-96	38	0	1	751	100.0 at 0 mo									
5038	CapSure VDD-2	Sep-98	552	55	5	17,296	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.8 +0.2/-1.4	98.3 +1.2/-3.9	97.4 +1.7/-4.6	97.4 +1.7/-4.6	95.6 +2.8/-7.4 at 78 mo.			

Source: System Longevity Study Data as of July 31, 2010

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
5032	CapSure VDD	Mar-96	5,400	1,400	6	0	7	0
5038	CapSure VDD-2	Sep-98	8,600	3,700	3	1	1	1

Source: Returned Product Analysis Data as of July 31, 2010

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Lead Dislodgement	Failure to Capture	Failure to Sense	Extracardiac Stimulation
5032	CapSure VDD	5,400	1	4	1	0
5038	CapSure VDD-2	8,600	0	1	0	1

Report Cutoff Date: July 31, 2010

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous Ventricular Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic products is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than 6-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a 6-month interval, a conservative approach has been adopted whereby only the maximum charge time in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

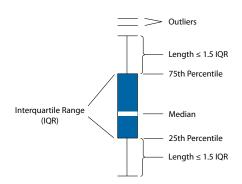
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

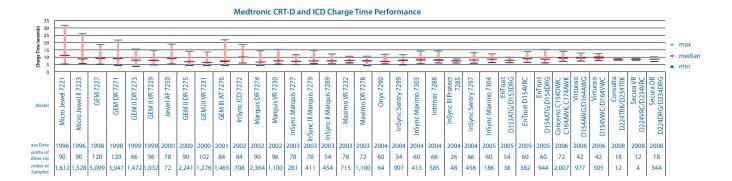
Data Presentation

Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data – the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the third quartile or the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the first quartile or the 25th percentile. Vertical lines are drawn from the quartiles to the farthest value not more than 1.5 times the interquartile range. Any values more extreme than the vertical lines are considered outliers.

Results

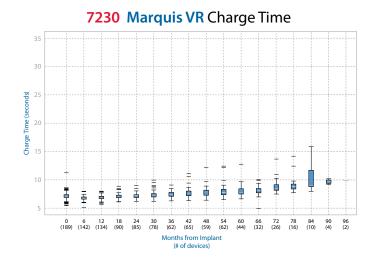
The graph below shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel.

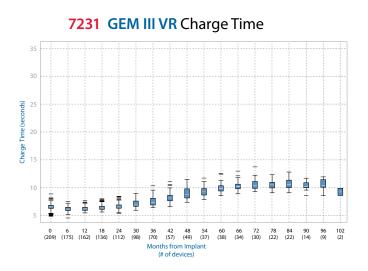


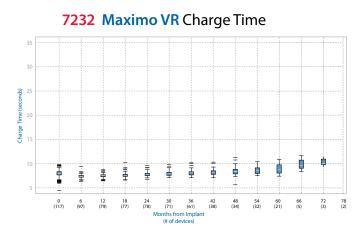


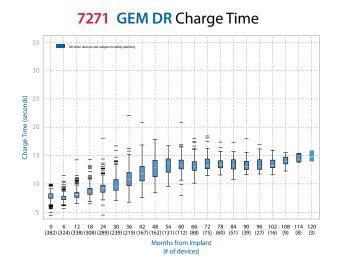
ICD and CRT-D Charge Time Performance continued

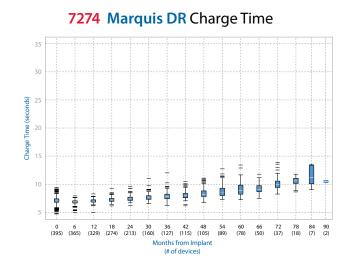
7227 GEM Charge Time Charge Time (seconds) Months from Implant (# of devices)



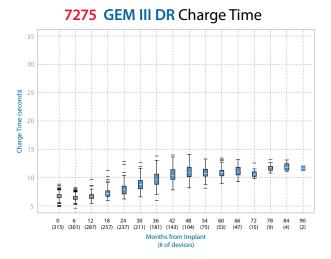


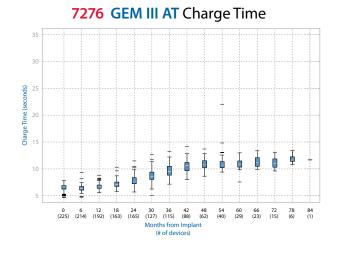


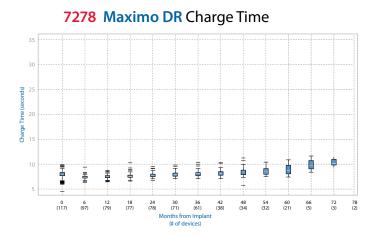


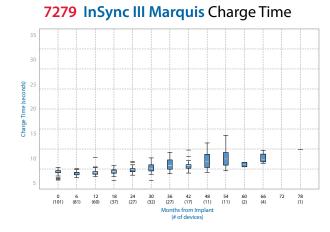


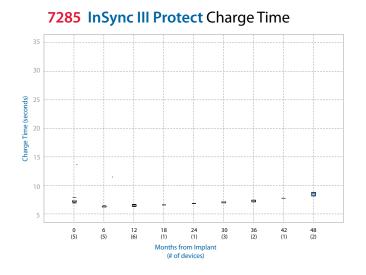
ICD and CRT-D Charge Time Performance continued

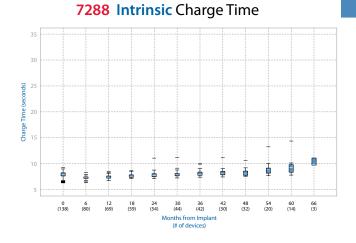






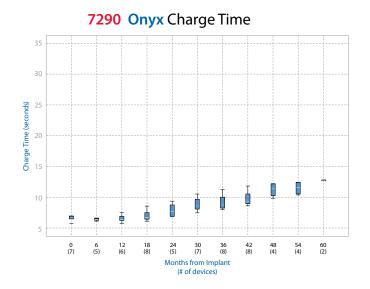


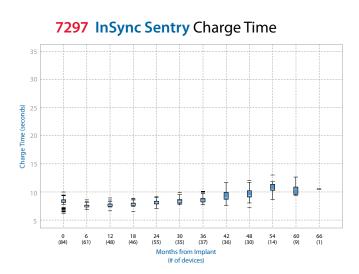


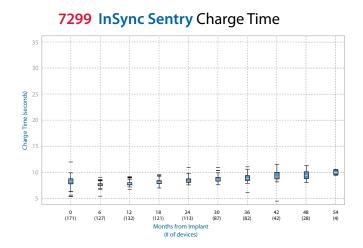


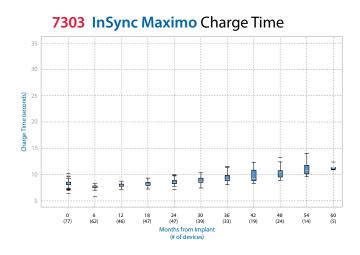
ICCDaandCCBRTEDCGlaaggeTimeePeefoonmaangeecondintireded

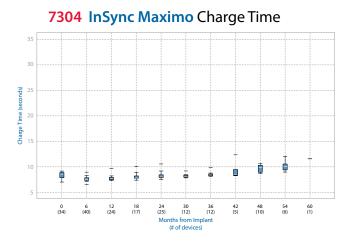
7289 InSync II Marquis Charge Time Charge Time (seconds) 6 (72) Months from Implant



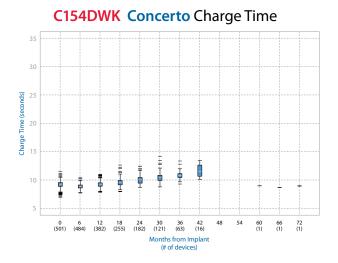


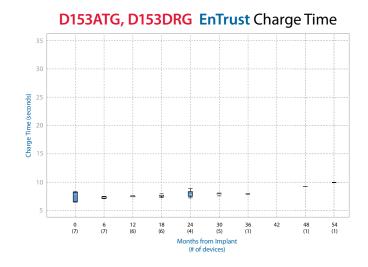


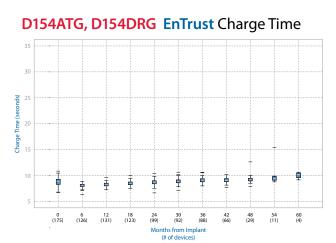


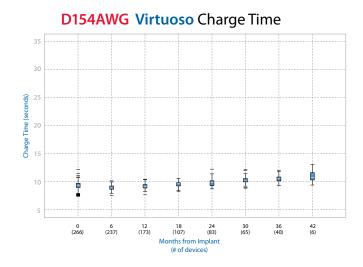


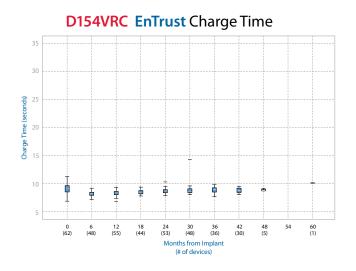
ICD and CRT-D Charge Time Performance continued

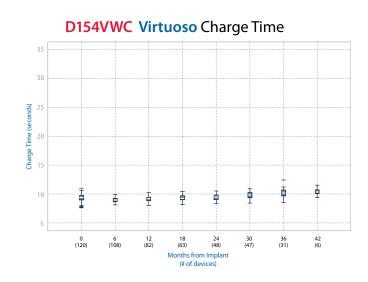






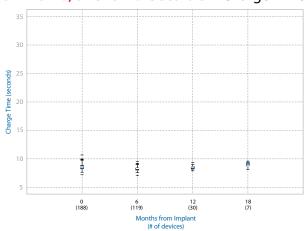




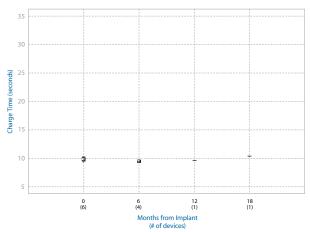


ICD and CRT-D Charge Time Performance continued

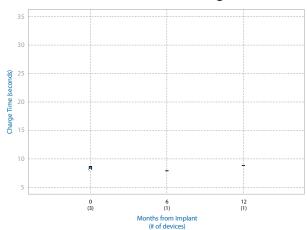
D224DRG, D234DRG Secura DR Charge Time



D234TRK Consulta Charge Time



D234VRC Secura VR Charge Time



Advisories

EnRhythm Pacemakers

Original Date of Advisory: February 2010

Low Battery Voltage Displayed at Device Interrogation

Product

All EnRhythm pacemakers.

Advisory

Two specific battery issues with EnRhythm pacemakers have been identified and both will be addressed by a Medtronic software update. EnRhythm devices were commercially released in 2005, and these devices have been implanted for less than 5 years.

First Issue

As of February 2010, Medtronic had received 62 reports (out of approximately 110,000 devices worldwide) indicating that the battery voltage at device interrogation was lower than the battery voltage that is tracked by the device to provide data for the elective replacement indicator (ERI) notification. The lower voltage measurement has caused confusion and occasionally has resulted in unnecessary explants.

Medtronic's investigation has shown that none of these reports have resulted in loss of therapy. Importantly, the ERI notification, which uses the nightly battery measurement, is unaffected and accurate. Medtronic has identified the root cause as higher than expected battery resistance.

Medtronic's internal testing has shown that there is no current risk for compromised therapy delivery. If the software update referenced above is not implemented, there will be a potential risk of loss of device functionality in a small percent (less than 0.08% 6 years post-implant) of devices. The software update will eliminate this risk.

Patient Management Recommendations

Medtronic recommends physicians continue to use the ERI notification to determine time for device replacement. At this time, no other action, reprogramming, or change in the frequency of follow-up is recommended.

Second Issue

Through internal accelerated testing, Medtronic has identified a second issue that projects battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion. This issue has not been clinically observed and is not expected to occur for another 4 years (approximately 9 years post-implant). If the software update referenced above is not implemented, there may be a potential risk for loss of therapy at or near ERI in a small number of devices. The software will eliminate this issue by changing ERI criteria.

Summary

The software update will eliminate any potential future risk of the two battery issues described above by changing the ERI criteria. This update will reduce longevity of these devices by approximately 10-15%, but the expected average longevity will still be 8.5 to 10.5 years depending on device settings.1 At this time, no other action, reprogramming, or change in the frequency of patient follow-up is recommended. Your Medtronic representative will notify you when the software update is available, following regulatory approval.

Status Update

As of July 31, 2010, 171 devices out of approximately 135,000 devices worldwide have been confirmed as having exhibited an advisory related event. Approximately 98,000 remain implanted.

 1 The 8.5 year estimate represents a high use scenario (DDD, 100% pacing in atrium and ventricle with 3.0 V output in both chambers). The 10.5 year estimate represents a typical use scenario for a sinus node dysfunction patient with the MVP function ON (AAI(R) <=> DDD(R), 50% pacing in atrium and 5% pacing in ventricle with 3.0 V output in both chambers).

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	The software update will eliminate any potential future risk of the two battery issues described above by changing the ERI criteria. Your
All EnRhythm pacemakers (135,500 Worldwide).	171 Worldwide	98,000 Worldwide	0.13%	Medtronic representative will notify you when the software update is available, following regulatory approval.



Concerto CRT-D and Virtuoso ICD

Original Date of Advisory: September 2009

Potential Reduced Device Longevity

Product

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity. Specific model and serial numbers of affected devices are available online at: http://cvsnlist.medtronic.com/

Advisory

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity due to gradually increasing current drain caused by low voltage capacitor degradation. This issue may present in the affected devices as reaching the Recommended Replacement Time (RRT) earlier than projected. This issue does not compromise device functionality or affect therapy delivery.

Based on information from returned devices, Medtronic expects that affected devices will continue to provide at least 3 months of normal device function between RRT and End of Service (EOS) as described in device labeling.

A total of 8,900 devices worldwide are affected by this advisory. An estimated 6,300 of these devices were active at the time of the original advisory communication.

Concerto and Virtuoso devices in the affected subset were manufactured primarily in 2006 and can be traced to a specific subset of low voltage capacitors.

Patient Management Recommendations

After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients with devices in the affected subset:

Physicians should continue routine follow-up sessions at least every 3 months in accordance with product labeling.

Physicians should verify that the Low Battery Voltage RRT alert is programmed to "On-High." This provides an audible, alternating tone when the device reaches RRT. These devices are shipped with this alert programmed nominally to "On-High."

Physicians may consider monitoring patients through CareLink. The CareLink home monitor can be used to automatically notify the clinician when the device reaches RRT.

Status Update

As of July 31, 2010, 2,442 devices out of approximately 8,900 devices in this subset worldwide have been confirmed as having exhibited this capacitor degradation. Out of the initial advisory population of 8,900 worldwide, approximately 1,400 remain implanted. Approximately 1,100 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)
8,900 Implanted Worldwide (7,000 United States)	2,442 Worldwide (2,064 United States)	1,400 Worldwide (1,100 United States)	27% Worldwide (29% United States)



Kappa 600/700/900 Pacemakers Sigma 100/200/300 Pacemakers

Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires

Product

A specific subset of Kappa and Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Specific model and serial numbers of affected devices are available online at: http://kappasigmasnlist.medtronic.com

Advisory Population

Specific subsets of Kappa and Sigma series pacemakers may fail at a higher than expected rate due to separation of wires that connect the electronic circuit to other pacemaker components (e.g., battery, connector). This may present clinically as loss of rate response, premature battery depletion, loss of telemetry, or no output.

Some patients, whose devices experience a wire separation resulting in a loss of pacing output, will experience a return of bradycardia symptoms (e.g., fainting or lightheadedness). In rare cases involving pacemaker dependent patients, loss of pacing output may result in death or serious injury.

Since 1997, there have been over 1.7 million Kappa and Sigma devices implanted worldwide. . At the time of the original advisory communication, an estimated 15,200 Kappa and 6,100 Sigma devices affected by the advisory remained implanted and active. These devices were manufactured primarily between November 2000 and November 2002. Most of these devices have been implanted in patients for five years or longer and may be nearing normal elective replacement time.

There is no provocative testing that can predict which specific devices may fail, and no device programming can mitigate this issue if it occurs.

Patient Management Recommendations

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Advisory Population

Patient management recommendations remain unchanged. As of July 31, 2010, Medtronic has observed 437 Kappa devices and 241 Sigma devices with this failure mechanism from the Kappa and new Sigma device subsets. This represents 0.75% (Kappa) and 1.62% (Sigma) of the original affected implant population.

Four hundred three (403) of the Kappa devices (0.69%) and 178 of the Sigma devices (1.19%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 34 Kappa devices (0.06%) and 63 Sigma devices (0.42%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

As of May 2009, our modeling predicts failure rates due to this issue of 1.1% (Kappa) and 4.8% (Sigma) over the remaining lifetime of those pacemakers still in service at that time.

Out of the initial advisory population of 58,300 Kappa devices and 14,900 Sigma devices worldwide, approximately 6,000 Kappa devices and 3,700 Sigma devices remain implanted. Of these, approximately 1,800 Kappa and 900 Sigma devices are in the United States.

Continued Vigilance

Included in the advisory communication was information about an additional subset of Kappa devices where we have observed a much lower rate of occurrence of this issue. Approximately 58,000 devices of this subset remain active. We have observed a failure rate of approximately 0.07% in this subset and our May 2009 modeling predicts a failure rate of 0.12% over the remaining device life of those pacemakers still in service at that time. After review with our Independent Physician Quality Panel, we do not recommend any specific actions for this group of devices. We will continue to monitor performance and inform you if any specific patient management recommendations are warranted.

continued



Kappa 600/700/900 Pacemakers Sigma 100/200/300 Pacemakers Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires, continued

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
Kappa Pacemakers				
58,300 Implanted Worldwide (est.) (17,600 United States)	403 Worldwide (213 United States) with information indicating a clinical presentation. An additional 34 worldwide (23 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	6,000 Worldwide (1,800 United States)	0.75% Worldwide 1.34% (United States)	1.1%
Sigma Pacemakers				
14,900 Implanted Worldwide (est.) (3,700 United States)	178 Worldwide (38 United States) with information indicating a clinical presentation. An additional 63 worldwide (14 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	3,700 Worldwide (900 United States)	1.62% Worldwide 1.41% (United States)	4.8%



6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture

Product

All Model 6930, 6931, 6948, and 6949 implantable defibrillation leads

Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for approximately 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

Patient Management Recommendations

Medtronic recommends you consider the following as part of routine follow-up for each patient:

- To reduce the risk of inappropriate detection and therapy due to oversensing, program VF detection for initial Number of Intervals to Detect (NID) to nominal settings (18/24) or longer at physician $\,$ discretion and Redetect NID to nominal settings (12/16)
- Turn ON Patient Alert for RV Pacing, RV Defibrillation, and SVC Defibrillation impedance. For Concerto, Virtuoso, Consulta, Secura and Maximo II devices enrolled on the Medtronic CareLink Network, turn ON the Medtronic CareAlert Notifications for these same parameters.
- To optimize effectiveness of the lead impedance alert:
 - Review V. Pacing Lead Performance Trend to determine typical chronic impedance value for the patient (typical values for Fidelis leads should be 350-1,000 ohms)
 - Program lead impedance alert threshold for RV Pacing to 1,000 ohms, if the typical chronic impedance for the patient is ≤ 700 ohms, or
 - Program lead impedance alert threshold for RV Pacing to 1,500 ohms, if the typical chronic impedance for the patient is > 700 ohms
 - Program lead impedance alert threshold for RV Defibrillation and SVC Defibrillation to 100 ohms

Status Update

Sprint Fidelis lead performance continues to be in line with the information provided in the October 2007, May 2008 and March 2009 advisory communications. In consultation with the Independent Physician Quality Panel, our patient management recommendations are as follows:

- When a lead fracture is suspected or confirmed, we strongly recommend prompt patient attention. Patients should contact their physician without delay if they experience unexpected shocks.
- The Lead Integrity Alert (LIA†) is expected to provide 3 days advance notice prior to inappropriate therapy to 76% of the patients with lead fractures. As a result, we strongly recommend that all Sprint Fidelis patients who have the ability to upgrade to Lead Integrity Alert do so promptly.
- The risk of prophylactic intervention appears to be greater than the risk of serious injury resulting from lead fracture even for pacemaker dependent patients, except in select individual patient circumstances as determined by the physician
- Special circumstances may apply to device change-out or upgrade procedures when a lead fracture has not occurred. At least four options are available, each of which carries risks and benefits that should be taken into consideration:
 - Leave a properly performing lead intact; this is likely to be the best choice for the majority of patients
 - Place a new ICD lead without extraction of the existing lead
 - Place a pace sense lead without the extraction of the existing lead. This option reflects the observation that approximately 90% of Fidelis failures are related to fractures in the pace sense circuit. It is unknown what the failure rate of the high voltage conductor would be should a pace sense conductor failure occur in the existing Sprint
 - Unusual patient circumstances may warrant extracting and implanting a new ICD lead. Factors to consider when making this decision include patient life expectancy, age, and comorbidities, number of implanted leads and duration of implant, and patient preference. Medtronic's Independent Physician Quality Panel recommends that if a lead requires removal, the procedure be performed by a physician with extensive lead extraction experience.

As of July 31, 2010, of the initial implant population of 205,600 in the United States, approximately 125,000 remain implanted. According to System Longevity Study results, lead survival is estimated to be 92.8% (+2.1/-2.8%) at 63 months. As the implanted population ages and the sample size increases for each time interval, the accuracy of the estimated survival probability will increase as shown by tighter confidence intervals.

continued



6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture, continued

As part of our commitment to keep you informed about Sprint Fidelis lead performance, Medtronic publishes the quarterly System Longevity Study's all-cause lead survival curve and the CareLink dataset lead survival curve for the Model 6949 lead at: www. medtronic.com/fidelis. Semi-annual updates will also continue to be provided in the Product Performance Report. Additional information about the Sprint Fidelis lead is available at: www.medtronic.com/ fidelis.

Lead Integrity Alert[†]

Medtronic has released Lead Integrity Alert (LIA) software. LIA was designed to provide patients more advance notice via an audible sound of a potential lead fracture that could result in an unnecessary shock.

Data show that with LIA, approximately 76% of the patients with Sprint Fidelis leads are expected to receive 3 or more days advance warning of a potential lead fracture that could result in an unnecessary shock.

Upon hearing the alert, patients should contact their physician without delay.

LIA can be downloaded into nearly all Medtronic implantable cardioverter defibrillators (ICDs) and cardiac resynchronization therapy defibrillators (CRT-Ds) implanted worldwide.

† LIA software released September 2008

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population
205,600	3,658 (United	125,000 (United
(United States)	States)	States)

According to System Longevity Study results, lead survival is estimated to be 92.8% (+2.1/-2.8%) at 63 months. Additional information about the Sprint Fidelis lead is available at: www. medtronic.com/fidelis.



Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Specific model and serial numbers of affected devices are available online at: http://SigmaSNList.medtronic.com.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

No provocative testing can predict which devices may fail.

Patient Management Recommendations

Recommendation for the management of patients who have pacemakers affected by this advisory were changed in May 2009. Current recommendations are:

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients in the 2005 Sigma advisory:

 Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).

- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Patient management recommendations remain unchanged. As of July 31, 2010, 600 devices out of approximately 40,000 devices worldwide have been confirmed as having experienced interconnect wire separation.

Two hundred seventy-four (274) of the Sigma devices (0.69%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 326 Sigma devices (0.82%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Our original modeling predicted a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. However, as of May 2009 updated updated modeling now predicts a failure rate of 3.9% over the remaining device life of those devices still in service at that time.

Out of the initial advisory population of 40,000 worldwide, approximately 10,000 remain implanted. Approximately 2,500 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still in Service as of May 2009
40,000 Implanted Worldwide (est.) (9,900 United States)	274 Worldwide (57 United States) with information indicating a clinical presentation. An additional 326 Worldwide (61 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	10,000 Worldwide (2,500 United States)	1.50% Worldwide 1.19% (United States)	3.9%



7274 Marquis DR 7230 Marquis VR 7278 Maximo DR 7232 Maximo VR

7277 InSync Marquis **7289** InSync II Marquis 7279 InSync III Marquis 7285 InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Specific model and serial numbers of affected devices are available online at: http://MarquisSNList.medtronic.com.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

· Conduct quarterly (i.e., every 3 months) follow-up procedures

- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.
- Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, follow-up care should be sought promptly.

Status Update

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of July 31, 2010, 182 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. One hundred ten (110) of these devices were returned from the United States.

Out of the initial advisory population of 87,000 worldwide, approximately 14,000 remain implanted. Approximately 12,000 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
87,000 Implanted Worldwide (76,000 United States)	182 Worldwide (110 United States)	14,000 Worldwide (12,000 United States)	0.21% Worldwide (0.14% United States)	Consistent with Medtronic projections, the observed rate of shorting may increase to between 0.2% and 1.5% over the second half of device life.



Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

Potential Fractured Power Supply Wires

Product

A specific subset of Kappa 700/600 dual chamber (D, DR, and VDD) implantable pulse generators has been identified by serial numbers. Hospitals and Physicians were notified. Specific model and serial numbers of affected devices are available by calling US Technical Services at 1 (800) 505-4636.

Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 dual chamber (D, DR, and VDD) series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free of charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

Status Update

Patient management recommendations remain unchanged. As of July 31, 2010, 320 out of approximately 180,000 distributed (0.18% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. One hundred sixty-eight (168) of these devices were returned from the United States. Out of the initial implant population of 121,000 in the United States, approximately 1,700 remain implanted.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
180,000 Active Worldwide at time of advisory (121,000 United States)	320 Worldwide (168 United States)	2,500 Worldwide (1,700 United States)	0.18% Worldwide (0.14% United States)	0.03%



Minix and Minix ST IPGs

Original Date of Advisory: May 6, 1991

Potential Delayed Restoration of Permanent Settings

Product

All Models of the Minix and Minix ST families of implantable pulse generators

Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

Status Update

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 3,400 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

Initial Affected Population	Estimated Remaining Active Population	To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head
All Minix and Minix ST implantable pulse generators	3,400	away from the pulse generator.

Performance Notes

Helix Retraction of the Sprint Quattro Secure S 6935 and Sprint Quattro Secure 6947

Purpose of this Information

This performance note is intended to provide guidance regarding retraction of the helix of Sprint Quattro Model 6935 or 6947 leads.

Background

In certain cases, over-retraction of the helix, during initial implant or subsequent repositioning, may result in the inability to extend the helix. This does not impact acute or chronic performance of successfully implanted leads.

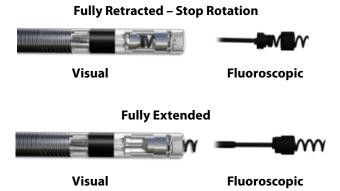
The root cause is over-retraction of the helix mechanism beyond the retraction stop, resulting in the inability to extend the helix in a subsequent attempt.

Recommendations

Consistent with the Technical Manual, the following steps can be used to mitigate this issue.

- Fluoroscopy should be used to confirm when the helix is fully retracted.
- Rotation of fixation tool should be stopped once full helix retraction is visually verified.
- If helix is unable to extend, replace with a new lead and report the issue to Medtronic.

Retraction Stop



Potential Malfunction of CRT, ICD, and IPG Products due to Anomalies in MOSFET Integrated Circuit Technology

Medtronic has detected a specific pattern of MOSFET IC malfunctions in its Concerto, Virtuoso and EnRhythm family of devices. As of July 2009, Medtronic has confirmed twenty-eight (28) malfunctions related to this pattern out of 115,000 EnRhythm and 233,000 Concerto/Virtuoso products distributed worldwide. Reliability analysis of this pattern shows the probability of occurrence decreases with time and, to date over 90% of the malfunctions related to the pattern have occurred within the first twelve months after implant. With process improvements in place, Medtronic expects few, if any, additional malfunctions related to this pattern.

The pattern involves metal-oxide-semiconductor fieldeffect transistors (MOSFET). A MOSFET is an electronic circuit used to amplify or switch electronic signals. MOSFETs have been used in the electronics industries for decades and MOSFET technology is the most widely used type of integrated circuit. Medtronic uses this technology in the circuitry of its CRT, ICD, and IPG products. Each product contains thousands of MOSFETs in its electronic circuitry.

Each MOSFET depends on a layer of insulating material to electrically isolate its components. The integrity of this insulating layer is important to the operation of the MOSFET. Variation in the thickness of the insulating layer can cause the MOSFET to operate in an undesirable manner. Process variations for electronic circuits can affect the integrity of the insulating material, and can lead to MOSFET malfunction. Medtronic's quality system strives to control process variation and detect undesired anomalies that are characteristic of all MOSFET manufacturing. In addition, Medtronic's post-market vigilance activities monitor malfunctions and may implement screening and testing improvements when a pattern of related malfunctions is identified.

The pattern with the Concerto, Virtuoso and EnRhythm models has presented clinically as high lead impedance, sensing difficulty, loss of pacing therapy and/or early battery depletion due to higher than normal battery drain. The degree of battery drain varies case by case, such that the time from the onset to battery depletion has ranged from several days to several months. If not detected by normal patient follow-up procedures, the use of patient alerts or CareLink remote monitoring, the battery will fully deplete, leaving the patient without therapy.

As of March 2009, Medtronic has implemented additional electrical screening and stress tests to address this specific pattern for products being sold.

Since these rates of malfunction are low and the probability of occurrence decreases with time, Medtronic recommends physicians continue following patients in accordance with standard practice.

Clinical Management of VCM near Elective Replacement

Background

Medtronic Technical Services has received reports of devices going to ERI or end of life (EOL) sooner than expected after a normal follow-up in which the device longevity was projected to be approximately 18 months. It has been noted that these cases typically involve Kappa 700 devices where Ventricular Capture Management set the ventricular lead to high output (5 V, 1 ms), which occurs by device design when a high threshold is measured. It is important for physicians and allied professionals to understand VCM behavior as it relates to longevity so that they can, in turn, understand how this affects management of the device and follow-up visits as VCM equipped IPGs near the end of their expected longevity.

Device Longevity and VCM Behavior

Ventricular Capture Management is a feature that uses evoked response sensing to determine the stimulation threshold needed to capture the ventricular chamber. Proper detection of the evoked response is crucial to the VCM algorithm determining an accurate capture threshold. There are rare conditions, however, during which the VCM algorithm will not be able to measure the evoked response accurately. When this occurs, for safety reasons the VCM algorithm will reprogram the output to 5 V, 1 ms until the subsequent VCM measurement.

If the device has considerable remaining longevity, these occasional excursions to high output do not substantially affect remaining longevity. However, if the device has less than approximately 18 months remaining longevity, there is the possibility that the high output condition caused by the 5 V, 1 ms output will drain the battery and trigger ERI.

When ERI is declared by the device, VCM is disabled and the outputs are left at 5 V, 1 ms until the device is reprogrammed at an in-office follow-up. This increased current drain of a high output condition will speed depletion of the device, possibly resulting in the device getting to the EOL (battery voltage ≤ 2.15 V).

Please note that the following parameter changes occur when the device goes to ERI:

Table: IPG Therapy Parameter Changes at ERI

Parameter	Value
Pacing Mode	VVI
Lower Rate	65 bpm
Single Chamber Hysteresis	OFF
Sleep Function	OFF
Ventricular Capture Management	OFF
Atrial Sensing Assurance	OFF
Ventricular Sensing Assurance	OFF

Kappa 700 is Medtronic's first-generation VCM algorithm, which has a relatively higher incidence of evoked response undersensing compared to subsequent algorithms, resulting in more frequent high output conditions. Therefore, Kappa 700 products are the primary focus of this note. It should be noted that IPGs equipped with the second-generation VCM algorithm (Kappa 900, EnPulse, Adapta/Versa/Sensia, and Relia) have not been observed with evoked response undersensing in the general population, though the items listed in "Follow-Up Considerations" may also be used on these devices.

Follow-Up Considerations

- Estimated longevity in the event the device goes to high output can be determined by the following steps. This allows the clinician to determine follow-up frequency if he or she is concerned the device may go to ERI due to high output.
 - Program the ventricular channel to 5 V, 1 ms
 - Navigate to Data/Battery and Lead Measurements
 - When the message stating "Warning Old Data" is displayed, select "Yes" to measure battery voltage and lead impedance at the new ventricular outputs
 - An updated remaining longevity estimate will be calculated on the elevated outputs. Note the "Minimum Remaining Longevity." Clinical decisions can be based on this value.
 - Program the Amplitude and Pulse Widths back to their original values before leaving the session
- If the capture trends and lead impedance trends are stable, VCM can be programmed to "Monitor Only" for the remaining device life. This should be considered only if remaining longevity is 18 months or less.
- Follow-up frequency can be increased for those patients who do not have stable capture or lead impedance trends. This can be done via a CareLink Home Monitor, or in-office.

 $^{^1}$ Medtronic, Inc. (2001). Medtronic Kappa 700/600 Series Pacemaker Reference Guide (Chapter 4, p. 27). Can be retrieved from http://manuals.medtronic.com.

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of This Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- The amount of electrical energy expended in providing therapy to the patient
- The amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- The energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

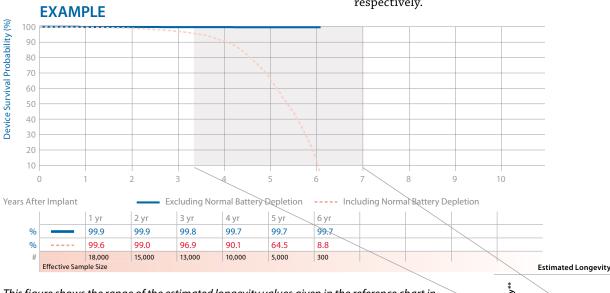
Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.



This figure shows the range of the estimated longevity values given in the reference chart in relation to the survival curve. The range of longevity is representative of a typical range of use values, not the absolute minimum or maximum longevities possible. In this example, the survival curve including normal battery depletion is approaching 50% at approximately the mid-point of the range of longevity values.

Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation

Purpose of This Information

This article is intended to provide information for consideration when programming pacemaker operation in ICDs and pacemakers.

Background

Right ventricular pacing has been associated with increased risk of appropriate therapy for ventricular tachycardia (VT) and ventricular fibrillation (VF) in ICD patients.1 Abrupt changes in ventricular cycle lengths (short-long-short, S-L-S) may precede initiation of VT/VF in some instances. S-L-S sequences may be permitted in all forms of cardiac pacing. The pause lengths depend upon pacing mode and lower rate programming.²⁻⁴ Because pauses may be associated with VT/VF initiation, pause suppression algorithms have been developed in ICDs. Although pause suppression may have utility in specific patients with repolarization abnormalities and pause dependent VT, it has not been shown to reduce arrhythmia incidence in the general ICD population.5 Conversely, S-L-S sequences may occur with ventricular pacing in a variety of ways, including atrial tracking of premature atrial contractions (PACs) or by terminating pauses with ventricular paced beats. 6 In some patients, the ectopic depolarization pattern of a ventricular paced beat may be pro-arrhythmic, independent of pause timing. These observations have further enforced the desire to reduce unnecessary ventricular pacing.

Clinical Trial Observations

Medtronic-sponsored clinical trials were retrospectively analyzed to further understand pause-mediated (i.e., S-L-S) scenarios prior to VT/VF. S-L-S onset scenarios were observed in a minority of patients in all pacing modes. Pacemaker interactions prior to VT/VF are dependent on patient conditions, as well as the technical aspects of pacing operation (i.e., pacing mode, lower rate, and AV interval). Because a very low frequency of ventricular pacing is observed during Managed Ventricular Pacing (MVP)⁷⁻⁹ or VVI 40 pacing modes, ¹⁰ the long interval tended to terminate with a ventricular sense. In DDD mode, the long interval tended to be terminated by a ventricular pace. Long intervals of > 1,000 ms prior to VT/VF were rare in MVP mode. In these analyses, only an association between cardiac pacing and VT/VF initiation can be observed, causality cannot be established. The ongoing MVP (Managed Ventricular Pacing vs. VVI 40 Pacing) Trial, a 2-year, 1,000-patient prospective, randomized trial in ICD patients may offer more insight into the frequency of VT/ VF across pacing modes.11

Pacemaker Patients

In pacemaker patients, ventricular pacing has been associated with higher incidence of AT/AF and heart failure hospitalization. ^{12,13} MVP provides atrial rate support while dramatically reducing ventricular pacing in patients with sinus node dysfunction and transient AV block. ⁹ However, as stated in Medtronic reference manuals, depending upon the patient's intrinsic rhythm and conduction, MVP may allow ventricular cycle variation and occasional pauses of up to twice the lower rate.

DDD pacing with long AV intervals may reduce ventricular pacing and may decrease the potential length of pauses compared to MVP. However, DDD with long AV interval programming does not appear to be as effective as AAI-based pacing modes at reducing ventricular pacing, 13,14 may lead to endless loop tachycardia, 14,15 and does not completely eliminate pauses. Also, in DDD mode, a higher programmed lower rate or activation of rate response can lead to an increase in AV conduction times and a higher percentage of ventricular pacing. The potential benefits of reducing ventricular pacing must be weighed against the potential for longer ventricular pauses. Therefore, careful consideration should be given to pacemaker mode and lower rate programming, particularly in the setting of frequent AV block and repolarization abnormalities due to congenital Long QT, electrolyte imbalances, and some medications that prolong QT.

Conclusion

Pacemaker operation may interact with VT/VF initiation in a variety of ways. The patient's heart failure status, arrhythmia substrate, medications, and the relative importance of maintaining ventricular synchrony versus ensuring ventricular rate support must be weighed when choosing optimal hardware (ICD vs. pacemaker) and pacemaker programming (pacing mode, lower rate, etc.).

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AT500 Pacing System Follow-Up Protocol

Purpose of This Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below end of life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform transtelephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

Battery depletion curves are shown in Figure 1, with special focus on device longevity when programming EGM prestorage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately 9 days for each month pre-storage is ON
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM prestorage, or Holter Telemetry features

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/replacement occurs prior to end of life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary.



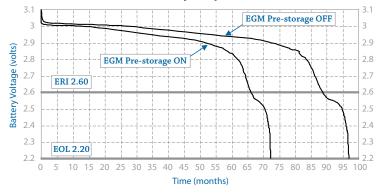


Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial – 2 V, 0.4 ms, 600 ohms, Ventricle - 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least one lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards, the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the performance note, "Clinical Management of High Voltage Lead System Oversensing."

Performing the following steps can be used for each lead connection during the implant procedure:

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- 3 Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- 5 Tug gently on the lead to confirm a secure fit.

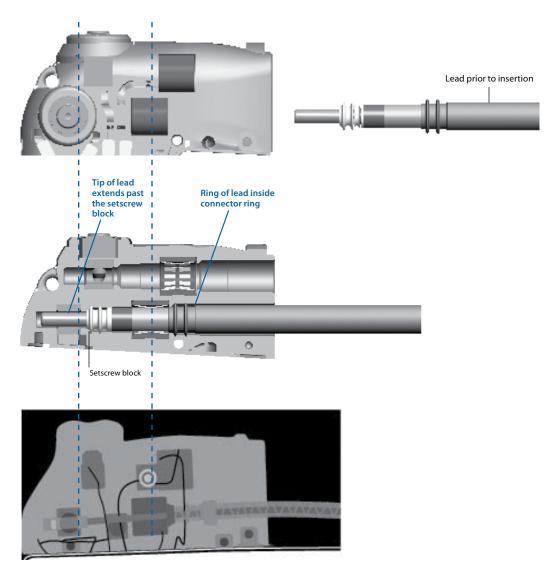
Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.1

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. J Cardiovasc Electrophysiol. September 2004;15(9):1095-1099.

Connector module before lead insertion

Cross-section of connector module after lead fully installed





GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactured and utilized a unique lithium/ silver vanadium oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching middle of life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

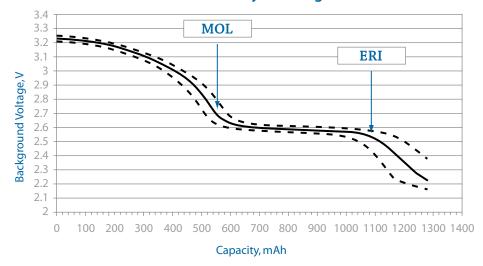
characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the battery in subsequently released models has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.

GEM II/III Battery Discharge Curve



General Follow-Up and Replacement of ICD Leads

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead integrity.

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit block, etc.
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the nonsustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture
- Elicit and investigate any patient complaints/symptoms that may be suggestive of potential lead failure

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the System Longevity Study (SLS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed below.

Factors that should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads.¹⁻³ Ultimately, the decision to replace an implanted lead involves medical judgment.
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Clinical Management of High-Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus, ICD systems attempt to dynamically adjust sensing of electrical events and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T and far-field P waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high-voltage therapies. This is due, in part, to the desire to err on the side of delivering lifesaving high voltage therapy rather than withholding it. Thus, an ICD system that is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/farfield sensing, electromagnetic interference, T wave sensing, connector issues, incomplete or complete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far-field sensing	Diaphragmatic muscle potentials in breathing, wide tip-to-ring (coil on integrated bipolar leads) spacing	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks	Check R waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change-out to true bipolar lead, or if true bipolar lead in use, one with closer tip-to-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave sensing	Drugs, ischemic tissue, exercise, Long QT syndrome, electrolyte imbalance	Sense markers seen on EGM related to T wave. False positive detection.	Check for R wave deterioration and characteristics. If R wave > 3.0 mV, reprogram sensitivity. If R wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header	This is an acute phenomenon seen within 6 months of implant (usually sooner)	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete conductor fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit	Characterized by chaotic oversensing related to motion of the fracture site	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead insulation breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.
Oversensing during interrogation with programming head (not wireless telemetry) with complete lead fracture	Interrogation with a programming head in combination with complete lead fracture that creates an open circuit can induce noise on the sensing circuitry inside the ICD can	Nonphysiologic sensed event on EGM. If detection is enabled during interrogation, oversensing may result in inappropriate therapy.	Quickly remove the programming head. CANCEL the interrupted interrogation and manually load the software for the specific device model. Reposition the programmer head over the device and immediately select SUSPEND. Device will resume detection when programming head is removed, or when RESUME is selected. Replace lead.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement Perforation Electrolyte Imbalance Improper IPG/Lead Connection	Decrease Increase or Decrease Increase or Decrease Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase, Especially in Bipolar System	Sudden and Significant Increase	Dislodgement	Increase Increase Increase Increase Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/ or Slew Rates for P and/or R Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P and/or R Waves	Dislodgement	Decrease Decrease Decrease Decrease Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	l Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset, Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/Leac Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct a Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab.

CRDM Returned Product Analysis Laboratory

Phone: 1 (800) 328-2518, ext. 44800 Email: crdm.returnedproduct@medtronic.com



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